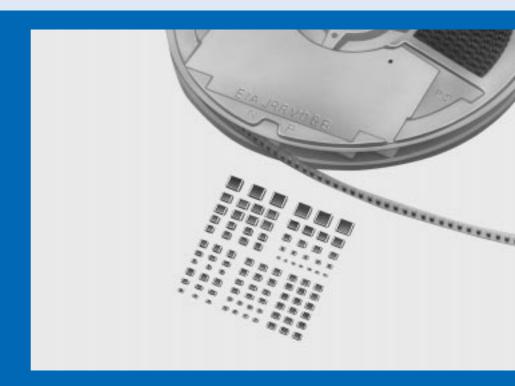
Chip Monolithic Ceramic Capacitors

CHIP MONOLITHIC CERAMIC CAPACITORS







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17	Safety Standard Recognized Type ————————————————————————————————————
GRI	M/GA2/GA3 Series Data1
Pac	kage 1
<u> </u>	caution 1
Not	
ISO	9000 Certifications — 12

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■ Part Numbering (The structure of the "Global Part Numbers" that have been adopted since June 2001 and the meaning of each code are described herein.)

Chip Monolithic Ceramic Capacitors

(Global Part Number) GR M 18 8 B1 1H 102 K A01 K

1 Product ID

2 Series

Product ID	Code	Series		
Productib		2322		
GR	М	Tin Plated layer		
	P	Soldering Electrode		
	F	High-frequency and high-power Type		
ER	н	High-frequency and high-power Type (Ribbon Terminal)		
	Α	High-frequency Type		
	D	High-frequency Type (Ribbon Terminal)		
GQ	М	High-frequency for Flow/Reflow Soldering		
GM	Α	Monolithic Microchip		
GN	М	Capacitor Array		
LL	L	Low ESL Wide-width Type		
GJ	6	Low Dissipation		
	2	Smoothing Type		
GA	2	for AC250V (r.m.s.)		
GA	3	Safety Standard Recognized Type		

3Dimension (LXW)

Code	Dimension (L×W)	EIA		
03	0.6×0.3 mm	0201		
05	0.5×0.5 mm	0202		
08	0.8×0.8 mm	0303		
11	1.25×1.0 mm	0504		
15	1.0×0.5 mm	0402		
18	1.6×0.8 mm	0603		
1X	Depends on individual standards.			
21	2.0×1.25 mm	0805		
22	2.8×2.8 mm	1111		
31	3.2×1.6 mm	1206		
32	3.2×2.5 mm	1210		
3X	Depends on individual	standards.		
42	4.5×2.0 mm	1808		
43	4.5×3.2 mm	1812		
52	5.7×2.8 mm	2211		
55	5.7×5.0 mm	2220		

4Dimension (T)

Code	Dimension (T)
3	0.3 mm
4	4-elements (Array Type)
5	0.5 mm
6	0.6 mm
7	0.7 mm
8	0.8 mm
9	0.85 mm
Α	1.0 mm
В	1.25 mm
С	1.6 mm
D	2.0 mm
E	2.5 mm
M	1.15 mm
N	1.35 mm
R	1.8 mm
Q	1.5 mm
X	Depends on individual standards.

With the array type GNM series, "Dimension(T)" indicates the number of elements.

5Temperature Characteristics

Code	Temperature Characteristics	Temperature Range	Cap. Change or Temp. Coeff.	
1X	SL	-55 to 125°C	+350 to -1000ppm/°C	
5C	C0G	-55 to 125°C	0±30ppm/°C	
6C	C0H	-55 to 125°C	0±60ppm/°C	
6P	P2H	-55 to 85°C	-150±60ppm/°C	
6R	R2H	-55 to 85°C	-220±60ppm/°C	
6T	T2H	-55 to 85°C	-470±60ppm/°C	
7U	U2J	-55 to 85°C	-750±120ppm/°C	
В3	В	-25 to 85°C	±10%	
E4	Z5U	10 to 85°C	+22, -82%	
F5	Y5V	-30 to 85°C	+22, -82%	
R3	R	-55 to 125°C	±15%	
R6	X5R	-55 to 85°C	±15%	
R7	X7R	-55 to 125°C	±15%	

Continued on the following page.





Continued from the preceding page.

(Global Part Number) GR M 18 8 B1 1H 102 K A01 K

6Rated Voltage

Code	Rated Voltage
0J	DC6.3V
1A	DC10V
1C	DC16V
1E	DC25V
1H	DC50V
2A	DC100V
2D	DC200V
2E	DC250V
YD	DC300V
2H	DC500V
2J	DC630V
3A	DC1kV
3D	DC2kV
3F	DC3.15kV
E2	AC250V
GB	X2; AC250V (Safety Standard Recognized Type GB)
GC	X1, Y2; AC250V (Safety Standard Recognized Type GC)

Code A**/B**/C**/W**

Other than above

9Individual Specification Code

* indicates an alphabet or figure.

Prackaging					
Code	Packaging				
E	ø178mm 2mm Pitch Paper Taping				
F	ø330mm 2mm Pitch Paper Taping				
L	ø178mm 4mm Pitch Plastic Taping				
D	ø178mm 4mm Pitch Paper Taping				
K	ø330mm 4mm Pitch Plastic Taping				
J	ø330mm 4mm Pitch Paper Taping				
В	Bulk				
С	Bulk Case				
Т	Bulk Tray				

Individual Specification

Base Metal Inner Electrode Precious Metal Inner Electrode

Capacitance

Expressed by three figures. The unit is pico-farad(pF). The first and second figures are significant digits, and the third figure expresses the number of zeros which follow the two numbers. If there is a decimal point, it is expressed by the capital letter "R". In this case, all figures are significant digits.

Ex.)	Code	Capacitance
	R50	0.5pF
	1R0	1.0pF
	100	10pF
	103	10000pF

8 Capacitance Tolerance

Code	Capacitance Tolerance	TC	Series	Capacit	tance Step		
В	±0.1pF	СΔ	GJ6,GQM	≦5pF	E24 Series,1pF		
С	10.25%	CΔ-SL	GRP/GRM/ERF/ERH/ERA/ERD	≦5pF	* 1pF		
C	±0.25pF	СΔ	GJ6,GQM	<10pF	E24 Series,1pF		
D	10 Epc	C∆-SL	GRP/GRM	6.0 to 9.0pF	* 1pF		
Ь	±0.5pF	СΔ	ERF/ERH/ERA/ERD	5.1 to 9.1pF	E24 Series		
G	130/	СΔ	GJ6	≥10pF	E12 Series		
G	±2%	СΔ	GQM	≥10pF	E24 Series		
	150/	C∆–SL	GRP/GRM	≥10pF	E12 Series		
J	±5%	СΔ	ERF/ERH/ERA/ERD	≥10pF	E24 Series		
К	1100/	B,R,X7R,X5R,ZLM	GRP/GRM/GA3	E6 Series			
r.	±10%	B,R,X7R	LLL	E12 Series			
		Z5U GRM		E3	Series		
M	±20%	B,R,X7R	GMA	E6 Series			
		В	GA2	E3 Series			
Z	.000/ 200/	F,Y5V	GRP/GRM/GJ2	E3 Series			
	+80%, -20%	F,Y5V,E	LLL	E6 Series			
R	Depends on individual standards.						

^{*} E24 series is also available.

Chip Monolithic Ceramic Capacitors

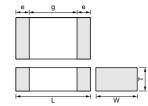


for Flow/Reflow Soldering GRP15/GRM15/18/21/31 Series

■ Features

- 1. Terminations are made of metal highly resistant to migration.
- 2. The GRM series is a complete line of chip ceramic capacitors in 6.3V, 10V, 16V, 25V, 50V and 100V ratings. These capacitors have temperature characteristics ranging from C0G to Y5V.
- 3. A wide selection of sizes is available, from the miniature LxWxT:1.0x0.5x0.5mm to LxWxT:3.2x1.6x1.15 mm.
 - GRM18, 21 and GRM31 types are suited to flow and reflow soldering.
 - GRP15 types is applied to only reflow soldering.
- 4. Stringent dimensional tolerances allow highly reliable, high speed automatic chip placement on PCBs.
- 5. The GRP/GRM series is available in paper or plastic embossed tape and reel packaging for automatic placement. Bulk case packaging is also available for GRP15,GRM18,GRM21ectronic equipment.
- 6. Dielectric layer of GRP15 Y5V 0.22uF/0.47uF/1.0uF are relaxor





Part Number	Dimensions (mm)							
Part Number	L	W	Т	е	g min.			
GRP155	1 0 40 05	0.5 ±0.05	0.5 ±0.05	0.15 to 0.3	0.4			
GRM155	1.0 ±0.03	0.5 <u>1</u> 0.05	0.5 ±0.05	0.15 10 0.3	0.4			
GRM188*	1.6 ±0.1	0.8 ±0.1	0.8 ±0.1	0.2 to 0.5	0.5			
GRM216		1.25 ±0.1	0.6 ±0.1		0.7			
GRM219	2.0 ± 0.1		0.85 ±0.1	0.2 to 0.7				
GRM21B			1.25 ±0.1					
GRM319	2 2 ±0 1E	1 (10 15	0.85 ±0.1		1.5			
GRM31M	3.∠ ±0.15	1.6 ±0.15	1.15 ±0.1	0.3 to 0.8				
GRM31C	3.2 ±0.2	1.6 ±0.2	1.6 ±0.2					

^{*} Bulk Case : 1.6 ±0.07(L) × 0.8 ±0.07(W) × 0.8 ±0.07(T)

Applications

General electronic equipment.

Temperature Compensating Type GRP15/GRM15 Series (1.0x0.5mm)

Part Number					GRP15/GRM15	5			,		
L x W [EIA]	1.00x0.50 [0402]										
тс	C0G (5C)	C0H (6C)	P2H (6P)	R2H (6R)	S2H (6S)	(1	SL I X)	T2H (6T)	U2J (7U)		
Rated Volt.	50 (1H)	25 (1E)	50 (1H)	50 (1H)	50 (1H)	25 (1E)	50 (1H)	50 (1H)	50 (1H)		
Capacitance and	T Dimension						<u>'</u>				
0.5pF(R50)	0.50(5)										
0.75pF(R75)	0.50(5)										
1.0pF(1R0)	0.50(5)										
2.0pF(2R0)	0.50(5)										
3.0pF(3R0)	0.50(5)		0.50(5)	0.50(5)	0.50(5)			0.50(5)	0.50(5)		
4.0pF(4R0)	0.50(5)		0.50(5)	0.50(5)	0.50(5)			0.50 (5)	0.50(5)		
5.0pF(5R0)	0.50(5)		0.50(5)	0.50(5)	0.50(5)			0.50 (5)	0.50(5)		
6.0pF(6R0)	0.50(5)		0.50(5)	0.50(5)	0.50(5)			0.50 (5)	0.50(5)		
7.0pF(7R0)	0.50(5)		0.50(5)	0.50(5)	0.50(5)			0.50 (5)	0.50(5)		
8.0pF(8R0)	0.50(5)		0.50(5)	0.50(5)	0.50(5)			0.50 (5)	0.50(5)		
9.0pF(9R0)	0.50(5)		0.50(5)	0.50(5)	0.50(5)			0.50 (5)	0.50(5)		
10.0pF(100)	0.50(5)		0.50(5)	0.50(5)	0.50(5)			0.50(5)	0.50(5)		
12.0pF(120)	0.50(5)		0.50(5)	0.50(5)	0.50(5)			0.50(5)	0.50(5)		
15.0pF(150)	0.50(5)		0.50(5)	0.50(5)	0.50(5)			0.50(5)	0.50(5)		
18.0pF(180)	0.50(5)		0.50(5)	0.50(5)	0.50(5)			0.50(5)	0.50(5)		
22.0pF(220)	0.50(5)		0.50(5)	0.50(5)	0.50(5)			0.50(5)	0.50(5)		
27.0pF(270)	0.50(5)		0.50(5)	0.50(5)	0.50(5)			0.50(5)	0.50(5)		

Continued from the preceding page.

Part Number		GRP15/GRM15								
L x W [EIA]	1.00x0.50 [0402]									
тс	C0G (5C)	C0H (6C)	P2H (6P)	R2H (6R)	S2H (6S)	SL (1X)		T2H (6T)	U2J (7U)	
Rated Volt.	50 (1H)	25 (1E)	50 (1H)	50 (1H)	50 (1H)	25 (1E)	50 (1H)	50 (1H)	50 (1H)	
Capacitance and	T Dimension					'		'		
33.0pF(330)	0.50(5)			0.50(5)	0.50(5)			0.50(5)	0.50(5)	
39.0pF(390)	0.50(5)				0.50(5)			0.50(5)	0.50(5)	
47pF(470)	0.50(5)						0.50(5)	0.50(5)	0.50(5)	
56pF(560)	0.50(5)						0.50(5)	0.50(5)	0.50(5)	
68pF(680)	0.50(5)						0.50(5)	0.50(5)	0.50(5)	
82pF(820)	0.50(5)						0.50(5)	0.50(5)	0.50(5)	
100pF(101)	0.50(5)						0.50(5)	0.50(5)	0.50(5)	
120pF(121)	0.50(5)						0.50(5)		0.50(5)	
150pF(151)	0.50(5)						0.50(5)		0.50(5)	
180pF(181)		0.50(5)					0.50(5)		0.50(5)	
220pF(221)		0.50(5)				0.50(5)				
270pF(271)		0.50(5)				0.50(5)				
330pF(331)						0.50(5)				
390pF(391)						0.50(5)				

The part numbering code is shown in ().

Temperature Compensating Type GRM18 Series (1.60x0.80mm)

Part Number							GRM18						
L x W [EIA]						1.6	0x0.80 [0 <i>6</i>	03]					
TC		C0G (5C)		C0H (6C)	P2H (6P)	R2H (6R)	S2H (6S)			X)		T2H (6T)	U2J (7U)
Rated Volt.	50 (1H)	100 (2A)	200 (2D)	25 (1E)	50 (1H)	50 (1H)	50 (1H)	25 (1E)	50 (1H)	100 (2A)	200 (2D)	50 (1H)	50 (1H)
Capacitance and	d T Dimen	sion											
0.5pF(R50)	0.80(8)		0.80(8)										
0.75pF(R75)	0.80(8)		0.80(8)										
1.0pF(1R0)	0.80(8)		0.80(8)										
2.0pF(2R0)	0.80(8)		0.80(8)										
3.0pF(3R0)	0.80(8)		0.80(8)		0.80(8)	0.80(8)	0.80(8)					0.80(8)	0.80(8)
4.0pF(4R0)	0.80(8)		0.80(8)		0.80(8)	0.80(8)	0.80(8)					0.80(8)	0.80(8)
5.0pF(5R0)	0.80(8)		0.80(8)		0.80(8)	0.80(8)	0.80(8)					0.80(8)	0.80(8)
6.0pF(6R0)	0.80(8)		0.80(8)		0.80(8)	0.80(8)	0.80(8)					0.80(8)	0.80(8)
7.0pF(7R0)	0.80(8)		0.80(8)		0.80(8)	0.80(8)	0.80(8)					0.80(8)	0.80(8)
8.0pF(8R0)	0.80(8)		0.80(8)		0.80(8)	0.80(8)	0.80(8)					0.80(8)	0.80(8)
9.0pF(9R0)	0.80(8)		0.80(8)		0.80(8)	0.80(8)	0.80(8)					0.80(8)	0.80(8)
10.0pF(100)	0.80(8)		0.80(8)		0.80(8)	0.80(8)	0.80(8)					0.80(8)	0.80(8)
12pF(120)	0.80(8)	0.80(8)			0.80(8)	0.80(8)	0.80(8)				0.80(8)	0.80(8)	0.80(8)
15pF(150)	0.80(8)	0.80(8)			0.80(8)	0.80(8)	0.80(8)				0.80(8)	0.80(8)	0.80(8)
18pF(180)	0.80(8)	0.80(8)			0.80(8)	0.80(8)	0.80(8)				0.80(8)	0.80(8)	0.80(8)
22pF(220)	0.80(8)	0.80(8)			0.80(8)	0.80(8)	0.80(8)				0.80(8)	0.80(8)	0.80(8)
27pF(270)	0.80(8)	0.80(8)			0.80(8)	0.80(8)	0.80(8)				0.80(8)	0.80(8)	0.80(8)
33pF(330)	0.80(8)	0.80(8)			0.80(8)	0.80(8)	0.80(8)				0.80(8)	0.80(8)	0.80(8)
39pF(390)	0.80(8)	0.80(8)			0.80(8)	0.80(8)	0.80(8)				0.80(8)	0.80(8)	0.80(8)
47pF(470)	0.80(8)	0.80(8)			0.80(8)	0.80(8)	0.80(8)				0.80(8)	0.80(8)	0.80(8)
56pF(560)	0.80(8)	0.80(8)			0.80(8)	0.80(8)	0.80(8)				0.80(8)	0.80(8)	0.80(8)
68pF(680)	0.80(8)	0.80(8)			0.80(8)	0.80(8)	0.80(8)		0.80(8)		0.80(8)	0.80(8)	0.80(8)
82pF(820)	0.80(8)	0.80(8)			0.80(8)	0.80(8)	0.80(8)		0.80(8)		0.80(8)	0.80(8)	0.80(8)
100pF(101)	0.80(8)	0.80(8)			0.80(8)	0.80(8)	0.80(8)		0.80(8)		0.80(8)	0.80(8)	0.80(8)
120pF(121)	0.80(8)	0.80(8)			0.80(8)	0.80(8)	0.80(8)		0.80(8)	0.80(8)		0.80(8)	0.80(8)

Dimensions are shown in mm and Rated Voltage in Vdc.

D 1 N 1													
Part Number		•					GRM18						
L x W [EIA]						1.6	0x0.80 [06	503]					
тс		C0G (5C)		C0H (6C)	P2H (6P)	R2H (6R)	S2H (6S)		S (1	X)		T2H (6T)	U2J (7U)
Rated Volt.	50 (1H)	100 (2A)	200 (2D)	25 (1E)	50 (1H)	50 (1H)	50 (1H)	25 (1E)	50 (1H)	100 (2A)	200 (2D)	50 (1H)	50 (1H)
Capacitance and	I T Dimens	sion											
150pF(151)	0.80(8)	0.80(8)			0.80(8)	0.80(8)	0.80(8)		0.80(8)	0.80(8)		0.80(8)	0.80(8)
180pF(181)	0.80(8)					0.80(8)	0.80(8)		0.80(8)	0.80(8)		0.80(8)	0.80(8)
220pF(221)	0.80(8)						0.80(8)		0.80(8)	0.80(8)		0.80(8)	0.80(8)
270pF(271)	0.80(8)								0.80(8)	0.80(8)		0.80(8)	0.80(8)
330pF(331)	0.80(8)								0.80(8)	0.80(8)		0.80(8)	0.80(8)
390pF(391)	0.80(8)								0.80(8)	0.80(8)		0.80(8)	0.80(8)
470pF(471)	0.80(8)								0.80(8)				0.80(8)
560pF(561)	0.80(8)			0.80(8)					0.80(8)				0.80(8)
680pF(681)	0.80(8)								0.80(8)				0.80(8)
820pF(821)	0.80(8)							0.80(8)					
1000pF(102)	0.80(8)							0.80(8)					
1200pF(122)								0.80(8)					

0.80(8)

1500pF(**152**)

Temperature Compensating Type GRM21 Series (2.00x1.25mm)

Part Number							GRM21				-		
L x W [EIA]		,				2.0	0x1.25 [08	305]			,		
тс		C0G (5C)		C0H (6C)	P2H (6P)	R2H (6R)	S2H (6S)		(1	X)		T2H (6T)	U2J (7U)
Rated Volt.	50 (1H)	100 (2A)	200 (2D)	25 (1E)	50 (1H)	50 (1H)	50 (1H)	25 (1E)	50 (1H)	100 (2A)	200 (2D)	50 (1H)	50 (1H)
Capacitance and	d T Dimen	sion			<u>'</u>		'		•			<u>'</u>	
12pF(120)			0.85(9)										
15pF(150)			0.85(9)										
18pF(180)			0.85(9)										
22pF(220)			0.85(9)										
27pF(270)			0.85(9)										
33pF(330)			0.85(9)										
39pF(390)			0.85(9)										
47pF(470)			0.85(9)										
56pF(560)			0.85(9)										
68pF(680)		0.85(9)	1.25(B)										
82pF(820)		0.85(9)	1.25(B)										
100pF(101)		0.85(9)	1.25(B)										
120pF(121)		0.85(9)	1.25(B)								0.85(9)		
150pF(151)		0.85(9)	1.25(B)								1.25(B)		
180pF(181)		0.85(9)	1.25(B)		0.85(9)						1.25(B)		
220pF(221)		0.85(9)	1.25(B)		0.85(9)	0.85(9)					1.25(B)		
270pF(271)		0.85(9)			0.85(9)	0.85(9)	0.85(9)				1.25(B)		
330pF(331)		0.85(9)			0.85(9)	0.85(9)	0.85(9)				1.25(B)		
390pF(391)		1.25(B)			1.25(B)	0.85(9)	0.85(9)				1.25(B)		
470pF(471)		1.25(B)			1.25(B)	0.85(9)	0.85(9)			0.85(9)	1.25(B)		
560pF(561)	0.60(6)	1.25(B)			1.25(B)	1.25(B)	1.25(B)			0.85(9)		1.25(B)	
680pF(681)	0.85(9)	1.25(B)				1.25(B)	1.25(B)			0.85(9)		1.25(B)	
820pF(821)	0.85(9)	1.25(B)					1.25(B)		0.60(6)	1.25(B)		1.25(B)	0.60(6)
1000pF(102)	0.85(9)	1.25(B)							0.60(6)	1.25(B)		1.25(B)	0.60(6)
1200pF(122)	0.85(9)								0.60(6)	1.25(B)		1.25(B)	0.60(6)
1500pF(152)	0.85(9)								0.85(9)	1.25(B)		1.25(B)	0.85(9)



The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

Continued from the preceding page.

Part Number							GRM21						
L x W [EIA]						2.0	0x1.25 [0	805]					
тс		C0G (5C)		C0H (6C)	P2H (6P)	R2H (6R)	S2H (6S)		(1	X)		T2H (6T)	U2J (7U)
Rated Volt.	50 (1H)	100 (2A)	200 (2D)	25 (1E)	50 (1H)	50 (1H)	50 (1H)	25 (1E)	50 (1H)	100 (2A)	200 (2D)	50 (1H)	50 (1H)
Capacitance and	d T Dimens	sion		'								•	
1800pF(182)	1.25(B)								0.85(9)	1.25(B)		1.25(B)	0.85(9)
2200pF(222)	1.25(B)								0.85(9)				0.85(9)
2700pF(272)				1.25(B)					1.25(B)				1.25(B)
3300pF(332)				1.25(B)					1.25(B)				1.25(B)
3900pF(392)				1.25(B)				0.85(9)					
4700pF(472)								0.85(9)					
5600pF(562)								1.25(B)					
6800pF(682)								1.25(B)					

The part numbering code is shown in ().

Temperature Compensating Type GRM31 Series (3.20x1.60mm)

Part Number								GRM31							
L x W [EIA]							3.20)x1.60 [1	206]						
тс		(5	0G 6C)		C0H (6C)	P2H (6P)	R2H (6R)	S2H (6S)			SL (1X)			T2H (6T)	U2J (7U)
Rated Volt.	25 (1E)	50 (1H)	200 (2D)	500 (2H)	25 (1E)	50 (1H)	50 (1H)	50 (1H)	25 (1E)	50 (1H)	100 (2A)	200 (2D)	500 (2H)	50 (1H)	50 (1H)
Capacitance and	I T Dime	nsion	•								•	•			,
1.0pF(1R0)				1.15(M)											
2.0pF(2R0)				1.15(M)											
3.0pF(3R0)				1.15(M)											
4.0pF(4R0)				1.15(M)											
5.0pF(5R0)				1.15(M)											
6.0pF(6R0)				1.15(M)											
7.0pF(7R0)				1.15(M)											
8.0pF(8R0)				1.15(M)											
9.0pF(9R0)				1.15(M)											
10.0pF(100)				1.15(M)											
12pF(120)				1.15(M)											
15pF(150)				1.15(M)											
18pF(180)				1.15(M)											
22pF(220)				1.15(M)											
27pF(270)				1.15(M)											
33pF(330)				1.15(M)											
39pF(390)				1.15(M)											
47pF(470)				1.15(M)											
56pF(560)				1.15(M)											
68pF(680)				1.15(M)											
82pF(820)				1.15(M)											
100pF(101)				1.15(M)											
120pF(121)				1.15(M)											
150pF(151)													1.15(M)		
180pF(181)													1.15(M)		
220pF(221)													1.15(M)		
270pF(271)			1.15(M)										1.15(M)		
330pF(331)			1.15(M)												
390pF(391)			1.15(M)												
470pF(471)			1.15(M)												
560pF(561)												1.15(M)			

Dimensions are shown in mm and Rated Voltage in Vdc.

Continued from the preceding page.

Part Number								GRM31							
L x W [EIA]							3.20	x1.60 [1	206]						
тс		C(5)G C)		C0H (6C)	P2H (6P)	R2H (6R)	S2H (6S)			SL (1X)			T2H (6T)	U2J (7U)
Rated Volt.	25 (1E)	50 (1H)	200 (2D)	500 (2H)	25 (1E)	50 (1H)	50 (1H)	50 (1H)	25 (1E)	50 (1H)	100 (2A)	200 (2D)	500 (2H)	50 (1H)	50 (1H)
Capacitance and	d T Dime	nsion			1	1				1				1	
680pF(681)						0.85(9)						1.15(M)			
820pF(821)						0.85(9)	0.85(9)					1.15(M)			
1000pF(102)						1.15(M)	1.15(M)	0.85(9)				1.15(M)			
1200pF(122)						1.15(M)	1.15(M)	1.15(M)				1.15(M)			
1500pF(152)						1.15(M)	1.15(M)	1.15(M)							
1800pF(182)								1.15(M)							
2200pF(222)											1.15(M)			1.15(M)	
2700pF(272)		0.85(9)									1.15(M)			1.15(M)	
3300pF(332)		0.85(9)									1.15(M)			1.15(M)	
3900pF(392)		1.15(M)								0.85(9)	1.15(M)			1.15(M)	0.85(9)
4700pF(472)		0.85(9)								0.85(9)	1.15(M)				0.85(9)
5600pF(562)		1.15(M)								0.85(9)					0.85(9)
6800pF(682)					0.85(9)					1.15(M)					1.15(M)
8200pF(822)					1.15(M)					1.15(M)					1.15(M)
10000pF(103)	0.85(9)								1.15(M)						
12000pF(123)									1.15(M)						
15000pF(153)									1.15(M)						

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

High Dielectric Constant Type X5R(R6) Characteristics

тс			X! (R	5R 8 6)		
Part Number	GRP15	GRM18	GR	M21	GRI	M31
L x W [EIA]	1.00x0.50 [0402]	1.60x0.80 [0603]	2.00x1.2	25 [0805]	3.20x1.6	0 [1206]
Rated Volt.	10 (1A)	6.3 (0J)	6.3 (0J)	10 (1A)	6.3 (0J)	10 (1A)
Capacitance and	T Dimension					
68000pF(683)	0.50(5)					
0.1μF(104)	0.50(5)					
0.47μF(474)		0.80(8)				
1.0μF(105)		0.80(8)		0.85(9)		
1.5μF(155)			0.85(9)			
2.2μF(225)			1.25(B)			0.85(9)
3.3μF(335)			1.25(B)			1.30(X)
4.7μF(475)			1.25(B)		1.15(M)	1.60(C)
10μF(106)					1.60(C)	

The part numbering code is shown in each ().



 $^{3.3\}mu F$ and $4.7\mu F$ for 6.3V is replaced with GRM21B series of L:2±0.15, W:1.25±0.15, T:1.25±0.15.

 $T{:}1.25{\pm}0.1mm$ is also available for GRM21 10V 1.0 μF type.

 $^{3.3\}mu F$ for 10V rated is replaced with GRM31X series of L:3.2±0.2, W:1.6±0.2, T:1.2±0.1mm.

T:1.15 \pm 0.1 is also available for GRM31, 16V, 1.0 μ F type.

High Dielectric Constant Type X7R(R7) Characteristics

тс								X**	7R ?7)							
Part Number			P15				GRM18				GRM21				M31	
L x W [EIA]		1.00x0.5					03 08.0xi				x1.25 [0			3.20x1.6		
Rated Volt.	10 (1A)	16 (1C)	25 (1E)	50 (1H)	10 (1A)	16 (1C)	25 (1E)	50 (1H)	100 (2A)	16 (1C)	25 (1E)	50 (1H)	10 (1A)	16 (1C)	25 (1E)	50 (1H)
Capacitance and	d T Dime	ension	I		I	I	I	I	I	I	I	I	I	I		I
220pF (221)				0.50 (5)				0.80 (8)								
330pF (331)				0.50 (5)				0.80 (8)								
470pF (471)				0.50 (5)				0.80 (8)								
680pF (681)				0.50 (5)				0.80 (8)								
1000pF (102)				0.50 (5)				0.80 (8)								
1500pF (152)				0.50 (5)				0.80 (8)								
2200pF (222)				0.50 (5)				0.80 (8)	0.80 (8)							
3300pF (332)				0.50 (5)				0.80 (8)	0.80 (8)							
4700pF (472)				0.50 (5)				0.80 (8)								
6800pF (682)			0.50 (5)					0.80 (8)								
10000pF (103)			0.50 (5)					0.80 (8)								
15000pF (153)		0.50 (5)						0.80 (8)								
22000pF (223)		0.50 (5)						0.80 (8)								
33000pF (333)	0.50 (5)						0.80 (8)					0.85 (9)				
47000pF (473)	0.50 (5)						0.80 (8)					1.25 (B)				
68000pF (683)							0.80 (8)					1.25 (B)				
0.10μF (104)						0.80 (8)	0.80 (8)				1.25 (B)	1.25 (B)				
0.15μF (154)					0.80 (8)						1.25 (B)	1.25 (B)				
0.22μF (224)					0.80 (8)						0.85 (B)	1.25 (B)				
0.33μF (334)											1.25 (B)					0.85 (9)
0.47μF (474)										0.85 (9)	1.25 (B)					1.15 (M)
0.68μF (684)										0.85 (9)					0.85 (9)	
1.00μF (105)										1.25 (B)			0.85 (9)	0.85 (9)	1.15 (M)	
1.5μF (155)														1.15 (M)		

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тс								X7 (R								
Part Number		GR	P15				GRM18				GRM21			GRI	M31	
L x W [EIA]		1.00x0.5	0 [0402]	1.60x0.80 [0603]					2.00	x1.25 [0	805]	;	3.20x1.6	0 [1206]
Rated Volt.	10 (1A)	16 (1C)	25 (1E)	50 (1H)	10 (1A)	16 (1C)	25 (1E)	50 (1 H)	100 (2A)	16 (1C)	25 (1E)	50 (1H)	10 (1A)	16 (1C)	25 (1E)	50 (1H)
Capacitance and	d T Dime	nsion														
2.2μF (225)			·										1.15 (M)	1.15 (M)		

The part numbering code is shown in each ().

High Dielectric Constant Type Y5V(F5) Characteristics

тс										Y5V (F5)									
Part Number			GRP15	,				GRM18	3			GRI	M21				GRM31		
L x W [EIA]		1.00	x0.50 [(0402]			1.60	(0.80 (0603]		2.	.00x1.2	25 [080	5]		3.20	x1.60 [1206]	
Rated Volt.	6.3 (0J)	10 (1A)	16 (1C)	25 (1E)	50 (1H)	10 (1A)	16 (1C)	25 (1E)	50 (1H)	100 (2A)	10 (1A)	16 (1C)	25 (1E)	50 (1H)	6.3 (0J)	10 (1A)	16 (1C)	25 (1E)	50 (1H)
Capacitance and	d T Dim	ension	1																
2200pF (222)					0.50 (5)														
4700pF (472)					0.50 (5)					0.80 (8)									
10000pF (103)					0.50 (5)				0.80 (8)										
22000pF (223)				0.50 (5)					0.80 (8)										
47000pF (473)			0.50 (5)						0.80 (8)										
0.10μF (104)			0.50 (5)					0.80 (8)						0.85 (9)					
0.22μF (224)		0.50 (5)					0.80 (8)						0.85 (9)	1.25 (B)					
0.47μF (474)		0.50 (5)				0.80 (8)	0.80 (8)						1.25 (B)						1.15 (M)
1.0μF (105)	0.50 (5)					0.80 (8)					0.85 (9)	0.85 (9)	0.85 (9)				0.85 (9)	1.15 (M)	
2.2μF (225)											1.25 (B)	1.25 (B)	1.25 (B)			0.85 (9)	1.15 (M)		
4.7μF (475)											1.25 (B)					1.15 (M)	1.15 (M)		
10.0μF (106)															1.15 (M)	1.15 (M)			

The part numbering code is shown in each ().



 $^{0.10 \}mu F$, 50V rated are GRM21 series of L:2±0.15, W:1.25±0.15, T:1.25±0.15.

 $T:1.25\pm0.1$ mm is also available for GRM31 $1.0\mu F$ for 16V.

The torelance will be changed to L:3.2 \pm 0.2,W:1.6 \pm 0.2 for GRM31 16V 1.0 μ F type. Also L:3.2 \pm 0.2, W:1.6 \pm 0.2, T:1.15 \pm 0.15 for GRM31 16V 1.5 μ F and 2.2 μ F type.

Dimensions are shown in mm and Rated Voltage in Vdc.

 $T:1.25\pm0.1$ mm is also available for GRM21 25V or 16V 1.0 μ F type.

Dimensions are shown in mm and Rated Voltage in Vdc.

High Dielectric Constant Type Z5U(E4) Characteristics

тс		Z5U (E4)	
Part Number	GRM18	GRM21	GRM31
L x W [EIA]	1.60x0.80 [0603]	2.00x1.25 [0805]	3.20x1.60 [1206]
Rated Volt.	50 (1H)	50 (1H)	50 (1H)
Capacitance and	T Dimension		
10000pF(103)	0.80(8)		
22000pF(223)	0.80(8)		
47000pF(473)		0.60(6)	
0.10μF(104)		0.85 (9)	
0.22μF(224)			0.85 (9)

The part numbering code is shown in $\ (\).$

Dimensions are shown in mm and Rated Voltage in Vdc.

Chip Monolithic Ceramic Capacitors

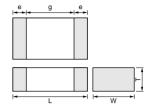


for Reflow Soldering GRM32/43/55 Series

■ Features

- 1. Terminations are made of metal highly resistant to migration.
- The GRM series is a complete line of chip ceramic capacitors in 10V, 16V, 25V, 50V and 100V ratings.
 These capacitors have temperature characteristics ranging from C0G to Y5V.
- 3. This series consists of type LxWxT:3.2x2.5x0.85mm to LxWxT:5.7x5.9x2.0mm. These are suited to only reflow soldering.
- Stringent dimensional tolerances allow highly reliable, high speed automatic chip placement on PCBs.
- The GRM series is available in paper or plastic embossed tape and reel packaging for automatic placement.





Part Number		Dir	mensions (m	ım)	
Part Number	L	W	Т	e min.	g min.
GRM329			0.85 ±0.1		
GRM32M	3.2 ±0.3		1.15 ±0.1		
GRM32N		2.5 ±0.2	1.35 ±0.15	0.3	1.0
GRM32R			1.8 ±0.2		
GRM32E			2.5 ±0.2		
GRM43M			1.15 ±0.1	0.3	
GRM43N	4.5 ±0.4	3.2 ±0.3	1.35 ±0.15		2.0
GRM43R			1.8 ±0.2		
GRM55N	5.7 ±0.4	5.0 ±0.4	1.35 ±0.15	0.3	2.0
GRM55R	5.7 ±0.4	5.0 ±0.4	1.8 ±0.2		2.0

■ Applications

General electronic equipment.

Temperature Compensating Type GRM32 Series (3.20x2.50mm)

Part Number	GRM32							
L x W [EIA]	3.20x2.50 [1210]							
тс	C (5	0G 6C)		SL (1X)				
Rated Volt.	200 (2D)	500 (2H)	50 (1H)	100 (2A)	200 (2D)	500 (2H)		
Capacitance and T	Dimension	<u>'</u>		"				
150pF(151)		1.35(N)						
180pF(181)		1.35(N)						
330pF(331)						1.15(M)		
390pF(391)						1.15(M)		
470pF(471)						1.35(N)		
560pF(561)	1.35(N)							
680pF(681)	1.35(N)							
820pF(821)	1.35(N)							
1000pF(102)	1.35(N)							
1500pF(152)					1.35(N)			
5600pF(562)				1.35(N)				
6800pF(682)				1.35(N)				
10000pF(103)			1.35(N)					
12000pF(123)			1.35(N)					

The part numbering code is shown in ().



Temperature Compensating Type GRM43 Series (4.50x3.20mm)

Part Number	GRM43								
L x W [EIA]	4.50x3.20 [1812]								
тс	C((5	0G 6 C)		S (1)	L X)				
Rated Volt.	200 (2D)	500 (2H)	50 (1H)	100 (2A)	200 (2D)	500 (2H)			
Capacitance and T	Dimension								
220pF(221)		1.80(R)							
270pF(271)		1.80(R)							
330pF(331)		1.80(R)							
390pF(391)		1.80(R)							
470pF(471)		1.80(R)							
560pF(561)						1.15(M)			
680pF(681)						1.15(M)			
820pF(821)						1.35(N)			
1000pF(102)						1.80(R)			
1200pF(122)	1.80(R)					1.80(R)			
1500pF(152)	1.80(R)								
1800pF(182)	1.80(R)				1.35(N)				
2200pF(222)	1.80(R)								
2700pF(272)	1.80(R)				1.80(R)				
3300pF(332)					1.80(R)				
3900pF(392)					1.80(R)				
8200pF(822)				1.35(N)					
10000pF(103)				1.80(R)					
12000pF(123)				1.80(R)					
15000pF(153)			1.80(R)	1.80(R)					

The part numbering code is shown in $\,$ ().

Dimensions are shown in mm and Rated Voltage in Vdc.

Temperature Compensating Type GRM55 Series (5.70x5.00mm)

Part Number	GRM55						
L x W [EIA]	5.70x5.00 [2220]						
тс	C0 (5 0	G C)		SL (1X)			
Rated Volt.	200 (2D)	500 (2H)	50 (1H)	100 (2A)	200 (2D)		
Capacitance and T	Dimension						
560pF(561)		1.80(R)					
680pF(681)		1.80(R)					
820pF(821)		1.80(R)					
1000pF(102)		1.80(R)					
3300pF(332)	1.35(N)						
3900pF(392)	1.80(R)						
4700pF(472)	1.80(R)				1.35(N)		
5600pF(562)	1.80(R)				1.80(R)		
6800pF(682)					1.80(R)		
8200pF(822)					1.80(R)		
18000pF(183)			1.15(M)	1.15(M)			
22000pF(223)			1.35(N)	1.35 (N)			
27000pF(273)			1.80(R)	1.80 (R)			
33000pF(333)			1.80(R)	1.80 (R)			
39000pF(393)			1.80(R)	1.80(R)			

The part numbering code is shown in $\ (\).$



High Dielectric Constant Type GRM32 Series (3.20x2.50mm)

Part Number	GRM32							
L x W [EIA]				3.20x2.	50 [1210]			
тс	X5R (R6)	X7R (R7)				Y5V (F5)		
Rated Volt.	10 (1A)	16 (1C)	25 (1E)	50 (1H)	100 (2A)	16 (1C)	25 (1E)	50 (1H)
Capacitance and	T Dimension	'						
68000pF(683)					1.35(N)			
0.10μF(104)					1.35(N)			
0.68μF(684)				1.35(N)				
1.0μF(105)				1.80(R)				1.8(R)
2.2μF(225)		1.15(M)	1.80(R)					
3.3μF(335)		1.35(N)						
4.7μF(475)		1.80(R)					0.85(9)	
10μF(106)	2.50(E)					1.35(N)	1.35(N)	

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

High Dielectric Constant Type GRM43 Series (4.50x3.20mm)

Part Number	GRM43
L x W [EIA]	4.50x3.20 [1812]
тс	X7R (R7)
Rated Volt.	100 (2A)
Capacitance and	d T Dimension
0.15μF(154)	1.80(R)
0.22μF(224)	1.80(R)

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

High Dielectric Constant Type GRM55 Series (5.70x5.00mm)

Part Number	GRM55					
L x W [EIA]	5.70x5.0	5.70x5.00 [2220]				
тс	X7R (R7)					
Rated Volt.	50 (1H)	100 (2A)				
Capacitance and	T Dimension					
0.33μF(334)		1.80(R)				
0.47μF(474)		1.80(R)				
1.0μF(105)	1.80(R)					
1.5μF(155)	1.80(R)					

The part numbering code is shown in ().

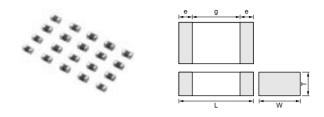
Chip Monolithic Ceramic Capacitors



Ultra-small GRP03 Series

■ Features

- 1. Small chip size (LxWxT:0.6x0.3x0.3mm).
- 2. Terminations are made of metal highly resistant to migration.
- 3. GRP03 type is suited to only reflow soldering.
- 4. Stringent dimensional tolerances are allow highly reliable, high speed autom atic chip placements on PCBs.
- GRP03 series are suited to miniature micro wave module, portable equipment and high-frequency circuit.



Part Number	Dimensions (mm)					
	L	W	T	е	g min.	
GRP033	0.6 ±0.03	0.3 ±0.03	0.3 ±0.03	0.1 to 0.2	0.2	

■ Applications

- Miniature micro wave module.
- Portable equipment.
- High-frequency circuit.

Part Number		GR	P03					
LxW	0.6x0.3							
тс	C0G (5C)	X [*] (R	7R 77)	Y5V (F5)				
Rated Volt.	25 (1E)	6.3 (0J)	16 (1C)	10 (1A)				
Capacitance and T Di	mension							
0.5pF(R50)	0.3(3)							
1pF(1R0)	0.3(3)							
2pF(2R0)	0.3 (3)							
3pF(3R0)	0.3 (3)							
4pF(4R0)	0.3 (3)							
5pF(5R0)	0.3(3)							
6pF(6R0)	0.3(3)							
7pF(7R0)	0.3(3)							
8pF(8R0)	0.3(3)							
9pF(9R0)	0.3(3)							
10pF(100)	0.3(3)							
12pF(120)	0.3(3)							
15pF(150)	0.3(3)							
18pF(180)	0.3(3)							
22pF(220)	0.3(3)							
27pF(270)	0.3(3)							
33pF(330)	0.3(3)							
39pF(390)	0.3(3)							
47pF(470)	0.3(3)							
56pF(560)	0.3(3)							
68pF(680)	0.3(3)							
82pF(820)	0.3(3)							
100pF(101)	0.3(3)		0.3(3)					
150pF(151)			0.3(3)					
220pF(221)			0.3(3)					
330pF(331)			0.3(3)					
470pF(471)			0.3(3)					
680pF(681)			0.3(3)					

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Part Number	GRP03						
LxW		0.6x	0.3				
тс	C0G (5C)	X7R (R7)		Y5V (F5)			
Rated Volt.	25 (1E)	6.3 (0J)	16 (1C)	10 (1A)			
Capacitance and T D	imension						
1000pF(102)			0.3(3)				
1500pF(152)		0.3(3)					
2200pF(222)		0.3(3)		0.3(3)			
4700pF(472)		0.3(3)		0.3(3)			
6800pF(682)		0.3(3)					
10000pF(103)		0.3(3)		0.3(3)			

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

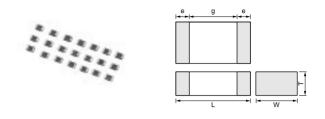
Chip Monolithic Ceramic Capacitors



Thin Type(Flow/Reflow)

■ Features

- This series is suited to flow and reflow soldering.
 Capacitor terminations are made of metal highly resistant to migration.
- 2. Large capacitance values enable excellent bypass effects to be realized.
- 3. Its thin package makes this series ideally suited for the production of small electronic products and for mounting underneath ICs.



Part Number	Dimensions (mm)					
	L	W	Т	е	g min.	
GRP15X	1.0 ±0.05	0.5 ±0.05	0.25 ±0.05	0.15 to 0.3	0.4	

■ Application

hin equipment such as IC cards.

Part Number	тс	Rated Voltage (Vdc)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GRP15X5C1E121JD11	C0G	25	120 ±5%	1.00	0.50	0.25
GRP15X5C1E151JD11	C0G	25	150 ±5%	1.00	0.50	0.25
GRP15X5C1E181JD11	C0G	25	180 ±5%	1.00	0.50	0.25
GRP15X5C1E221JD11	C0G	25	220 ±5%	1.00	0.50	0.25
GRP15X5C1H1R0CD11	C0G	50	1 ±0.25pF	1.00	0.50	0.25
GRP15X5C1H2R0CD11	C0G	50	2 ±0.25pF	1.00	0.50	0.25
GRP15X5C1H3R0CD11	C0G	50	3 ±0.25pF	1.00	0.50	0.25
GRP15X5C1H4R0CD11	C0G	50	4 ±0.25pF	1.00	0.50	0.25
GRP15X5C1H5R0CD11	C0G	50	5 ±0.25pF	1.00	0.50	0.25
GRP15X5C1H6R0DD11	C0G	50	6 ±0.5pF	1.00	0.50	0.25
GRP15X5C1H7R0DD11	C0G	50	7 ±0.5pF	1.00	0.50	0.25
GRP15X5C1H8R0DD11	C0G	50	8 ±0.5pF	1.00	0.50	0.25
GRP15X5C1H9R0DD11	C0G	50	9 ±0.5pF	1.00	0.50	0.25
GRP15X5C1H100JD11	C0G	50	10 ±0.5pF	1.00	0.50	0.25
GRP15X5C1H120JD11	C0G	50	12 ±5%	1.00	0.50	0.25
GRP15X5C1H150JD11	C0G	50	15 ±5%	1.00	0.50	0.25
GRP15X5C1H180JD11	C0G	50	18 ±5%	1.00	0.50	0.25
GRP15X5C1H220JD11	C0G	50	22 ±5%	1.00	0.50	0.25
GRP15X5C1H270JD11	C0G	50	27 ±5%	1.00	0.50	0.25
GRP15X5C1H330JD11	C0G	50	33 ±5%	1.00	0.50	0.25
GRP15X5C1H390JD11	C0G	50	39 ±5%	1.00	0.50	0.25
GRP15X5C1H470JD11	C0G	50	47 ±5%	1.00	0.50	0.25
GRP15X5C1H560JD11	C0G	50	56 ±5%	1.00	0.50	0.25
GRP15X5C1H680JD11	C0G	50	68 ±5%	1.00	0.50	0.25
GRP15X5C1H820JD11	C0G	50	82 ±5%	1.00	0.50	0.25
GRP15X5C1H101JD11	COG	50	100 ±5%	1.00	0.50	0.25

			Specif	ication				
No.	lt€	em	Temperature Compensating Type	High Dielectric Type		Test Method		
1	Operating Tempera	-	-55 to +125℃	R6: -55 to +85°C R7: -55 to +125°C E4: +10 to +85°C F5: -30 to +85°C				
2	2 Rated Voltage		See the previous page.		The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p,p} or V ^{o,p} , whichever is larger, shall be maintained within the rated voltage range.			
3	Appearar	nce	No defects or abnormalities.		Visual inspection.			
4	Dimensio	ns	Within the specified dimensions).	Using calipers on mice	rometer.		
5 Dielectric Strength No defects or abnormalities. No defects or abnormalities.		No failure shall be obs (C0∆ to U2J and SL) of Z5U and Y5V) is appli seconds, provided the 50mA. *200% for 500	or *250% of the rate ed between the term charge/discharge of	d voltage (X5R, X7R, minations for 1 to 5				
6	Insulation Resistan		More than 10,000M Ω or 500 Ω •	F (Whichever is smaller)	The insulation resistar not exceeding the rate within 2 minutes of ch	ed voltage at 25℃ a		
7	Capacita	nce	Within the specified tolerance.	IDC DZI	The capacitance/Q/D. frequency and voltage			
				[R6, R7] W.V.: 25Vmin.: 0.025max.	Item Char		Voltage	
				W.V.: 16/10V: 0.035max. W.V.: 6.3V 0.05max.(C<3.3μF)	ΔC to 7U, 1X (1000pF and below)	1±0.1MHz	0.5 to 5Vrms	
8	Q/ Dissipation Factor (D.F.)		30pFmin. : Q≥1000 30pFmax. : Q≥400+20C C : Nominal Capacitance (pF)	0.1max.(C≥3.3μF) [E4] W.V.: 25Vmin.: 0.025max. [F5] W.V.: 25Vmin. : 0.05max.(C<10μF)	ΔC to 7U, 1X (more than 1000pF)	1±0.1kHz	1±0.2Vrms	
					R6, R7, F5 (10µF and below)	1±0.1kHz	1±0.2Vrms	
				: 0.09max.(C≧1.0µF) W.V. : 16V : 0.07max.(C<1.0µF)	R6, R7, F5 (more than 10µF)	120±24Hz	0.5±0.1Vrms	
				: 0.09max.(C≧1.0µF) W.V. : 10Vmax. : 0.125max.	E4	1±0.1kHz	0.5±0.05Vrms	
	Capacitance Change		Within the specified tolerance. (Table A)	R6: Within±15% (-55 to +85°C) R7: Within±15% (-55 to +125°C) E4: Within +22/-56% (+10 to +85°C) F5: Within +22/-82% (-30 to +85°C)	The capacitance char each specified temper (1) Temperature Com The temperature coef Capacitance measure When cycling the tem 5 (C0∆: +25°C to +12+85°C) the capacitance for the temperature coefficient of the temperatu	ature stage. pensating Type ficient is determined d in step 3 as a refe perature sequential 25°C: other temp. co e shall be within the	I using the erence. Iy from step 1 through offs.: +25°C to be specified tolerance	
	Capacitance	Townson	Mish in the consistent to the		Table A. The capacitance drift is caluculated by dividing the differences between the maximum and minimum measured values in the step 1,3 and 5 by the cap value in step 3.			
9	Temperature Characteristics	Temperature Coefficient	Within the specified tolerance. (Table A)	_	Step 1	Tempera 25±	· '	
	Characteristics				2	-55±3 (for ΔC to -30±3 (10±3 (f	7U/1X/R6/R7) (for F5)	
					3	25±		
					4	125±3 (for ΔC/R7) 85±3 (for other TC)		
		Capacitance	Within ±0.2% or ±0.05pF (Whichever is larger.)		5	25±	· · · · · · · · · · · · · · · · · · ·	
		Drift	i i (vynichever is jarder)			(2) High Dielectric Constant Type The ranges of capacitance change compared with the above 25°C value over the temperature ranges shown in the table shall be within the specified ranges.		

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الخسا	S Continued from the pre			fication	
No.	lte	em	Temperature Compensating Type	fication High Dielectric Type	Test Method
10	Adhesive of Termin	_	No removal of the terminations or other defect shall occur.		Solder the capacitor to the test jig (glass epoxy board) shown in Fig.1 using a eutectic solder. Then apply 10N* force in parallel with the test jig for 10±1sec. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so that the soldering is uniform and gree of defects such as heat shock. *2N (GRP03) 5N (GRP15,GRM18) Solder resist Baked electrode or copper foil
					GRP03 0.3 0.9 0.3 GRP15 0.4 1.5 0.5 GRM18 1.0 3.0 1.2 GRM21 1.2 4.0 1.65 GRM31 2.2 5.0 2.0 GRM32 2.2 5.0 2.9 GRM43 3.5 7.0 3.7 GRM55 4.5 8.0 5.6 (in mm)
		Appearance	No defects or abnormalities.		
		Capacitance	Within the specified tolerance.		
11	Vibration Resistance	Q/D.F.	30pFmin. : Q≥1000 30pFmax. : Q≥400+20C C : Nominal Capacitance (pF)	[R6, R7] W.V.: 25Vmin.: 0.025max. W.V.: 16/10V: 0.035max. W.V.: 6.3V:	Solder the capacitor to the test jig (glass epoxy board) in the same manner and under the same conditions as (10). The capacitor shall be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, shall be traversed in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3 mutually perpendicular directions (total of 6 hours).
12	12 Deflection		Type a GRP03 0.3 GRP15 0.4 GRM18 1.0	t: 1.6mm (GRP03/15: 0.8mm) b c 0.9 0.3 1.5 0.5 3.0 1.2	Solder the capacitor on the test jig (glass epoxy board) shown in Fig. 2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing speed: 1.0mm/sec. Pressurize Capacitance meter 45 45
			GRM21 1.2 GRM31 2.2 GRM32 2.2 GRM43 3.5 GRM55 4.5	4.0 1.65 5.0 2.0 5.0 2.9 7.0 3.7 8.0 5.6 (in mm)	Fig.3

Continued from the preceding page.

			Speci	fication					
No.	lt€	em	Temperature Compensating Type	High Dielectric Type	Test Method				
13	Solderab Terminati	continuously.			Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight propotion). Preheat at 80 to 120°C for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5°C.				
			The measured and observed characteristics shall satisfy the specifications in the following table.						
		Appearance	No marking defects.						
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	R6, R7 : Within ±7.5% E4, F5 : Within ±20%	Preheat the capacitor at 120 to 150°C for 1 minute.				
14	Resistance to Soldering Heat	Q/D.F.	30pFmin. : Q≥1000 30pFmax. : Q≥400+20C C : Nominal Capacitance (pF)	[R6, R7] W.V.: 25Vmin.: 0.025max. W.V.: 16/10V: 0.035max. W.V.: 6.3V:	Immerse the capacitor in a eutectic solder solution at 270±5% for 10±0.5 seconds. Let sit at room temperature for 24±2 hot (temperature compensating type) or 48±4 hours (high dielect constant type), then measure. •Initial measurement for high dielectric constant type Perform a heat treatment at 150 ±₁8℃ for one hour and then let sit for 48±4 hours at room temperature. Perform the initial measurement. *Preheating for GRM32/43/55 Step Temperature Time 1 100℃ to 120℃ 1 min. 2 170℃ to 200℃ 1 min.				
				vv.v To vinax 0.120max.					
		I.R.	More than 10,000MΩ or 500Ω		_				
		I.R. Dielectric Strength	More than 10,000M Ω or 500 Ω No failure						
		Dielectric	·	• F (Whichever is smaller) naracteristics shall safisfy the					
		Dielectric	No failure The measured and observed of	• F (Whichever is smaller) naracteristics shall safisfy the					
		Dielectric Strength	No failure The measured and observed of specifications in the following to	• F (Whichever is smaller) naracteristics shall safisfy the	Fix the capacitor to the supporting jig in the same manner and				
		Dielectric Strength Appearance Capacitance	No failure The measured and observed of specifications in the following to No marking defects. Within ±2.5% or ±0.25pF	• F (Whichever is smaller) • F (Whichever is smaller) naracteristics shall safisfy the able. R6, R7 : Within ±7.5% E4, F5 : Within ±20% [R6, R7] W.V. : 25Vmin. : 0.025max. W.V. : 16/10V : 0.035max. W.V. : 6.3V 0.05max. (C<3.3µF)	Fix the capacitor to the supporting jig in the same manner and under the same conditions as (10). Perform the five cycles according to the four heat treatments listed in the following table. Let sit for 24±2 hours (temperature compensating type or 48±4 hour (high dielectric constant type) at room temperature, then measure.				
	Temperature	Dielectric Strength Appearance Capacitance	No failure The measured and observed of specifications in the following to No marking defects. Within ±2.5% or ±0.25pF	• F (Whichever is smaller) • F (Whichever is smaller) naracteristics shall safisfy the able. R6, R7 : Within ±7.5% E4, F5 : Within ±20% [R6, R7] W.V. : 25Vmin. : 0.025max. W.V. : 16/10V : 0.035max. W.V. : 6.3V 0.05max. (C≤3.3µF) 0.1max. (C≥3.3µF)	under the same conditions as (10). Perform the five cycles according to the four heat treatments listed in the following table. Let sit for 24±2 hours (temperature compensating type or 48±4 hour (high dielectric constant type) at room temperature, then measure. Step 1 2 3 4				
15	Temperature Cycle	Dielectric Strength Appearance Capacitance	No failure The measured and observed of specifications in the following to No marking defects. Within ±2.5% or ±0.25pF (Whichever is larger) 30pFmin.: Q≥1000 30pFmax.: Q≥400+20C	• F (Whichever is smaller) • F (Whichever is smaller) naracteristics shall safisfy the able. R6, R7 : Within ±7.5% E4, F5 : Within ±20% [R6, R7] W.V. : 25Vmin. : 0.025max. W.V. : 16/10V : 0.035max. W.V. : 6.3V 0.05max. (C<3.3µF) 0.1max. (C≥3.3µF) [E4] W.V. : 2.5Vmin. : 0.025max.	under the same conditions as (10). Perform the five cycles according to the four heat treatments listed in the following table. Let sit for 24±2 hours (temperature compensating type or 48±4 hour (high dielectric constant type) at room temperature, then measure. Step 1 2 3 4 Min. Temp.(°C) Operating Room Operating Temperature Temperature Room				
15		Dielectric Strength Appearance Capacitance Change	No failure The measured and observed of specifications in the following to No marking defects. Within ±2.5% or ±0.25pF (Whichever is larger)	• F (Whichever is smaller) • F (Whichever is smaller) naracteristics shall safisfy the able. R6, R7 : Within ±7.5% E4, F5 : Within ±20% [R6, R7] W.V. : 25Vmin. : 0.025max. W.V. : 16/10V : 0.035max. W.V. : 6.3V 0.05max. (C<3.3µF) 0.1max. (C≥3.3µF) [E4]	under the same conditions as (10). Perform the five cycles according to the four heat treatments listed in the following table. Let sit for 24±2 hours (temperature compensating type or 48±4 hour (high dielectric constant type) at room temperature, then measure. Step 1 2 3 4 Min. Temp.(°C) Operating Room Operating Tomp				
15		Dielectric Strength Appearance Capacitance Change	No failure The measured and observed of specifications in the following to No marking defects. Within ±2.5% or ±0.25pF (Whichever is larger) 30pFmin.: Q≥1000 30pFmax.: Q≥400+20C	• F (Whichever is smaller) • F (Whichever is smaller) naracteristics shall safisfy the able. R6, R7 : Within ±7.5% E4, F5 : Within ±20% [R6, R7] W.V. : 25Vmin. : 0.025max. W.V. : 16/10V : 0.035max. W.V. : 6.3V 0.05max. (C<3.3µF) 0.1max. (C≥3.3µF) [E4] W.V. : 2.5Vmin. : 0.025max. [F5] W.V. : 2.5Vmin. : 0.025max. [F5] W.V. : 25Vmin. : 0.05max. (C<1.0µF) : 0.09max. (C≥1.0µF) W.V. : 16V : 0.07max. (C≤1.0µF) : 0.09max. (C≥1.0µF)	under the same conditions as (10). Perform the five cycles according to the four heat treatments listed in the following table. Let sit for 24±2 hours (temperature compensating type or 48±4 hour (high dielectric constant type) at room temperature, then measure. Step				

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			Specif	ication	
No.	Ite	em	Temperature Compensating Type	High Dielectric Type	Test Method
			The measured and observed chapecifications in the following ta	•	
		Appearance	No marking defects.		
		Capacitance Change	Within ±5% or ±0.5pF (Whichever is larger)	R6, R7 : Within ±12.5% E4, F5 : Within ±30%	
16	Humidity Steady State	Q/D.F.	30pF and over : Q≥350 10pF and over 30pF and below : Q≥275+5C/2 10pF and below : Q≥200+10C C : Nominal Capacitance (pF)	[R6, R7] W.V.: 25Vmin.: 0.05max. W.V.: 16/10V: 0.05max. W.V.: 6.3V 0.075max. (C<3.3μF) 0.125max. (C≥3.3μF) [E4] W.V.: 25Vmin.: 0.05max. [F5] W.V.: 25Vmin. : 0.075max. (C<1.0μF) : 0.0125max. (C≥1.0μF) W.V.: 16V : 0.1max. (C<1.0μF) : 0.125max. (C≥1.0μF) W.V.: 10Vmax.: 0.15max.	Sit the capacitor at 40±2°C and 90 to 95% humiduty for 500±12 hours. Remove and let sit for 24±2 hours (temperature compensating type) or 48±4 hours (high dielectric constant type) at room temperature, then measure.
		I.R.	More than 1,000M Ω or 50 Ω • F	(Whichever is smaller)	
		Dielectric Strength	No failure		
		The measured and observed characteristics shall satisfy the specifications in the following table.			
		Appearance	No marking defects.		
		Capacitance Change	Within ±7.5% or ±0.75pF (Whichever is larger)	R6, R7 : Within ±12.5% E4 : Within ±30% F5 : Within ±30% [W.V. : 10Vmax.] F5 : Within +30/-40%	
17	Humidity Load	Q/D.F.	30pF and over : Q≥200 30pF and below : Q≥100±10C/3 C : Nominal Capacitance (pF)	[R6, R7] W.V.: 25Vmin.: 0.05max. W.V.: 16/10V: 0.05max. W.V.: 6.3V 0.075max. (C<3.3μF) 0.125max. (C≥3.3μF) [E4] W.V.: 25Vmin.: 0.05max. [F5] W.V.: 25Vmin. : 0.075max. (C<1.0μF) : 0.0125max. (C≥1.0μF)	Apply the rated voltage at 40±2℃ and 90 to 95% humidity for 500±12 hours. Remove and let sit for 24±2 hours (temperature compensating type) or 48±4 hours (high dielectric constant type) at room temperature, then muasure. The charge/discharge current is less than 50mA. •Initial measurement for F5/10Vmax. Apply the rated DC voltage for 1 hour at 40±2℃. Remove and let sit for 48±4 hours at room temperature. Perform initial measurement.
				W.V. : 16V : 0.1max. (C<1.0μF) : 0.125max. (C≥1.0μF) W.V. : 10Vmax. : 0.15max.	
		I.R.	More than $500\text{M}\Omega$ or $25\Omega \bullet \text{F(W)}$	/hichever is smaller)	
		Dielectric Strength	No failure		

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			Specif	ication	
No.	lt∈	em	Temperature Compensating Type	High Dielectric Type	Test Method
			The measured and observed characteristics shall satisfy the specifications in the following table.		
		Appearance	No marking defects.		
		Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	R6, R7 : Within ±12.5% E4 : Within ±30% F5 : Within ±30% (Cap<1.0µF) F5 : Within +30/-40%(Cap≧1.0µF)	Apply 200% of the rated voltage for 1000±12 hours at the maximun operating temperature ±3°C. Let sit for 24±2 hours
18	High Temperature Load	Q/D.F.	30pF and over : Q≥350 10pF and over 30pF and below : Q≥275±5C/2 10pF and below : Q≥200±10C C : Nominal Capacitance (pF)	[R6, R7] W.V.: 25Vmin.: 0.05max. W.V.: 16/10V: 0.05max. W.V.: 6.3V 0.075max. (C<3.3μF) 0.125max. (C≥3.3μF) [E4] W.V.: 25Vmin.: 0.05max [F5] W.V.: 25Vmin. : 0.075max. (C<1.0μF) : 0.0125max.(C≥1.0μF) W.V.: 16V : 0.1max. (C<1.0μF) : 0.125max. (C≥1.0μF) W.V.: 10Vmax.: 0.15max.	(temperature compensating type) or 48±4 hours (high dielectric constant type) at room temperature, then measure. The charge/discharge current is less than 50mA. •Initial measurement for high dielectric constant type. Apply 200% of the rated DC voltage for one hour at the maximun operating temperature ±3℃. Remove and let sit for 48±4 hours at room temperature. Perform initial measurement. *150% for 500V and C≥10μF
		I.R.	More than 1,000M Ω or 50 Ω •F(\)	Whichever is smaller)	
		Dielectric Strength	No failure		
19	Notice		When mounting capacitor of 50	0V rated voltage, perform the epo	oxy resin coating(min.1.0mm thickness)

Table A

		Capacitance Change from 25℃ (%)						
Char. Code	Nominal Values (ppm/°C)*	- 55		-30		-10		
		Max.	Min.	Max.	Min.	Max.	Min.	
5C	0± 30	0.58	-0.24	0.40	-0.17	0.25	-0.11	
6C	0± 60	0.87	-0.48	0.59	-0.33	0.38	-0.21	
6P	-150± 60	2.33	0.72	1.61	0.50	1.02	0.32	
6R	-220± 60	3.02	1.28	2.08	0.88	1.32	0.56	
6S	-330± 60	4.09	2.16	2.81	1.49	1.79	0.95	
6T	-470± 60	5.46	3.28	3.75	2.26	2.39	1.44	
7U	-750±120	8.78	5.04	6.04	3.47	3.84	2.21	
1X	+350 to -1000	_	_	_	_	_	_	

^{*}Nominal values denote the temperature coefficient within a range of 25℃ to 125℃ (for ΔC)/85℃ (for other TC).



Chip Monolithic Ceramic Capacitors



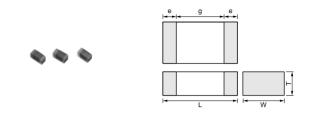
High-power Type

■ Features

- 1. Mobile Telecommunication and RF module, mainly.
- 2. Quality improvement of telephone call, Low power consumption, yield ratio improvement.

■ Applications

VCO, PA, Mobile Telecommunication



Part Number	Dimensions (mm)						
Part Number	L	W	T	е	g min.		
GJ6155	1.0 ±0.05	0.5 ±0.05	0.5 ±0.05	0.15 to 0.3	0.4		

Part Number	тс	Rated Voltage (Vdc)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GJ61555C1HR50BB01	COG	50	0.5 ±0.1pF	1.00	0.50	0.50
GJ61555C1HR50CB01	COG	50	0.50 ±0.25pF	1.00	0.50	0.50
GJ61555C1HR75BB01	COG	50	0.75 ±0.1pF	1.00	0.50	0.50
GJ61555C1HR75CB01	COG	50	0.75 ±0.25pF	1.00	0.50	0.50
GJ61555C1H1R0BB01	COG	50	1.0 ±0.1pF	1.00	0.50	0.50
GJ61555C1H1R0CB01	COG	50	1.0 ±0.25pF	1.00	0.50	0.50
GJ61555C1H1R1BB01	COG	50	1.1 ±0.1pF	1.00	0.50	0.50
GJ61555C1H1R2BB01	COG	50	1.2 ±0.1pF	1.00	0.50	0.50
GJ61555C1H1R3BB01	COG	50	1.3 ±0.1pF	1.00	0.50	0.50
GJ61555C1H1R5BB01	C0G	50	1.5 ±0.1pF	1.00	0.50	0.50
GJ61555C1H1R5CB01	C0G	50	1.5 ±0.25pF	1.00	0.50	0.50
GJ61555C1H1R6BB01	C0G	50	1.6 ±0.1pF	1.00	0.50	0.50
GJ61555C1H1R8BB01	C0G	50	1.8 ±0.1pF	1.00	0.50	0.50
GJ61555C1H2R0BB01	C0G	50	2.0 ±0.1pF	1.00	0.50	0.50
GJ61555C1H2R0CB01	C0G	50	2.0 ±0.25pF	1.00	0.50	0.50
GJ61555C1H2R2BB01	C0G	50	2.2 ±0.1pF	1.00	0.50	0.50
GJ61555C1H2R4BB01	C0G	50	2.4 ±0.1pF	1.00	0.50	0.50
GJ61555C1H2R7BB01	C0G	50	2.7 ±0.1pF	1.00	0.50	0.50
GJ61555C1H3R0BB01	C0G	50	3.0 ±0.1pF	1.00	0.50	0.50
GJ61555C1H3R0CB01	C0G	50	3.0 ±0.25pF	1.00	0.50	0.50
GJ61555C1H3R3BB01	C0G	50	3.3 ±0.1pF	1.00	0.50	0.50
GJ61555C1H3R6BB01	C0G	50	3.6 ±0.1pF	1.00	0.50	0.50
GJ61555C1H3R9BB01	C0G	50	3.9 ±0.1pF	1.00	0.50	0.50
GJ61555C1H4R0BB01	C0G	50	4.0 ±0.1pF	1.00	0.50	0.50
GJ61555C1H4R0CB01	C0G	50	4.0 ±0.25pF	1.00	0.50	0.50
GJ61555C1H4R3BB01	C0G	50	4.3 ±0.1pF	1.00	0.50	0.50
GJ61555C1H4R7BB01	C0G	50	4.7 ±0.1pF	1.00	0.50	0.50
GJ61555C1H5R0BB01	C0G	50	5.0 ±0.1pF	1.00	0.50	0.50
GJ61555C1H5R0CB01	C0G	50	5.0 ±0.25pF	1.00	0.50	0.50
GJ61555C1H5R1CB01	C0G	50	5.1 ±0.25pF	1.00	0.50	0.50
GJ61555C1H5R6CB01	C0G	50	5.6 ±0.25pF	1.00	0.50	0.50
GJ61555C1H6R0CB01	C0G	50	6.0 ±0.25pF	1.00	0.50	0.50
GJ61555C1H6R0DB01	C0G	50	6.0 ±0.5pF	1.00	0.50	0.50
GJ61555C1H6R2CB01	C0G	50	6.2 ±0.25pF	1.00	0.50	0.50
GJ61555C1H6R8CB01	C0G	50	6.8 ±0.25pF	1.00	0.50	0.50
GJ61555C1H7R0CB01	C0G	50	7.0 ±0.25pF	1.00	0.50	0.50
GJ61555C1H7R0DB01	C0G	50	7.0 ±0.5pF	1.00	0.50	0.50
GJ61555C1H7R5CB01	C0G	50	7.5 ±0.25pF	1.00	0.50	0.50

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Part Number	тс	Rated Voltage (Vdc)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GJ61555C1H8R0CB01	COG	50	8.0 ±0.25pF	1.00	0.50	0.50
GJ61555C1H8R0DB01	COG	50	8.0 ±0.5pF	1.00	0.50	0.50
GJ61555C1H8R2CB01	COG	50	8.2 ±0.25pF	1.00	0.50	0.50
GJ61555C1H9R0CB01	COG	50	9.0 ±0.25pF	1.00	0.50	0.50
GJ61555C1H9R0DB01	COG	50	9.0 ±0.5pF	1.00	0.50	0.50
GJ61555C1H9R1CB01	COG	50	9.1 ±0.25pF	1.00	0.50	0.50
GJ61555C1H100JB01	COG	50	10.0 ±0.5pF	1.00	0.50	0.50
GJ61555C1H100RB01	COG	50	10 ±0.25pF	1.00	0.50	0.50
GJ61555C1H120GB01	COG	50	12 ±2%	1.00	0.50	0.50
GJ61555C1H120JB01	COG	50	12 ±5%	1.00	0.50	0.50
GJ61555C1H150GB01	COG	50	15 ±2%	1.00	0.50	0.50
GJ61555C1H150JB01	COG	50	15 ±5%	1.00	0.50	0.50
GJ61555C1H180GB01	C0G	50	18 ±2%	1.00	0.50	0.50
GJ61555C1H180JB01	C0G	50	18 ±5%	1.00	0.50	0.50
GJ61555C1H200GB01	COG	50	20 ±2%	1.00	0.50	0.50

		Specification											
Ite	em	Temperature Compensating Type	_	Test Method									
	ure Range	-55 to +125°C											
2 Rated Voltage		See the previous pages.	may be applied contin When AC voltage is su	efined as the maximum voltage which uously to the capacitor. uperimposed on DC voltage, V ^{p.p} or V ^{o.p} , all be maintained within the rated voltage									
Appearar	nce	No defects or abnormalities.	Visual inspection.										
Dimensio	ns	Within the specified dimensions.	Using calipers.										
Dielectric	Strength	No defects or abnormalities.	applied between the te	served when 300% of the rated voltage is erminations for 1 to 5 seconds, provided current is less than 50mA.									
Insulation (I.R.)	Resistance	10,000M Ω min. or 500 Ω • F min. (Whichever is smaller)		nce shall be measured with a DC voltage and voltage at 25°C and 75%RH max. and arging.									
Capacita	nce	Within the specified tolerance.	•	all be measured at 25℃ at the frequency									
	20nE min · O>4 000												
Q		30pF max. : Q≧4,000 30pF max. : Q≥400+20C		1±0.1MHz									
		C : Nominal Capacitance (pF)	Voltage	0.5 to 5Vr.m.s.									
	Capacitance Change	Within the specified tolerance. (Table A-1)	each specified temper										
	Temperature Coefficent	Within the specified tolerance. (Table A-1)	The temperature coeff	icient is determined using the									
Capacitance Temperature Characteristics	mperature	Within $\pm 0.2\%$ or ± 0.05 pF	When cycling the temp 5, (CoG: +25°C to+12 the capacitance shall I temperature coefficien The capacitance drift i	perature sequentially from step 1 through 25°C: other temp. coeffs.: +25°C to 85°C) be within the specified tolerance for the and capacitance change as Table A. It is calculated by dividing the differences and minimum measured values in the									
		Drift	Drift	Drift	Drift	Drift	Drift	Drift	Drift	Drift	(Whichever is larger.)	Step	Temperature(°C)
				25±2									
						125±3							
			5	25±2									
Adhesive Strength of Termination		No removal of the terminations or other defect shall occur.	Solder the capacitor to Fig.1 using a eutectic s with the test jig for 10± The soldering shall be comethod and shall be comethod.	the test jig (glass epoxy board) shown in older. Then apply a 5N force in parallel									
	Operating Temperature Rated Vo Appearar Dimension Dielectricular Insulation (I.R.) Capacitan Q Capacitance Temperature Characteristics	Operating Temperature Range Rated Voltage Appearance Dimensions Dielectric Strength Insulation Resistance (I.R.) Capacitance Q Capacitance Change Temperature Coefficent Capacitance Capacitance Coefficent Capacitance Capacitance Coefficent	Temperature Compensating Type	Temperature Compensating Type									

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<u> </u>	Continued from the preceding page.								
			Specification						
No.	No. Item		Temperature Compensating Type		Tes	st Metho	d		
		Appearance	No defects or abnormalities.	Solder the capacitor to the test jig (glass epoxy board) in the same manner and under the same conditions as (10).				•	
11	Vibration Resistance Q		30pF min. : Q≥1,000 30pF max. : Q≥400+20C C : Nominal Capacitance (pF)		The capacitor shall be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, shall be traversed in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3 mutually perpendicula directions (total of 6 hours). Solder the capacitor to the test jig (glass epoxy boards) shown			ic motion ng varied 55Hz. The z, shall be all be	
			No cracking or marking defects shall occur.	in Fig.2 using Then apply a The soldering reflow method	a eutectic sold force in the dire shall be done I and shall be d	er. ection she either wit onducted		ng the	
12	Deflection	1	Type a b c GJ615 0.4 1.5 0.5 (in mm)	5	R230 Capacitan 45	Pressu	d : 1.0mm/sec.)	
			i ig.z		Fig.:	3	•		
13		Solderability of Termination 75% of the terminations is to be soldered evenly and continuously. rosin Preh				Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120℃ for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5℃.			
			The measured and observed characteristics shall satisfy the specifications in the following table.						
		Appearance	No marking defects.						
	Resistance	Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	Preheat the capacitor at 120 to 150°C for 1 r Immerse the capacitor in a eutectic solder s for 10±0.5 seconds. Let sit at room temperature for 24±2 hours.					
14	to Soldering Heat	Q	30pF and over : Q≥1,000 30pF and below : Q≥400+20C C : Nominal Capacitance (pF)				24±2 hours.		
		I.R.	More than $10,000M\Omega$ or $500\Omega \bullet F$ (Whichever is smaller)						
		Dielectric Strength	No failure						
			The measured and observed characteristics shall satisfy the specifications in the following table.		Fix the capacitor to the supporting jig in the same manner and				
		Appearance	No marking defects.	1			n the same mar rform the five cy		
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)				isted in the follo ature, then mea		
15	Temperature Cycle	·	30pF and over : Q≥1,000	Step	1	2	3	4	
	0,5.0	Q	30pF and below : Q≥400+20C C : Nominal Capacitance (pF)	Temp.(℃)	Min. Operating Temp. $\stackrel{+0}{-3}$	Room Temp.	Max. Operating Temp. $\overset{+3}{-}$	Room Temp.	
		I.R.	More than 10,000MΩ or 500Ω • F (Whichever is smaller)	Time(min.)	30±3	2 to 3	30±3	2 to 3	
		Dielectric Strength	No failure						
			The measured and observed characteristics shall satisfy the specifications in the following table.						
		Appearance	No marking defects.	_					
16	Humidity, Steady	Capacitance Change	Within ±5% or ±0.5pF (Whichever is larger)	hours.			95% humidity f		
16	State	Q	30pF and over. : Q≥350 10pF and over, 30pF and below : Q≥275+ ½ C 10pF and below : Q≥200+10C C : Nominal Capacitance (pF)		et sit for 24±2 temperature, th		emperature com sure.	pensating	
		I.R.	More than 10,000MΩ or 500Ω • F (Whichever is smaller)						

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			Specification	
No.	lt∈	em	Temperature Compensating Type	Test Method
			The measured and observed characteristics shall satisfy the specifications in the following table.	
		Appearance	No marking defects.	
	l looma i alikoo	Capacitance Change	Within ±7.5% or ±0.75pF (Whichever is larger)	Apply the rated voltage at 40±2°C and 90 to 95% humidity for 500±12 hours.
17	Humidity Load	Q	30pF and over : Q≥200 30pF and below : Q≥100+ ½ C C : Nominal Capacitance (pF)	Remove and let sit for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA.
		I.R.	More than $500 \mathrm{M}\Omega$ or 25Ω • F (Whichever is smaller)	
		Dielectric Strength	No failure	
			The measured and observed characteristics shall satisfy the specifications in the following table.	
		Appearance	No marking defects.	
	l liah	Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	Apply 200% of the rated voltage for 1000±12 hours at the
18	High Temperature Load	Q	30pF and over. : Q≥350 10pF and over, 30pF and below : Q≥275+ ½ C 10pF and below : Q≥200+10C C : Nominal Capacitance (pF)	maximum operating temperature ±3℃. Let sit for 24±2 hours (temperature compensating type) at room temperature, then measure. The charge/discharge current is less than 50mA.
		I.R.	More than 1,000M Ω or 50 Ω • F (Whichever is smaller)	
		Dielectric Strength	No failure	
19	ESR		0.5pF≦C≦1pF : 350mΩ . pF below 1pF <c≦5pf 300mω="" :="" below<br="">5pF<c≦10pf 250mω="" :="" below<="" td=""><td>The ESR shall be measured at room Temp. and frequency 1±0.2GHz with the equivalent of BOONTON Model 34A.</td></c≦10pf></c≦5pf>	The ESR shall be measured at room Temp. and frequency 1±0.2GHz with the equivalent of BOONTON Model 34A.
			10pF <c≦20pf 400mω="" :="" below<="" td=""><td>The ESR shall be measured at room Temp. and frequency 500±50MHz with the equivalent of HP8753B.</td></c≦20pf>	The ESR shall be measured at room Temp. and frequency 500±50MHz with the equivalent of HP8753B.

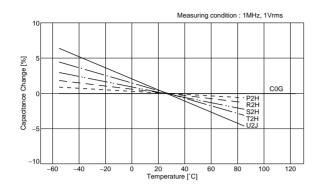
Table A

	T 0 "		Cap	oacitance Change	e from 25℃ Value	(%)	
Char. Code	Temp. Coeff. (ppm/℃) Note 1	− 55℃		-30℃		−10 ℃	
	(ppin/c) Note i	Max.	Min.	Max.	Min.	Max.	Min.
5C	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11

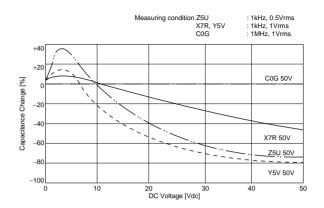
Note 1 : Nominal values denote the temperature coefficient within a range of 25 to 125°C.(for C0 Δ)

GRP/GRM Series Data

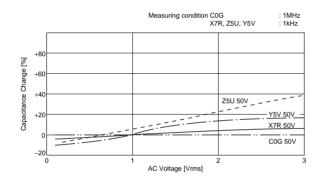
■ Capacitance-Temperature Characterstics



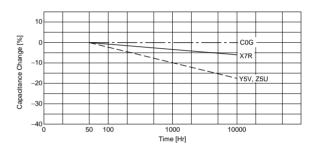
■ Capcitance-DC Voltage Characteristics



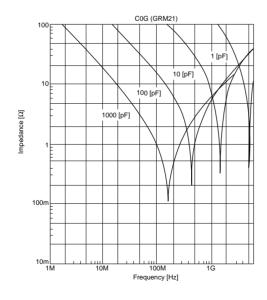
■ Capcitance-AC Voltage Characteristics



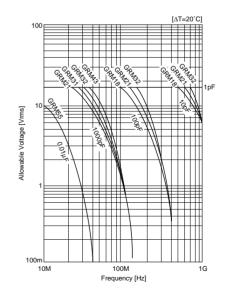
■ Capacitance Change-Aging



■ Impedance-Frequency Characteristics



■ Allowable Voltage-Frequency



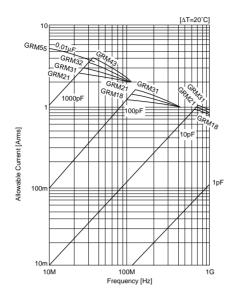
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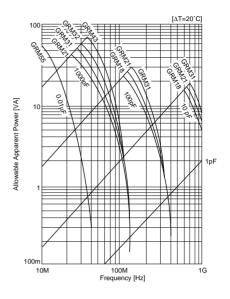
GRP/GRM Series Data

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■ Allowable Current-Frequency



■ Allowable Appearant Power



Chip Monolithic Ceramic Capacitors



for Smoothing

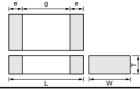
■ Features

- 1. Heat generation is low at high frequency because of low dielectric loss.
- 2. Compared with aluminum electrolytic capacitors, capacitance can be lower to obtain the same smoothing performance.
- 3. Ceramic capacitor has no polarity and ensures long life time.

■ Applications

- DC-DC converter
- Noise elimination LCD bias circuit (Use for only alumina, paper or glass epoxy board)





Part Number	Dimensions (mm)					
rait Number	L	W	Т	e min.	g min.	
GJ221B	2.0 ±0.1	1.25 ±0.1	1.25 ±0.1	0.2 to 0.7	0.7	
GJ231M	3.2 ±0.15	1.6 ±0.15	1.15 ±0.1	0.3 to 0.8	1.5	
GJ232N			1.35 ±0.15			
GJ232C	3.2 ±0.3	2.5 ±0.2	1.6 ±0.15	0.3	1.0	
GJ232R			1.8 ±0.2			
GJ243R	4.5 ±0.4	3.2 +0.3	1.8 ±0.2	0.3	2.0	
GJ243X	4.5 ±0.4	3.2 ±0.3	2.2 ±0.3	0.3	2.0	

Part Number	тс	Rated Voltage (Vdc)	Capacitance (μF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GJ221BF50J106ZD01	Y5V	6.3	10 +8020%	2.00	1.25	1.25
GJ231MF50J226ZD01	Y5V	6.3	22 +8020%	3.20	1.60	1.15
GJ232CF50J476ZD01	Y5V	6.3	47 +8020%	3.20	2.50	1.60
GJ243RF50J107ZD11	Y5V	6.3	100 +8020%	4.50	3.20	1.80
GJ232NF51A226ZD01	Y5V	10	22 +8020%	3.20	2.50	1.35
GJ232RF51H475ZD01	Y5V	50	4.7 +8020%	3.20	2.50	1.80
GJ243XF51H106ZD12	Y5V	50	10 +8020%	4.50	3.20	2.20
GJ232RF52A105ZD01	Y5V	100	1 +8020%	3.20	2.50	1.8

No.	Item	Specification	Test Method	
1	Operating Temperature Range	F5 : -30°C to 85°C		
2	Rated Voltage	See the previous pages.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p.p} or V ^{0.p} , whichever is larger, shall be maintained within the rated voltage range.	
3	Appearance	No defects or abnormalities.	Visual inspection.	
4	Dimensions	Within the specified dimension.	Using calipers.	
5	Dielectric Strength	No defects or abnormalities.	No failure shall be observed when 250% of the rated voltage is applied between the both terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA.	
6	Insulation Resistance	More than 10,000M Ω or 500 Ω · F. (Whichever is smaller)	The insulation resistance shall be measured with a DC voltage not exceeding the rated voltage at normal temperature and humidity and within 2 minutes* of charging. *5minutes for c>47µF.	
7	Capacitance	Within the specified tolerance.	The capacitance/D.F. shall be measured at 25°C at the fre-	
8	Dissipation Factor (D.F.)	0.07 max. (50/100V) 0.09 max. (10/16/25V) 0.15 max. (6.3V)	quency and voltage shown in the table. Capacitance Frequency Voltage C≤10µF 1±0.1kHz 1±0.2Vrms C>10µF 120±24Hz 0.5±0.1Vrms	
9	Capacitance Temperature Characteristics	Char. Temp. Reference Cap. Change Temp. Rate F5 -30 to +85°C 25°C Within +22%	The capacitance change shall be measured after 5 min. at each specified temperature stage. The ranges of capacitance change compared to 25°C with the temperature ranges shown in the table shall be within the specified ranges.	
10	Adhesive Strength of Termination	No removal of the terminations or other defects shall occur. C Baked electrode or copper foil Fig.1	Solder the capacitor on the testing jig (glass epoxy board) shown in Fig.1 using a eutectic solder. Then apply 5N force in parallel with the test jig for 10±1 sec. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so that the soldering is uniform and free of defect such as heat shock. Type a b c GJ218 1.0 3.0 1.2 GJ221 1.2 4.0 1.65 GJ231 2.2 5.0 2.0 GJ232 2.2 5.0 2.9 GJ243 3.5 7.0 3.7 (in mm)	
11	Vibration Resistance	Item Frequency Appearance No defects or abnormalities. Capacitance Change Within the specified tolerance. D.F. 50, 100V 10, 16, 25V 6.3V 0.07 max. Dielectric Strength No failure	Solder the capacitor on the testing jig (glass epoxy board) in the same manner and under the same conditions as (10). The capacitor shall be subjected to simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, shall be traversed in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3 mutually perpendicular directions (total of 6 hours).	

Continued on the following page.





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No.	Item	Specification	Test Method	
12	Deflection	Solder the capacitor to the test jig (glass epoxy be in Fig.2 using a eutectic solder. Then apply a for tion shown in Fig.3 for 5±1 sec. The soldering she either with an iron or using the reflow method and ducted with care so that the soldering is uniform defects such as heat shock. Fig.3 Fig.3 Fig.2 Type a b c GJ218 1.0 3.0 1.2 GJ221 1.2 4.0 1.65 GJ221 1.2 4.0 1.65 GJ231 2.2 5.0 2.0 GJ232 2.2 5.0 2.9 GJ233 3.5 7.0 3.7		
13	Solderability of Termination	75% of the terminations is to be soldered evenly and continuously.	Immerse the capacitor first ethanol (JIS-K-8101)a solution of rosin (JIS-K-5902) (25% rosin in weight proportion), then in an eutectic solder solution for 2±0.5 seconds at 230±5°C after preheating in the following table. then set it for 48±4 hours at room temperature and measure.	
14	Resistance to Soldering Heat	The measured values shall satisfy the values in the following table.	The capacitor shall be set for 48 ± 4 hours at room temperature after one hour heat of treatment at $150.^{+0.0}_{-10}$ °C. Immerse the capacitor in a eutectic solder solution at 270 ± 5 °C for 10 ± 0.5 seconds after preheating in the flowing table. Then set it for $48T4$ hours at room temperature and measure.	
15	Temperature Cycle	$\begin{tabular}{lll} No marking defects. \\ \hline Item & Specification \\ Appearance & No marked defect \\ \hline Capacitance Change & Within \pm 20\% \\ I. R. & More than $10,000 M\Omega$ or $500 \Omega \cdot F$ \\ (Whichever is smaller) \\ \hline D.F. & 50, 100V & 10, 16, 25V & 6.3V \\ 0.07 max. & 0.09 max. & 0.15 max. \\ \hline Dielectric Strength & No failure \\ \hline \end{tabular}$	The capacitor shall be set for 48 ± 4 hours at room temperature after one hour heat of treatment at 150^{+0}_{-10} °C. Then measure for the initial measurement. Fix capacitor to the supporting jig in the same manner and under the same conditions as in (10) and conduct the five cycles according to the temperature and time shown in the following table. Set it for 48 ± 4 hours at room temperature, then measure. $\begin{array}{c ccccccccccccccccccccccccccccccccccc$	
16	Humidity Steady State	No marking defects. Item Specification Appearance No marked defect Capacitance Change Within ±30% I. R. More than 1,000MΩ or 50Ω · F (Whichever is smaller) D.F. 50, 100V 10, 16, 25V 6.3V 0.1 max. 0.125 max. 0.2 max. Dielectric Strength No failure	Set the capacitor for 500±12 hours at 40±2°C and 90 to 95% humidity. Take it out and set it for 48T4 hours at room temperature, then measure.	
17	Humidity Load	$\begin{tabular}{l lllllllllllllllllllllllllllllllllll$	Apply the rated voltage for 500±12 hours at 40±2°C and 90 to 95% humidity and set it for 48±4 hours at room temperature, then measure. The charge/discharge current is less than 50mA.	

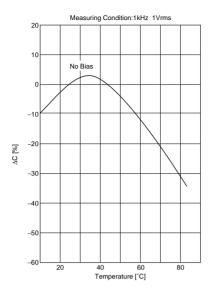
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No marked defect. Item Spec	cification	The voltage treatment shall be given to the capacitor, in which a DC voltage of 200%* the rated voltage is applied for one hour
High Temperature Load High Temperature Load Capacitance Change Within More (Whith D.F. 50, 1 0.1 r.	marked defect nin ±30% e than 1,000MΩ or 50Ω · F ichever is smaller) 100V	at the maximum operating temperature ±3°C then it shall be set for 48±4 hours at room temperature and the measurement shall be conducted. Then apply the above mentioned voltage continuously for 1000±12 hours at the same temperature, remove it from the bath, and set it for 48±4 hours at room temperature, then measure. The charge/discharge current is less than 50mA. *150% for C>10µF

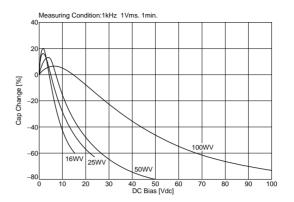


Characteristics Data

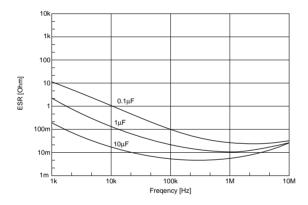
■ Capacitance-Temperature Characteristics



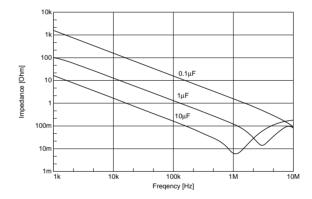
■ Capcitance-DC Voltage Characteristics



■ Capcitance-AC Voltage Characteristics



■ Impedance-Frequency Characteristics

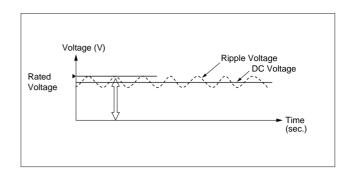


Reference Data

■ Allowable Ripple Current

Ripple current should be less than "Allowable ripple current value" shown in the following table.

And temperature rise of the chip surface (ΔT) should be below 20°C. When AC and DC voltage are superimposed, keep the peak value of the voltage within the rated voltage.



Allowable ripple current value

Series	Datad Valtage	Allowable ripple current value (r.m.s.)			
Series	Rated Voltage	100kHz≦ f <300kHz	300kHz≦ f <500kHz	500kHz≦ f <1MHz	
GJ221		1.4Ar.m.s.	1.5Ar.m.s.	1.6Ar.m.s.	
GJ231	41/// 21/	1.5Ar.m.s.	1.6Ar.m.s.	1.6Ar.m.s.	
GJ232	4V / 6.3V	1.7Ar.m.s.	1.8Ar.m.s.	2.0Ar.m.s.	
GJ243		1.4Ar.m.s.	1.3Ar.m.s.	1.2Ar.m.s.	
GJ218	- 10V	1.4Ar.m.s.	1.5Ar.m.s.	1.6Ar.m.s.	
GJ231		1.5Ar.m.s.	1.6Ar.m.s.	1.6Ar.m.s.	
GJ232		1.7Ar.m.s.	1.8Ar.m.s.	2.0Ar.m.s.	
GJ243		1.4Ar.m.s.	1.3Ar.m.s.	1.2Ar.m.s.	
GJ231	141/	1.5Ar.m.s.	1.6Ar.m.s.	1.6Ar.m.s.	
GJ232	- 16V	1.7Ar.m.s.	1.8Ar.m.s.	2.0Ar.m.s.	
GJ232	25V / 35V / 50V	2.0Ar.m.s.	2.2Ar.m.s.	2.2Ar.m.s.	
GJ243	250 / 350 / 500	2.0Ar.m.s.	2.2Ar.m.s.	2.2Ar.m.s.	
GJ232	100V	1.6Ar.m.s.	1.7Ar.m.s.	1.8Ar.m.s.	



Microchip

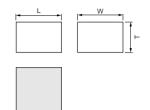
■ Features

- 1. Better micro wave characteristics.
- 2. Suitable for by-passing.
- 3. High density mounting.

■ Applications

- Optical device for telecommunication.
- IC, IC packaging built-in.
- Measuring equipment.





Part Number	Dimensions (mm)					
Part Number	L	W	T			
GMA05X	0.5 ±0.05	0.5 ±0.05	0.35 ±0.05			
GMA085	0.8 ±0.05	0.8 ±0.05	0.5 ±0.1			

Part Number	тс	Rated Voltage (Vdc)	Capacitance	Length L (mm)	Width W (mm)	Thickness T (mm)
GMA05XF51A153ZD01	Y5V	10	15000pF +80/-20%	0.5	0.5	0.35
GMA085F51A104ZD01	Y5V	10	0.1μF +80/-20%	0.8	0.8	0.5
GMA05XR71C102MD01	X7R	16	1000pF ±20%	0.5	0.5	0.35
GMA05XR71C152MD01	X7R	16	1500pF ±20%	0.5	0.5	0.35
GMA05XR71C222MD01	X7R	16	2200pF ±20%	0.5	0.5	0.35
GMA085R71C103MD01	X7R	16	10000pF ±20%	0.8	0.8	0.5
GMA05XF51C472ZD01	Y5V	16	4700pF +80/-20%	0.5	0.5	0.35
GMA05XF51C682ZD01	Y5V	16	6800pF +80/-20%	0.5	0.5	0.35
GMA085F51C473ZD01	Y5V	16	47000pF +80/-20%	0.8	0.8	0.5
GMA05XR71H471MD01	X7R	50	470pF ±20%	0.5	0.5	0.35

No.	Ite	em	Specification			Tes	st Method	d	
1	Operatino Temperati	•	R7 : −55℃ to +125℃ F5 : −30℃ to +85℃						
2	2 Rated Voltage		See the previous pages.		may be applie When AC volta	d continuously age is superim	to the ca	aximum voltage apacitor. In DC voltage, Ved within the ra	^{'P-P} or V ^{O-P} ,
3	Appearar	nce	No defects or abnormalitie	S.	Visual inspection.				
4	Dimensio	ns	See the previous pages.		Visual inspect	ion.			
5	Dielectric	Strength	No defects or abnormalitie	S.	voltage is app	lied between th	ne both te	oltage of 250% rminations for current is less the	1 to 5 sec-
6	Insulation (I.R.)	Resistance	10,000MΩ min.			the rated volta	age at no	asured with a E rmal temperatu ging.	•
7	Capacita	nce	Within the specified tolera	nce.	The capacitan			t 25℃ with 1±0 e.).1kHz in
8	Dissipatio (D.F.)	n Factor	R7 : 0.035 max. F5 : 0.09 max. (for 16V) : 0.125 max. (for 10V)		D.F. shall be r capacitance.	measured unde	er the san	ne conditions a	t the
9	Capacitance Temperature Characteristics		Char. Temp. Range R7 −55 to +125°c F5 −30 to +85°c	C 25°C Within±15%	the temperatu specified rang The capacitan	re range show es.	n in the ta	eference to 25° able shall be wi asured after 5 r	thin the
10	Bond Strength Strength		Pull force : 3.0g min.	I force : 3.0g min. Au-Sn (80/20) and bond a 20μr		Condition D I metallized alumina substrate with µm (0.0008 inch) gold wire to the trasonic wedge bond. Then, pull			
		Die Shear Strength	Die Spear force : 2000 min		MIL-STD-883 Method 2019 Mount the capacitor on a gold metallized alumina substrate with Au-Sn (80/20). Apply the force parallel to the substrate.				
		Appearance	No defects or abnormalitie	S.					
	Vibration	Capacitance Within the specified tolerance.		Ramp frequency from 10 to 55Hz then return to 10Hz all within 1 minute. Amplitude: 1.5 mm (0.06 inch) max. total excursion.					
11	Resistance	D.F.	R7: 0.035 max. F5: 0.09 max. (for 16V) : 0.125 max. (for 10V)			tion for a perio	d of 2 hou	urs in each of 3	
			The measured values shatable. Item Appearance Capacitance Change	Specification No marked defect R7 Within±7.5%	after one hour for the initial m jig in the same and conduct th	heat of treatm neasurement. I manner and the five cycles a	ent at 15 Fix the caunder the according	ours at room te 0^{+0}_{-10} °C, then in a pacitor to the same condition to the temperation to the temperation 0 0.	measure supporting ns as (11) atures and
12	Temperat	ture Cycle	I.R.	F5 ······ Within±20% More than 10,000MΩ	temperature, t		ub.01 0 01		
				R7 ····· 0.035 max.	Step	1	2	3	4
			D.F.	F5 ······ 0.09 max.(for 16V) 0.125 max.(for 10V)	Temp.(℃)	Min. Operating Temp. $\stackrel{+}{=}$ 3	Room Temp.	Max. Operating Temp. ±3	Room Temp.
			Dielectric Strength	No failure	Time(min.)	30±3	2 to 3	30±3	2 to 3
13	Humidity (Steady S		The measured values shatable. Item Appearance Capacitance Change I.R.	Specification No marked defect R7 ······ Within±12.5% F5 ····· Within±30% More than 1,000MΩ R7 ······ 0.05 max.	humidity.			t 40±20°C, in 90	
			D.F. Dielectric Strength	F5 ······ 0.05 max. F5 ····· 0.125 max.(for 16V) 0.15 max.(for 10V) No failure		measure.			

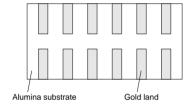


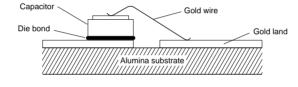


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No.	Item	S	pecification	Test Method
14	Humidity Load	The measured values shable. Item Appearance Capacitance Change I.R. D.F. Dielectric Strength	Specification No marked defect R7 ······ Within±12.5% F5 ····· Within±36% More than 500MΩ R7 ····· 0.05 max. F5 ···· 0.125 max.(for 16V) 0.15 max.(for 10V) No failure	Apply the rated voltage for 500 ± 12 hours at $40\pm20^\circ$ C, in 90 to 95% humidity and set it for 48 ± 4 hours at room temperature, then measure. The charge/discharge current is less than 50mA. • Initial measurement for Y5V Perform a heat treatment at $150\pm9^\circ$ C for one hour and then let sit for 48 ± 4 hours at room temperature. Perform the initial measurement.
15	High Temperature Load	The measured values shable. Item Appearance Capacitance Change I.R. D.F. Dielectric Strength	Specification No marked defect R7 ······· Within±12.5% F5 ····· Within±38% More than 1,000MΩ R7 ····· 0.05 max. F5 ···· 0.125 max.(for 16V) 0.15 max.(for 10V) No failure	A voltage treatment shall be given to the capacitor, in which a DC voltage of 200% the rated voltage is applied for one hour at the maximum operating temperature ±3°C then it shall be set for 48±4 hours at room temperature and the initial measurement shall be conducted. Then apply the above mentioned voltage continuously for 1000±12 hours at the same temperature, remove it from the bath, and set it for 48±4 hours at room temperature, then measure. The charge/discharge current is less than 50mA.

Mounting for testing: The capacitors shall be mounted on the substrate as shown below using die bonding and wire bonding when tests No. 11 to 15 are performed.







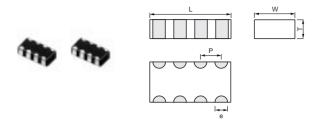
Capacitor Array

■ Features

- 1. High density mounting due to mounting space saving.
- 2. Mounting cost saving.

■ Applications

eneral electronic equipment



Part Number	Dimensions (mm)						
Part Number	L	W	Т	Р	е		
GNM314	2 2 +0 15	1 4 +0 15	0.8 ±0.1	0 0 10 1	0.4 ±0.15		
GNW314	3.2 ±0.15	3.2 ±0.15 1.6 ±0.15		0.6 ±0.1	0.4 ±0.15		

Temperature Compensating Type

Part Number	GNI	M31			
L x W	3.2>	x1.6			
тс	C0G (5C)				
Rated Volt.	50 (1H)	100 (2A)			
Capacitance and T Dimension					
10pF(100)	0.8(4)	0.8(4)			
11pF(110)	0.8(4)	0.8(4)			
12pF(120)	0.8(4)	0.8(4)			
13pF(130)	0.8(4)	0.8(4)			
15pF(150)	0.8(4)	0.8(4)			
16pF(160)	0.8(4)	0.8(4)			
18pF(180)	0.8(4)	0.8(4)			
20pF(200)	0.8(4)	0.8(4)			
22pF(220)	0.8(4)	0.8(4)			
24pF(240)	0.8(4)	0.8(4)			
27pF(270)	0.8(4)	0.8(4)			
30pF(300)	0.8(4)	0.8(4)			
33pF(330)	0.8(4)	0.8(4)			
36pF(360)	0.8(4)	0.8(4)			
39pF(390)	0.8(4)	0.8(4)			
43pF(430)	0.8(4)	0.8(4)			
47pF(470)	0.8(4)	0.8(4)			
51pF(510)	0.8(4)	0.8(4)			
56pF(560)	0.8(4)	0.8(4)			
62pF(620)	0.8(4)	0.8(4)			
68pF(680)	0.8(4)	0.8(4)			
75pF(750)	0.8(4)	0.8(4)			
82pF(820)	0.8(4)	0.8(4)			
91pF(910)	0.8(4)	0.8(4)			
100pF(101)	0.8(4)	0.8(4)			
110pF(111)	0.8(4)	0.8(4)			
120pF(121)	0.8(4)	0.8(4)			
130pF(131)	0.8(4)	0.8(4)			
150pF(151)	0.8(4)	0.8(4)			
160pF(161)	0.8(4)				
180pF(181)	0.8(4)				

Continued from the preceding page.

Part Number	GNI	M31					
LxW	3.2)	3.2x1.6					
тс	C0G (5C)						
Rated Volt.	50 (1H)	100 (2A)					
Capacitance and	T Dimension						
200pF(201)	0.8(4)						
220pF(221)	0.8(4)						
240pF(241)	0.8(4)						
270pF(271)	0.8(4)						
300pF(301)	0.8(4)						
330pF(331)	0.8(4)						
360pF(361)	0.8(4)						

The part numbering code is shown in each (). The (4) code in T(mm) means number of elements (four). Dimensions are shown in mm and Rated Voltage in Vdc.

High Dielectric Constant Type

Part Number				GNM31						
LxW	3.2x1.6									
тс	X7R (R7)				Y5V (F5)					
Rated Volt.	16 (1C)	25 (1E)	50 (1H)	100 (2A)	16 (1C)	50 (1H)	100 (2A)			
Capacitance and T	Dimension									
220pF(221)				0.8(4)						
270pF(271)				0.8(4)						
330pF(331)				0.8(4)						
390pF(391)			0.8(4)	0.8(4)						
470pF(471)			0.8(4)	0.8(4)						
560pF(561)			0.8(4)	0.8(4)						
680pF(681)			0.8(4)	0.8(4)						
820pF(821)			0.8(4)	0.8(4)						
1000pF(102)			0.8(4)	0.8(4)						
1200pF(122)			0.8(4)	0.8(4)						
1500pF(152)			0.8(4)	0.8(4)						
1800pF(182)			0.8(4)	0.8(4)						
2200pF(222)			0.8(4)	0.8(4)			0.8(4)			
2700pF(272)			0.8(4)	0.8(4)						
3300pF(332)			0.8(4)	0.8(4)			0.8(4)			
3900pF(392)			0.8(4)	0.8(4)						
4700pF(472)			0.8(4)	0.8(4)			0.8(4)			
5600pF(562)			0.8(4)							
6800pF(682)			0.8(4)							
8200pF(822)			0.8(4)							
10000pF(103)			0.8(4)							
12000pF(123)			0.8(4)							
15000pF(153)			0.8(4)							
18000pF(183)		0.8(4)								
22000pF(223)	0.8(4)					0.8(4)				
27000pF(273)	0.8(4)									
33000pF(333)	0.8(4)					0.8(4)				
39000pF(393)	0.8(4)									
47000pF(473)	1.0(4)					0.8(4)				
68000pF(683)	1.0(4)				0.8(4)	, ,				
100000pF(104)	1.0(4)				0.8(4)					
150000pF(154)	- ()				0.8(4)					

The part numbering code is shown in each (). The (4) code in T(mm) means number of elements (four). Dimensions are shown in mm and Rated Voltage in Vdc.



				Specification			
No.	Ite	em	Temperature			Test Method	
			Compensating Type	High Dielectric Constant Type			
1	Operating Temperating	5 50, -55 t0 +1/50					
2			See the previous page.	10. 60.0 160.0	may be applied contin When AC voltage is su	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p,p} or V ^{C,p} , whichever is larger, shall be maintained within the rated voltage	
3	Appearar	nce	No defects or abnormaliti	es.	Visual inspection.		
4	Dimensio	ns	Within the specified dime	nsion.	Using calipers.		
5	Dielectric	: Strength	No defects or abnormaliti	es.	No failure shall be obs (C0G) or 250% of the between the termination charge/discharge curre	rated voltage (X7R ons for 1 to 5 second	and Y5V) is applied ds, provided the
6	Insulation I (I.R.)	Resistance	More than 10,000MΩ or \$	500Ω • F (Whichever is smaller)	The insulation resistar not exceeding the rate within 2 minutes of characteristics.	ed voltage at 25℃ an	
7	Capacita	nce	Within the specified tolera	ance.	The capacitance/Q/D.		d at 25°C at the fre-
			30pF min. : Q≧1,000	Char. 25V min. 16V	quency and voltage shar.		R7, F5
8	Q/Dissipat (D.F.)	tion Factor	30pF max. : Q≥400+20C C : Nominal Capacitance	R7 0.025 max. 0.035 max.	Frequency	1±0.1MHz	1±0.1MHz
	(D.F.)		(pF)	F5 0.05 max. 0.07 max.	Voltage	0.5 to 5Vr.m.s.	1±0.2Vr.m.s.
9	Capacitance Temperature Characteristics	Capacitance Change Temperature Coefficient Capacitance Drift	Within the specified tolerance. (Table A-5) Within the specified tolerance. (Table A-5) Within ±0.2% or ±0.05pF (Whichever is larger)	Char. Temp. Range. Reference Temp. Change R7 -55to +125°C F5 -30to +85°C 25°C Within±15% Within±22%	capacitance measu. When cycling the te through 5, the capa- tolerance for the te change as Table A The capacitance d differences betwee values in the step 1 Step 1 2 3 4 5 (2) High Dielectric Con The ranges of capa	ature stage. Densating Type Defficient is determinated in step 3 as a reemperature sequent acitance shall be with mperature coefficien. Definition of the maximum and sequent acitance shall be with mperature coefficien. Definition of the maximum and sequent acitance shall be with maximum and sequent and sequent sequ	need using the eference. is in the specified in the speci
10	Adhesive Strength of Termination		No removal of the termina	ations or other defects shall occur.	Solder the capacitor to Fig.1 using a eutectic with the test jig for 10-1. The soldering shall be reflow method and shadering is uniform and to the soldering is uniform.	solder. Then apply 5 ±1 sec. done either with an all be conducted with	iron or using the n care so that the solars heat shock.

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И	Continued fr	om the prec	eding page.							
	Specification		Specification							
No.	Ite	em	Temperature Compensating Type	High Dielectric Constant 1		Nethod				
	Appearance		Appearance No defects or abnormalities.			Solder the capacitor to the test jig (glass epoxy board) in the				
		Capacitance	Within the specified toler	ance.	same manner and under the sa The capacitor shall be subjected	` '				
11	Vibration Resistance	Q/D.F.	30pF min. : Q≥1000 30pF max. : Q≥400+20C C : Nominal Capacitance (pF)	Char. 25V min. 16 R7 0.025 max. 0.035 F5 0.05 max. 0.07	having a total amplitude of 1.5m uniformly between the approxim The frequency range, from 10 to the traversed in approximately 1.5m	nm, the frequency being varied nate limits of 10 and 55Hz. o 55Hz and return to 10Hz, sha minute. This motion shall be				
			No cracking or marking of	lefects shall occur.	Solder the capacitor to the test in Fig.2 using a eutectic solder. tion shown in Fig.3. The soldering or using the reflow method care so that the soldering is unit	Then apply a force in the direc ng shall be done either with an and shall be conducted with				
12	2 Deflection		0.4±0.05	100	R230 Capacitance	0 Pressurizing speed: 1.0mm/sec. Pressurize Flexure: ≦1 meter 45 (in mm)				
13	•		75% of the terminations is to be soldered evenly and continuously.		rosin (JIS-K-5902) (25% rosin ir 80 to 120℃ for 10 to 30 second	Immerse the capacitor in a solution of ethanol (JIS-K-8101) an rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120℃ for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5℃.				
			The measured and obserspecifications in the follow	ved characteristics shall satisfy wing table.						
		Appearance	No marking defects.		Preheat the capacitor at 120 to	150℃ for 1 minute. Immerse th				
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	R7 ······· Within±7.5% F5 ······ Within±20%	capacitor in a eutectic solder so seconds. Let sit at room temper ture compensating type) or 48±	ature for 24±2 hours (tempera				
14	Resistance to Soldering Heat	Q/D.F.	30pF and over : Q≥1,000 30pF and below : Q≥400+20C C : Nominal Capacitance (pF)	Char. 25V min. 16 R7 0.025 max. 0.035 F5 0.05 max. 0.07	type), then measure. • Initial measurement for high di	ielectric constant type 0±00 ℃ for one hour and then				
		I.R.	More than 10,000M Ω or	500Ω • F (Whichever is smaller)	measurement.	·				
		Dielectric Strength	No failure							
			The measured and obserspecifications in the follow	ved characteristics shall satisfy wing table.	Fix the capacitor to the supporti under the same conditions as (
		Appearance	No marking defects.		according to the four heat treatr	according to the four heat treatments listed in the following table. Let sit for 24±2 hours (temperature compensating type)				
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	R7 ······ Within±7.5% F5 ····· Within±20%	or 48±4 hours (high dielectric cuture, then measure.					
15	Temperature Cycle	Q/D.F.	30pF and over : Q≥1,000 30pF and below : Q≥400+20C C : Nominal Capacitance (pF)	Char. 25V min. 16 R7 0.025 max. 0.035 F5 0.05 max. 0.07	K. Temp.(C) Temp. +0 T	2 3 4 200m Max. Operating Room				
		I.R.	More than 10,000MΩ or	500Ω • F (Whichever is smaller)	Perform a heat treatment at 150)±o₁o ℃ for one hour and then				
		Dielectric Strength	No failure		let sit for 48±4 hours at room te measurement.	emperature. Perform the initial				

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				Specification			
No.	Comp		Temperature Compensating Type	High Dielectric Constant Type	Test Method		
			The measured and obserspecifications in the follow	rved characteristics shall satisfy the wing table.			
		Appearance	No marking defects.				
		Capacitance Change	Within ±5% or ±0.5pF (Whichever is larger)	R7 ······ Within±12.5% F5 ····· Within±30%	Sit the capacitor at 40±2°c and 90 to 95% humidity for 500±12		
16	Humidity, Steady State	Q/D.F.	30pF and over : Q≥350 10pF and over, 30pF and below : Q≥275+-5-C 10pF and below : Q≥200+10C C : Nominal Capacitance (pF)	Char. 25V min. 16V R7 0.05 max. 0.05 max. F5 0.075 max. 0.1 max.	hours. Remove and let sit for 24±2 hours (temperature compensating type) or 48±4 hours (high dielectric constant type) at room temperature, then measure.		
		I.R.	More than 1,000MΩ or 5	0Ω • F (Whichever is smaller)			
			The measured and obserspecifications in the follow	rved characteristics shall satisfy the wing table.			
		Appearance	No marking defects.	_			
		Capacitance Change	Within ±7.5% or ±0.75pF (Whichever is larger)	R7 ······· Within±12.5% F5 ······ Within±30%	Apply the rated voltage at 40±2℃ and 90 to 95% humidity for		
17	Humidity Load	Q/D.F.	30pF and over : Q≥200 30pF and below : Q≥100+ ½ C C : Nominal Capacitance (pF)	Char. 25V min. 16V R7 0.05 max. 0.05 max. F5 0.075 max. 0.1 max.	500±12 hours. Remove and let sit for 24±2 hours (temperature compensating type) or 48±4 hours (high dielectric constant type) at room temperature, then measure. The charge/discharge current is less than 50mA.		
		I.R.	More than 500MΩ or 250	2 • F (Whichever is smaller)			
		Dielectric Strength	No failure				
		The measured and observed characteristics shall satisfy the specifications in the following table.		-			
		Appearance	No marking defects.				
		Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	R7 ······· Within±12.5% F5 ······ Within±30%	Apply 200% of the rated voltage for 1,000±12 hours at the maximum operating temperature ±3°C. Let sit for 24±2 hours		
18	High Temperature Load	Q/D.F.	30pF and over : Q≥350 10pF and over, 30pF and below : Q≥275+ ½ C 10pF and below : Q≥200+10C C : Nominal Capacitance (pF)	Char. 25V min. 16V R7 0.04 max. 0.05 max. F5 0.075 max. 0.1 max.	(temperature compensating type) or 48±4 hours (high dielectric constant type) at room temperature, then measure. The charge/discharge current is less than 50mA. •Initial measurement for high dielectric constant type. Apply 200% of the rated DC voltage for one hour at the maximum operating temperature ±3°C. Remove and let sit for 48±4 hours at room temperature. Perform initial measurement.		
		I.R.	More than 1,000M Ω or 5	0Ω • F (Whichever is smaller)			
		Dielectric Strength	No failure				

Table A

	Temp. Coeff. (ppm/°C) Note 1	Capacitance Change from 25℃ (%)					
Char. Code		−55℃		−30°C		−10 °C	
		Max.	Min.	Max.	Min.	Max.	Min.
5C	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11

Note 1 : Nominal values denote the temperature coefficient within a range of 25 to 125°C.



for Ultrasonic Sensors

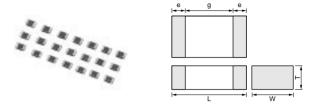
■ Features

- 1. Proper to compensate for ultrasonic sensor.
- 2. Small chip size and high cap. Value.

■ Application

Ultrasonic sensor

(Back sonar, Corner sonar and etc.)



Part Number	Dimensions (mm)					
Part Number	L	W	T	е	g min.	
GRM219	2.0 ±0.1	1.25 ±0.1	0.85 ±0.1	0.2 to 0.7	0.7	

Part Number	тс	Rated Voltage (Vdc)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GRM2199E2A102KD01	ZLM	100	1000 ±10%	2.0	1.25	0.85
GRM2199E2A152KD01	ZLM	100	1500 ±10%	2.0	1.25	0.85

No.	Ite	em	Specification		Test Me	thod	
1	Operating Temperat	•	−25°C to +85°C				
2	2 Rated Voltage		See the previous pages.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p,p} or V ^{o,p} , whichever is larger, shall be maintained within the rated voltage range.		ge, V ^{p.p} or V ^{o.p} ,	
3	Appearar	nce	No defects or abnormalities.	Visual inspection.			
4	Dimensio	ns	Within the specified dimensions.	Using calipers.			
5	Dielectric	Strength	No defects or abnormalities.	No failure shall be of applied between the the charge/discharge	e terminations	for 1 to 5 seco	nds, provided
6	Insulation (I.R.)	Resistance	More than 10,000MΩ or 500Ω • F. (Whichever is smaller)	The insulation resis not exceeding the r within 2 minutes of	ated voltage at		•
7	Capacita	nce	Within the specified tolerance.	The conscitance/D	E shall ha ma	ocured at 20°C	with 1±0.1kHz
8	Dissipatio	n Factor	0.01 max.	 The capacitance/D. in frequency and 1: 			will I±0.TKMZ
9	(D.F.) Capacitar Temperat		Within −4,700 ^{+1,200} _{-2,500} ppm/°C (at −25 to +20°C) Within −4,700 ⁺⁵⁰⁰ _{-1,000} ppm/°C (at +20 to +85°C)	The temperature of capacitance measu When cycling the te 5, the capacitance stemperature coeffic The capacitance che each specified temperature coefficient of the capacitance che capacitance	red in step 1 a emperature sec shall be within ient. ange shall be berature stage.	s a reference. quentially from the specified t measured afte	step 1 through olerance for the or 5 min. at
	Character		Within −4,700 ±1,000 ppm/ € (at +20 to +85 €)	Step 1	10	emperature(℃)
				2		20±2 -25±3	
				3		20±2	
				4		85±3	
				5		20±2	
10	Adhesive Strength of Termination		No removal of the terminations or other defect shall occur.	Solder the capacitor to the test jig (glass epoxy boar Fig.1 using a eutectic solder. Then apply 10N force direction of the arrow. The soldering shall be done either with an iron or us reflow method and shall be conducted with care so dering is uniform and free of defects such as heat sl		orce in the or using the so that the sol- at shock.	
		Appearance	No defects or abnormalities.	Solder the capacito	Fig.1		noard) in the
		Capacitance	Within the specified tolerance.				
11	Vibration Resistance	D.F.	0.01 max.	same manner and under the same conditions as (1). The capacitor shall be subjected to a simple harmon having a total amplitude of 1.5mm, the frequency be uniformly between the approximate limits of 10 and frequency range, from 10 to 55Hz and return to 10-traversed in approximately 1 minute. This motion shapplied for a period of 2 hours in each 3 mutually pedirections (total of 6 hours).		y being varied and 55Hz. The 10Hz, shall be n shall be	

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Continued from the preceding page. Specification No Item Test Method Solder the capacitor to the test jig (glass epoxy boards) shown No cracking or marking defects shall occur. in Fig.2 using a eutectic solder. Then apply a force in the direction shown in Fig.3. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so that the soldering is uniform and free of defects such as heat shock. 50 Pressurizing speed : 1.0mm/sec. Deflection Pressurize R230 t: 1.6mm Flexure : ≤1 Туре С GRM21 40 1.65 (in mm) (in mm) Fig.2 Fig.3 Immerse the capacitor in a solution of ethanol (JIS-K-8101) and Solderability of rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 13 75% of the terminations is to be soldered evenly and continuously. 80 to 120℃ for 10 to 30 seconds. After preheating, immerse in Termination eutectic solder solution for 2±0.5 seconds at 230±5°C. Appearance No defects or abnormalities. Capacitance Within ±7.5% Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the Change Resistance capacitor in a eutectic solder solution at 270±5℃ for 10±0.5 14 to Soldering D.F. 0.01 max seconds. Let sit at room temperature for 24±2 hours, then Heat More than $10,000M\Omega$ or $500\Omega \bullet F$ (Whichever is smaller) I.R Dielectric No failure Strength Appearance No defects or abnormalities Fix the capacitor to the supporting jig in the same manner and under the same conditions as (11). Capacitance Within ±7.5% Perform the five cycles according to the four heat treatments Change listed in the following table. Let sit for 24±2 hours at room tem-Temperature 15 D.F. 0.01 max perature, then measure. Cycle Step 3 LR More than $10,000M\Omega$ or $500\Omega \bullet F$ (Whichever is smaller) 85 +3 Temp.(°C) -25⁺3 RoomTemp RoomTemp. Dielectric No failure 30±3 30±3 Time(min.) 2 to 3 2 to 3 Strength Appearance No defects or abnormalities. Capacitance Within ±12.5% Sit the capacitor at 40±2℃ and 90 to 95% humidity for 500±12 Change Humidity, D.F. 16 Steady 0.02 max Remove and let sit for 24±2 hours at room temperature, then State I.R. More than $1,000M\Omega$ or $50\Omega \bullet F$ (Whichever is smaller) measure. Dielectric No failure Strength Appearance No defects or abnormalities Apply the rated voltage at 40±2℃ and 90 to 95% humidity for Capacitance Within ±12.5% Humidity 500±12 hours. Remove and let sit for 24±2 hours at room tem-Change Load perature, then measure. The charge/discharge current is less D.F. than 50mA. I.R. More than $500M\Omega$ or $25\Omega \bullet F$ (Whichever is smaller) Appearance No defects or abnormalities Capacitance High Apply 200% of the rated voltage for 1,000±12 hours at 85±3℃. Within ±12.5% Change Let sit for 24±2 hours at room temperature, then measure. 18 Temperature



The charge/discharge current is less than 50mA.

Load

D.F

I.R.

0.02 max

More than 1,000M Ω or 50 Ω • F (Whichever is smaller)



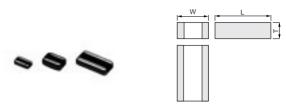
Low ESL

■ Features

- 1. Low ESL, good for noise reduction for high frequency.
- 2. Small, high cap.

■ APPLICATION

- High speed micro processor.
- High frequency digital equipment



Part Number	Dimensions (mm)				
Fait Number	L	W	T		
LLL185	1.6 ±0.1	0.8 ±0.1	0.6 max.		
LLL216	20+01	1.25 ±0.1	0.6 ±0.1		
LLL219	2.0 ±0.1	1.25 ±0.1	0.85 ±0.1		
LLL317	3.2 ±0.15	1.6 ±0.15	0.7 ±0.1		
LLL31M	3.∠ ±0.15	1.0 ±0.15	1.15 ±0.1		

LLL18 Series (1.6x0.8mm)

Part Number	LLL18				
LxW	1.6x0.8				
тс	X7R (R7)				
Rated Volt.	10 (1A)	16 (1C)	25 (1E)	50 (1H)	
Capacitance and	T Dimension				
2200pF(222)				0.6 (5)	
2700pF(272)				0.6 (5)	
3300pF(332)				0.6 (5)	
3900pF(392)				0.6(5)	
4700pF(472)				0.6(5)	
5600pF(562)				0.6(5)	
6800pF(682)			0.6(5)		
8200pF(822)			0.6(5)		
10000pF(103)			0.6(5)		
12000pF(123)			0.6(5)		
15000pF(153)			0.6(5)		
18000pF(183)			0.6(5)		
22000pF(223)			0.6(5)		
27000pF(273)		0.6(5)			
33000pF(333)		0.6(5)			
39000pF(393)		0.6(5)			
47000pF(473)		0.6(5)			
56000pF(563)		0.6(5)			
68000pF(683)		0.6(5)			
82000pF(823)	0.6(5)				
0.1μF(104)	0.6(5)				
0.12μF(124)	0.6(5)				

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.



LLL21 Series (2.0x1.25mm)

Part Number			LLL21			
LxW			2.0x1.25			
тс	X7R (R7)					
Rated Volt.	10 (1A)	16 (1C)	25 (1E)	50 (1H)		
Capacitance and T D	Dimension		·			
0.22pF(224)	0.6(6)					
4700pF(472)				0.6(6)		
5600pF(562)				0.6(6)		
6800pF(682)				0.6(6)		
8200pF(822)				0.6(6)		
10000pF(103)				0.6(6)		
12000pF(123)				0.6(6)		
15000pF(153)				0.6(6)		
18000pF(183)				0.6(6)		
22000pF(223)				0.6(6)		
27000pF(273)			0.6(6)	0.85(9)		
33000pF(333)		0.6(6)	0.6(6)	0.85(9)		
39000pF(393)		0.6(6)	0.6(6)	0.85(9)		
47000pF(473)		0.6(6)	0.6(6)			
56000pF(563)		0.6(6)	0.6(6)			
68000pF(683)		0.6(6)	0.6(6)			
82000pF(823)		0.6(6)	0.6(6)			
0.1μF(104)		0.6(6)	0.6(6)			
0.12μF(124)		0.6(6)	0.85(9)			
0.15μF(154)		0.6(6)	0.85(9)			
0.18μF(184)		0.6(6)				
0.22μF(224)		0.85(9)				
0.27μF(274)	0.6(6)					
0.33μF(334)	0.6(6)					
0.39μF(394)	0.85 (9)					
0.47μF(474)	0.85 (9)					
0.56μF(564)	0.85 (9)					

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

LLL31 Series (3.2x1.6mm)

Part Number	LLL31				
LxW	3.2x1.6				
тс	X7R (R7)				
Rated Volt.	10 (1A)	16 (1C)	25 (1E)	50 (1H)	
Capacitance and T Din	nension	'		1	
10000pF(103)				0.7(7)	
12000pF(123)				0.7(7)	
15000pF(153)				0.7(7)	
18000pF(183)				0.7(7)	
22000pF(223)				0.7(7)	
27000pF(273)				0.7(7)	
33000pF(333)				0.7(7)	
39000pF(393)				0.7(7)	
47000pF(473)				0.7(7)	



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Part Number		LLL31				
LxW	3.2x1.6					
тс		X (F	7R 77)			
Rated Volt.	10 (1A)	16 (1C)	25 (1E)	50 (1H)		
Capacitance and T [Dimension					
56000pF(563)				0.7(7)		
68000pF(683)				0.7(7)		
82000pF(823)			0.7(7)	1.15(M)		
0.1μF(104)		0.7(7)	0.7(7)	1.15(M)		
0.12μF(124)		0.7(7)	0.7(7)	1.15(M)		
0.15μF(154)		0.7(7)	0.7(7)			
0.18μF(184)		0.7(7)	0.7(7)			
0.22μF(224)		0.7(7)	1.15(M)			
0.27μF(274)		0.7(7)	1.15(M)			
0.33μF(334)		0.7(7)	1.15(M)			
0.39μF(394)		0.7(7)				
0.47μF(474)		0.7(7)	1.15(M)			
0.56μF(564)	0.7(7)	1.15(M)				
0.68μF(684)	0.7(7)	1.15(M)				
0.82μF(824)	0.7(7)	1.15(M)				
1.0μF(105)	0.7(7)	1.15(M)				
1.2μF(125)	1.15(M)					
1.5μF(155)	1.15 (M)					
1.8μF(185)	1.15(M)					
2.2μF(225)	1.15(M)					

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

No.	Iter	m	Specification	Test Method		
1	Operating Temperatu Range		-55°C to +125°C			
2	Rated Volt	tage	See the previous pages.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p,p} or V ^{op} , whichever is larger, shall be maintained within the rated voltage range.		
3	Appearance	ce	No defects or abnormalities.	Visual inspection.		
4	Dimension	าร	Within the specified dimension.	Using calipers.		
5	Dielectric	Strength	No defects or abnormalities.	No failure shall be observed when 250% of the rated voltage is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA.		
6	Insulation F (I.R.)	Resistance	More than 10,000MΩ or 500Ω • F (Whichever is smaller)	The insulation resistance shall be measured with a DC voltage not exceeding the rated voltage at 25℃ and 75%RH max. and within 2 minutes of charging.		
7	Capacitan	ce	Within the specified tolerance.	The capacitance/D.F. shall be measured at 25℃ at the		
				frequency and voltage shown in the table.		
8	Dissipation	n Factor	Char. 25V min. 16V	R7 Frequency 1±0.1kHz		
	(D.F.)		R7	Voltage 1±0.2Vr.m.s.		
9	Capacitance Temperature Characteristics Char. Temp. Range (°C) Reference Temp. Cap. Change. R7 -55 to +125 25°C Within±15%			The ranges of capacitance change compared with the 25°C value over the temperature ranges shown in the table shall be within the specified ranges. The capacitance change shall be measured after 5 min. at each specified temperature stage.		
10	Adhesive Strength of Termination No rem		No removal of the terminations or other defect shall occur.	Solder the capacitor to the test jig (glass epoxy board) shown in Fig.1 using a eutectic solder. Then apply 10N* force in the direction of the arrow. *5N:LLL18 The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so that the soldering is uniform and free of defects such as heat shock. Solder resist Baked electrode or copper foil Type a b c LLL18 0.3 1.2 2.0 LLL21 0.6 1.6 2.4 LLL31 1.0 3.0 3.7 (in mm)		
		Appearance	No defects or abnormalities.	Solder the capacitor to the test jig (glass epoxy board) in the		
	-	Capacitance	Within the specified tolerance.	same manner and under the same conditions as (10).		
11	Vibration Resistance	D.F.	Char. 25V min. 16V R7 0.025 max. 0.035 max.	The capacitor shall be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, shall be traversed in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3 mutually perpendicular directions (total of 6 hours).		

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Vo.	Ite	em	Specification	Test Method					
			No crack or marked defect shall occur.	Solder the capacitor to the test jig (glass epoxy boards) shown in Fig.2 using a eutectic solder. Then apply a force in the direction shown in Fig.3. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so that the soldering is uniform and free of defects such as heat shock.					
				20 50 Pressurizing speed : 1.0mm/sec.					
12	Deflection	n		R230					
			100 t:1.6mm						
			Time	Flexure : ≦1					
			Type a b c LLL18 0.3 1.2 2.0	Capacitance meter 45 45					
			LLL21 0.6 1.6 2.4 LLL31 1.0 3.0 3.7	(in mm)					
			(in mm)	Fig.3					
13	Solderabi Terminati	•	Fig.2 75% of the terminations is to be soldered evenly and continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120℃ for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5℃.					
		Appearance	No defects or abnormalities.	Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the					
		Capacitance Change	Within±7.5%	capacitor in a eutectic solder solution at 270±5℃ for 10±0.5 seconds. Let sit at room temperature for 48±4 hours , then					
14	Resistance to Soldering	D.F.	Char. 25V min. 16V	measure.					
	Heat			Initial measurement. Perform a heat treatment at 150 ⁺⁰ _{−10} °C for one hour and then					
		I.R. Dielectric Strength	More than 10,000M Ω or 500 Ω • F (Whichever is smaller) No failure	let sit for 48±4 hours at room temperature. Perform the initial measurement.					
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting jig in the same manner and					
		Capacitance Change	Within±7.5%	under the same conditions as (10). Perform the five cycles according to the four heat treatments listed in the following table. Let sit for 48±4 hours at room tem-					
		D.F.	Char. 25V min. 16V	perature, then measure.					
15	Temperature			Step 1 2 3 4 Town (%) Min. Operating Room Max. Operating Room					
13	Cycle	I.R.	More than 10,000MΩ or 500Ω • F (Whichever is smaller)	Temp. (C) Temp. +3 Temp. Temp. +3 Temp.					
				Time(min.) 30±3 2 to 3 30±3 2 to 3					
		Dielectric Strength	No failure	•Initial measurement. Perform a heat treatment at 150±⁰₀ ℃ for one hour and then let sit for 48±4 hours at room temperature. Perform the initial measurement.					
		Appearance	No defects or abnormalities.						
1/	Humidity,	Capacitance Change	Within±12.5%	Sit the capacitor at 40±2°C and 90 to 95% humidity for 500±12 hours.					
16	Steady State	D.F.	Char. 25V min. 16V R7 0.05 max. 0.05 max.	Remove and let sit for 48±4 hours at room temperature, then measure.					
		I.R.	More than 1,000MΩ or 50Ω • F (Whichever is smaller)						
		Appearance	No defects or abnormalities.						
		Capacitance Change	Within±12.5%						
	Humidity		Char. 25V min. 16V	Apply the rated voltage at 40±2°C and 90 to 95% humidity for 500±12 hours. Remove and let sit for 48±4 hours at room tem-					
17	Load	D.F.	R7 0.05 max. 0.05 max.	perature, then measure. The charge/discharge current is less					
		I.R.	More than 500MΩ or 25Ω • F (Whichever is smaller)	than 50mA.					
		Dielectric Strength	No failure						



Continued from the preceding page.

No.	Ite	m	Specification	Test Method
		Appearance	No defects or abnormalities.	Apply 200% of the rated voltage for 1,000±12 hours at maxi-
	High Temperature Load	Capacitance Change	Within±12.5%	mum operating temperature ±3°C. Let sit for 48±4 hours at room temperature, then measure.
18		D.F.	Char. 25V min. 16V R7 0.05 max. 0.05 max.	The charge/discharge current is less than 50mA. •Initial measurement.
		I.R.	More than 1,000MΩ or 50Ω • F (Whichever is smaller)	Apply 200% of the rated DC voltage for one hour at the maximum operating temperature ±3°C.
		Dielectric Strength	No failure	Remove and let sit for 48±4 hours at room temperature. Perform initial measurement.





High Frequency for Flow/Reflow Soldering

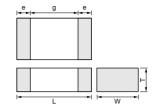
■ Features

- 1. HiQ and low ESR at VHF, UHF, Microwave.
- 2. Feature improvement, low power consumption for mobile telecommunication. (Base station, terminal,

■ Applications

High-frequency circuit (Mobile telecommunication, etc.)





Part Number		Dir	nensions (ı	nm)	
Part Number	L	W	T	е	g min.
GQM188	1.6 ±0.1	0.8 ±0.1	0.8 ±0.1	0.2 to 0.5	0.5
GQM219	2.0 ±0.1	1.25 ±0.1	0.85 ±0.1	0.2 to 0.7	0.7

Part Number	GQI	M18	GQM21				
LxW	1.60x	0.80	2.00x1.25				
тс	C0 (5 0		C0G (5C)				
Rated Volt.	50 (1H)	100 (2A)	50 (1H)	100 (2A)			
Capacitance and T D	imension	<u>'</u>		<u> </u>			
0.5pF(R50)		0.80(8)		0.85(9)			
0.75pF(R75)		0.80(8)		0.85(9)			
1.0pF(1R0)		0.80(8)		0.85(9)			
1.1pF(1R1)		0.80(8)		0.85(9)			
1.2pF(1R2)		0.80(8)		0.85(9)			
1.3pF(1R3)		0.80(8)		0.85(9)			
1.5pF(1R5)		0.80(8)		0.85(9)			
1.6pF(1R6)		0.80(8)		0.85(9)			
1.8pF(1R8)		0.80(8)		0.85(9)			
2.0pF(2R0)		0.80(8)		0.85(9)			
2.2pF(2R2)		0.80(8)		0.85(9)			
2.4pF(2R4)		0.80(8)		0.85(9)			
2.7pF(2R7)		0.80(8)		0.85(9)			
3.0pF(3R0)		0.80(8)		0.85(9)			
3.3pF(3R3)		0.80(8)		0.85(9)			
3.6pF(3R6)		0.80(8)		0.85(9)			
3.9pF(3R9)		0.80(8)		0.85(9)			
4.0pF(4R0)		0.80(8)		0.85(9)			
4.3pF(4R3)		0.80(8)		0.85(9)			
4.7pF(4R7)		0.80(8)		0.85(9)			
5.0pF(5R0)		0.80(8)		0.85(9)			
5.1pF(5R1)		0.80(8)		0.85(9)			
5.6pF(5R6)		0.80(8)		0.85(9)			
6.0pF(6R0)		0.80(8)		0.85(9)			
6.2pF(6R2)		0.80(8)		0.85(9)			
6.8pF(6R8)		0.80(8)		0.85(9)			
7.0pF(7R0)	0.80(8)			0.85(9)			
7.5pF(7R5)	0.80(8)			0.85(9)			
8.0pF(8R0)	0.80(8)			0.85(9)			
8.2pF(8R2)	0.80(8)			0.85(9)			
9.0pF(9R0)	0.80(8)			0.85(9)			
9.1pF(9R1)	0.80(8)			0.85(9)			
10.0pF(100)	0.80(8)			0.85(9)			

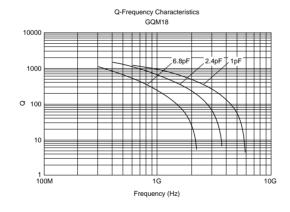
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Part Number	GQM18		GQM21				
LxW	1.60x0.8	0	2.00x1.25				
тс	C0G (5C) C0		0G 6C)				
Rated Volt.	50 (1H)	100 (2A)	50 (1H)	100 (2A)			
Capacitance and T D	imension						
11pF(110)	0.80(8)			0.85 (9)			
12pF(120)	0.80(8)			0.85(9)			
13pF(130)	0.80(8)			0.85 (9)			
15pF(150)	0.80(8)			0.85 (9)			
16pF(160)	0.80(8)			0.85 (9)			
18pF(180)	0.80(8)			0.85 (9)			
20pF(200)	0.80(8)		0.85 (9)				
22pF(220)	0.80(8)		0.85 (9)				
24pF(240)	0.80(8)		0.85 (9)				
27pF(270)			0.85(9)				
30pF(300)			0.85(9)				
33pF(330)			0.85(9)				
36pF(360)			0.85(9)				
39pF(390)			0.85(9)				
43pF(430)			0.85 (9)				
47pF(470)			0.85(9)				

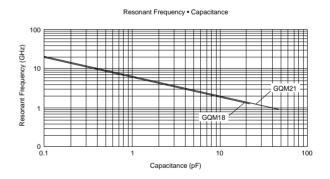
The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

■ Q-Frequency Characteristics



■ Resonant Frequency-Capacitance



No.	Ite	em	Specification		Test Method				
1	Operating Temperatu	ıre Range	C0G : −55°C to 125°C						
2	Rated Vo	-	See the previous pages.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p,p} or V ^{o,p} , whichever is larger, shall be maintained within the rated voltage range.					
3	Appearar	nce	No defects or abnormalities.	Visual inspection.					
4	Dimensio	ns	Within the specified dimensions.	Using calipers.					
5	Dielectric	Strength	No defects or abnormalities.	No failure shall be observed when 300% of the rated voltage is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA.					
6	Insulation (I.R.)	Resistance	More than $10{,}000M\Omega$ or 500Ω • F. (Whichever is smaller)		tance shall be measured with a DC voltage ated voltage at 25℃ and 75%RH max. and charging.				
7	Capacita	nce	Within the specified tolerance.		shall be measured at 25℃ at the frequency				
				and voltage shown i					
8	Q		Q≥1000	Frequency	ar. C0G(1000pF and below) 1±0.1MHz				
	8 Q			Voltage	0.5 to 5Vrms				
		Capacitance	MChiatha and Calabara (Table A.4)		efficient is determined using the capaci-				
		Change	Within the specified tolerance. (Table A-1)		step 3 as a reference.				
		Temperature Coefficent	Within the specified tolerance. (Table A-1)	When cycling the temperature sequentially from step 1 through 5, the capacitance shall be within the specified tolerance for the					
9	Capacitance Temperature			The capacitance drift between the maximus step 1, 3 and 5 by the	ent and capacitance change as Table A. ft is caluculated by dividing the differences um and minimum measured values in the ne cap. value in step 3.				
	Characteristics	Capacitance	Within ±0.2% or ±0.05pF	Step 1	Temperature(°C) 25±2				
		Drift	(Whichever is larger.)	2	-55±3				
				3	25±2				
				4 125±3 5 25+2					
				5	25±2				
10	Adhesive of Termin	-	No removal of the terminations or other defect shall occur.	Fig.1 using a eutectic with the test jig for 10 The soldering shall b method and shall be	to the test jig (glass epoxy board) shown in c solder. Then apply 10N* force in parallel 0±1sec. be done either with an iron or using the reflow conducted with care so that the soldering is lefects such as heat shock. *5N (GQM18) Solder resist Baked electrode or copper foil a b c 1.0 3.0 1.2 1.2 4.0 1.65				
					(in mm)				
		A	No defeate as above 200	Outlier if	Fig.1				
		Appearance	No defects or abnormalities.	·	r to the test jig (glass epoxy board) in the under the same conditions as (10).				
		Capacitance	Within the specified tolerance.	The capacitor shall be	be subjected to a simple harmonic motion				
11	Vibration Resistance	Q	Q≥1000	The capacitor shall be subjected to a simple harmonic having a total amplitude of 1.5mm, the frequency beir uniformly between the approximate limits of 10 and 5 frequency range, from 10 to 55Hz and return to 10Hz traversed in approximately 1 minute. This motion shat applied for a period of 2 hours in each 3 mutually periodirections (total of 6 hours).					





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Specifications and Test Methods

No.	Ite	em		Specific	cation			Tes	t Metho	d	
4 0.	ne		No cracking or mar	•			Fig.2 using a	pacitor to the te	est jig (gla Then ap	ass epoxy board oply a force in the	ne direction
12	2 Deflection		Type GQM18 GQM21	100 a 1.0 1.2	b 3.0 4.0	1.6mm C 1.2 1.65 (in mm)	or using the re	eflow method a	nd shall and free	be conducted wof defects such surizing d:1.0mm/sec.	vith care so a as heat
				3				Fig.:	3		
13	Solderabi Terminati	•	75% of the terminati	ions is to be so	ldered evenly	and continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-8101) a rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat 80 to 120°C for 10 to 30 seconds. After preheating, immerse eutectic solder solution for 2±0.5 seconds at 230±5°C.				
		A	The measured and specifications in the	e following tab		nall satisfy the					
		Appearance	No marking defects								
14	Resistance to Soldering	Capacitance Change	Within ±2.5% or ± (Whichever is large	•			capacitor in a	eutectic solder	solution	for 1 minute. Ir at 270±5℃ for	10±0.5
	Heat	Q	Q≧1000				seconds. Let	sit at room tem	perature	for 24±2 hours	i.
		I.R.	More than 10,000M	<i>I</i> Ω or 500Ω • F	(Whichever	is smaller)					
		Dielectric Strength	No failure								
			The measured and observed characteristics shall satisfy the specifications in the following table.				-	tor to the supp		in the same ma	anner and
		Appearance	No marking defects.				Perform the fir	ve cycles acco		he four heat tre	atments
	Temperature	Capacitance	Within ±2.5% or ±	listed in the following table. Let sit for 24±2 hours at room temperature, then measure.							
15	Cycle	Change	(Whichever is large	er)			Step	1	2	3	4
		I.R.	Q≧1000 More than 10,000N	//O or 500O • F	- (Whichever	is smaller)	Temp.(°C)	Min. Operating Temp.+0/-3		Max. Operating Temp.+3/-0	Room Temp.
		Dielectric	No failure	0. 00011	(**************************************		Time(min.)	30±3	2 to 3	30±3	2 to 3
		Strength	The measured and	l observed cha	racteristics sh	nall satisfy the					
			specifications in the			- ,					
		Appearance	No marking defects				Cit discrete	40 1 20-	- 4 OC :	050/ 1	500 / 15
1,	Humidity,	Capacitance Change	Within ±5% or ±0.4 (Whichever is large	•			hours.	or at 40±2°C a	na 90 to	95% humidity f	or 500±12
16	Steady State	Q	Q≥350	J1)					-	emperature com	npensating
		I.R.	More than 1,000Ms	O. or 50O. • F (\	Whichever is s	smaller)	_ type) at room	temperature, th	nen mea	sure.	
		Dielectric Strength	No failure				-				
		g	The measured and specifications in the			nall satisfy the					
		Appearance	No marking defects				1				
17	Humidity	Capacitance Change	Within ±7.5% or ±	•				-		d 90 to 95% hui r 24±2 hours at	-
17	Load	Q	Q≥200	,			-	measure. The	charge/	discharge curre	nt is less
		I.R.	More than 500MΩ	or 25Ω • F (WI	hichever is sn	naller)	than 50mA.				
		Dielectric		(***	3	 -1	+				
		Strength	No failure								



Continued from the preceding page.

No.	Ite	em	Specification	Test Method		
			The measured and observed characteristics shall satisfy the specifications in the following table.			
		Appearance	No marking defects.	Apply 2000/ of the roted voltage for 1 000±12 hours at the		
18	High Temperature	Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	Apply 200% of the rated voltage for 1,000±12 hours at the maximum operating temperature ±3℃. Let sit for 24±2 hours (temperature compensating type) at		
	Load	d Q	Q≥350	room temperature, then measure.		
		I.R.	More than 1,000MΩ or 50Ω • F (Whichever is smaller)	The charge/discharge current is less than 50mA.		
		Dielectric Strength	No failure			

Table A

		Capacitance Change from 25℃ (%)							
Char. Code	Nominal Values (ppm/℃) Note 1	− 55℃		−30℃		−10°C			
	(ppin/c) Note i	Max.	Min.	Max.	Min.	Max.	Min.		
COG	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11		

Note 1 : Nominal values denote the temperature coefficient within a range of 25°C to 125°C. (for COG)



High-Q & High Power Type

■ Features(ERF Series)

- 1. The dielectric is composed of low dielectric loss ceramic. This series is perfectly suited to high-frequency applications. (VHS-microwave band)
- 2. The series is ultraminiature, yet has a high-power capacity. This is the best capacitor available for transmitter and amplifier circuits such as those in broadcasting equipment and mobile base stations.
- 3. ERF1D type is designed for both flow and reflow soldering and ERF22 type is designed for reflow soldering.

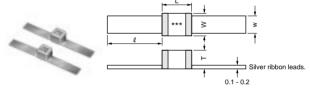


High-frequency and high-power circuits.

■ Features(ERH Series)

- 1. The dielectric is composed of low dielectric loss ceramics. This series is perfectly suited to highfrequency applications (VHS-microwave band).
- 2. The series is ultraminiature, yet has a high-power capacity. This is the best capacitor available for transmitter and amplifier circuits such as those in broadcasting equipment and mobile base stations.
- 3. ERH1X/3X Series capacitors withstand high temperatures because ribbon leads are attached with silver paste.
- 4. ERH1X/3X Series capacitors are easily soldered and especially well suited in applications where only a soldering iron can be used.

Part Number		Dimens	sions (mm)		
Part Number	L	W	T	е	
ERF1DM	1.4 ^{+0.6} _{-0.4}	1.4 +0.6	1.15 ^{+0.50} _{-0.35}	0.25 ^{+0.25} _{-0.15}	
ERF22X	2.8 ^{+0.6} _{-0.4}	2.8 ^{+0.6} _{-0.4}	2.3 +0.5	0.4 + 0.4 - 0.3	



*** : Capacitance Code

Part Number	Dimensions (mm)								
Part Number	L	W	T max.	l	w				
ERH1XC	1.6 ±0.4	1.4 ±0.4	1.6	5.0 min.	1.3 ±0.4				
ERH3XX	3.2 ±0.4	2.8 ±0.4	3.0	9.0 ±2.0	2.35 ±0.15				

■ Applications

High-frequency and high-power circuits.

Part Number	ERF1D			ERF22			ERH1X			ERH3X		
LxW	1.40x1.40			2.80x2.80			1.60x1.40	3.20x2.80				
тс	C0G (5C)					C0G (5C)	C0G (5C)					
Rated Volt.	50 (1H)	50 (1H)	100 (2A)	200 (2D)	300 (YD)	500 (2H)	50 (1H)	50 (1H)	100 (2A)	200 (2D)	300 (YD)	500 (2H)
Capacitance and	d T Dimensi	on				1	'			'		
0.5pF(R50)	1.15(M)					2.30(X)	1.60(C)					3.00(X)
0.6pF(R60)	1.15(M)					2.30(X)	1.60(C)					3.00(X)
0.7pF(R70)	1.15(M)					2.30(X)	1.60(C)					3.00(X)
0.8pF(R80)	1.15(M)					2.30(X)	1.60(C)					3.00(X)
0.9pF(R90)	1.15(M)					2.30(X)	1.60(C)					3.00(X)
1.0pF(1R0)	1.15(M)					2.30(X)	1.60(C)					3.00(X)
1.1pF(1R1)	1.15(M)					2.30(X)	1.60(C)					3.00(X)
1.2pF(1R2)	1.15(M)					2.30(X)	1.60(C)					3.00(X)
1.3pF(1R3)	1.15(M)					2.30(X)	1.60(C)					3.00(X)
1.4pF(1R4)	1.15(M)					2.30(X)	1.60(C)					3.00(X)
1.5pF(1R5)	1.15(M)					2.30(X)	1.60(C)					3.00(X)



	Continued	from	the	preceding	page.

Part Number	ERF1D			2 80v2 80			1 60×1 40			ERH3X 3.20x2.80 COG (5C) 100 200 300 (2A) (2D) (YD)		
LxW	1.40x1.40 C0G			2.80x2.80 C0G			1.60x1.40 C0G			-		
TC	(5C)			(5C)	ı	T	(5C)		T			1
Rated Volt.	50 (1H)	50 (1H)	100 (2A)	200 (2D)	300 (YD)	500 (2H)	50 (1H)	50 (1H)	100 (2A)	200 (2D)	300 (YD)	500 (2H)
Capacitance and		ion								ı	ı	
1.6pF(1R6)	1.15(M)					2.30(X)	1.60(C)					3.00(X
1.7pF(1R7)	1.15(M)					2.30(X)	1.60(C)					3.00()
1.8pF(1R8)	1.15(M)					2.30(X)	1.60(C)					3.00()
1.9pF(1R9)	1.15(M)					2.30(X)	1.60(C)					3.00()
2.0pF(2R0)	1.15(M)					2.30(X)	1.60(C)					3.00()
2.1pF(2R1) 2.2pF(2R2)	1.15(M) 1.15(M)					2.30(X) 2.30(X)	1.60(C)					3.00()
2.4pF(2R4)	1.15(M)					2.30(X)	1.60(C)					3.00()
2.4pr (2R4) 2.7pF(2R7)	1.15(M)					2.30(X)	1.60(C)					3.00()
3.0pF(3R0)	1.15(M)					2.30(X)	1.60(C)					3.00()
3.3pF(3R3)	1.15(M)					2.30(X)	1.60(C)					3.00()
3.6pF(3R6)	1.15(M)					2.30(X)	1.60(C)					3.00()
3.9pF(3R9)	1.15(M)					2.30(X)	1.60(C)					3.00()
4.3pF(4R3)	1.15(M)					2.30(X)	1.60(C)					3.00()
4.7pF(4R7)	1.15(M)					2.30(X)	1.60(C)					3.00()
5.1pF(5R1)	1.15(M)					2.30(X)	1.60(C)					3.00()
5.6pF(5R6)	1.15(M)					2.30(X)	1.60(C)					3.00()
6.2pF(6R2)	1.15(M)					2.30(X)	1.60(C)					3.00()
6.8pF(6R8)	1.15(M)					2.30(X)	1.60(C)					3.00()
7.5pF(7R5)	1.15(M)					2.30(X)	1.60(C)					3.00()
8.2pF(8R2)	1.15(M)					2.30(X)	1.60(C)					3.00()
9.1pF(9R1)	1.15(M)					2.30(X)	1.60(C)					3.00()
10.0pF(100)	1.15(M)					2.30(X)	1.60(C)					3.00()
11pF(110)	1.15(M)					2.30(X)	1.60(C)					3.00()
12pF(120)	1.15(M)					2.30(X)	1.60(C)					3.00(X
13pF(130)	1.15(M)					2.30(X)	1.60(C)					3.00(X
15pF(150)	1.15(M)					2.30(X)	1.60(C)					3.00()
16pF(160)	1.15(M)					2.30(X)	1.60(C)					3.00(X
18pF(180)	1.15(M)					2.30(X)	1.60(C)					3.00()
20pF(200)	1.15(M)					2.30(X)	1.60(C)					3.00(X
22pF(220)	1.15(M)					2.30(X)	1.60(C)					3.00(X
24pF(240)	1.15(M)					2.30(X)	1.60(C)					3.00(X
27pF(270)	1.15(M)					2.30(X)	1.60(C)					3.00(X
30pF(300)	1.15(M)					2.30(X)	1.60(C)					3.00(X
33pF(330)	1.15(M)					2.30(X)	1.60(C)					3.00(X
36pF(360)	1.15(M)					2.30(X)	1.60(C)					3.00(X
39pF(390)	1.15(M)					2.30(X)	1.60(C)					3.00(X
43pF(430)	1.15(M)					2.30(X)	1.60(C)					3.00(X
47pF(470)	1.15(M)					2.30(X)	1.60(C)					3.00(X
51pF(510)	1.15(M)					2.30(X)	1.60(C)					3.00(X
56pF(560)	1.15(M)					2.30(X)	1.60(C)					3.00(X
62pF(620)	1.15(M)					2.30(X)	1.60(C)					3.00(X
68pF(680)	1.15(M)					2.30(X)	1.60(C)					3.00(X
75pF(750)	1.15(M)					2.30(X)	1.60(C)					3.00(X
82pF(820)	1.15(M)					2.30(X)	1.60(C)					3.00(X
91pF(910)	1.15(M)					2.30(X)	1.60(C)					3.00(X
100pF(101)	1.15(M)					2.30(X)	1.60(C)					3.00()
110pF(111)					2.30(X)						3.00(X)	
120pF(121)					2.30(X)						3.00(X)	
130pF(131)					2.30(X)						3.00(X)	
150pF(151)					2.30(X)						3.00(X)	
160pF(161)					2.30(X)						3.00(X)	

Continued from the preceding page.

Part Number	ERF1D			ERF22			ERH1X			ERH3X		
LxW	1.40x1.40		2.80x2.80 1.60x1.40 3.20x2.80									
тс	C0G (5C)			C0G (5C)			C0G (5C)		C0G (5C)			
Rated Volt.	50 (1H)	50 (1H)	100 (2A)	200 (2D)	300 (YD)	500 (2H)	50 (1H)	50 (1H)	100 (2A)	200 (2D)	300 (YD)	500 (2H)
Capacitance an	d T Dimensi	ion										
180pF(181)					2.30(X)						3.00(X)	
200pF(201)					2.30(X)						3.00(X)	
220pF(221)				2.30(X)						3.00(X)		
240pF(241)				2.30(X)						3.00(X)		
270pF(271)				2.30(X)						3.00(X)		
300pF(301)				2.30(X)						3.00(X)		
330pF(331)				2.30(X)						3.00(X)		
360pF(361)				2.30(X)						3.00(X)		
390pF(391)				2.30(X)						3.00(X)		
430pF(431)				2.30(X)						3.00(X)		
470pF(471)				2.30(X)						3.00(X)		
510pF(511)			2.30(X)						3.00(X)			
560pF(561)			2.30(X)						3.00(X)			
620pF(621)			2.30(X)						3.00(X)			
680pF(681)			2.30(X)						3.00(X)			
750pF(751)		2.30(X)						3.00(X)				
820pF(821)		2.30(X)						3.00(X)				
910pF(911)		2.30(X)						3.00(X)				
1000pF(102)		2.30(X)				·		3.00(X)				

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

No.	Ite	em	Specification		Test Method				
1	Operating Temperati	ure Range	−55°C to +125°C						
2	Rated Vo	Rated Voltage Appearance Dimensions Dielectric Strength Assulation Resistance Capacitance Variation Rate Temperature Coefficient Adhesive Strength of Termination (for chip type) Ferminal Strength Tensile Strength Tensile Strength	See the previous pages.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{P-P} or V ^{O-P} , whichever is larger, shall be maintained within the rated voltagrange.					
3	Appearar	nce	No defects or abnormalities.	Visual inspection.					
4	Dimensio	ns	Within the specified dimension.	Using calipers.					
5	Dielectric	Strength	No defects or abnormalities.	applied between the t	served when 250% of the rated voltage is terminations for 1 to 5 seconds, provided current is less than 50mA.				
6	Insulation Resistance		C≦ 470pF :1,000,000MΩ min. 470pF <c≦1,000pf 100,000mω="" :="" min.<br="">C≦ 470pF : 100,000MΩ min.</c≦1,000pf>		ince shall be measured with a DC voltage ed voltage at 25°C and 125°C standard				
	(1.14.)	125 C	470pF <c≦1,000pf: 10,000mω="" min.<="" td=""><td>Harriatty and Within 2</td><td>Timides of orlarging.</td></c≦1,000pf:>	Harriatty and Within 2	Timides of orlarging.				
7	Capacita	nce	Within the specified tolerance.	1	hall be measured at 25°C at the frequency				
8	Q		C≦ 220pF : Q≥10,000 220pF <c≦ 470pf="" 5,000<br="" :="" q≥="">470pF<c≦1,000pf 3,000<br="" :="" q≥="">C : Nominal Capacitance (pF)</c≦1,000pf></c≦>	and voltage shown in Item Frequency Voltage	1±0.1MHz 0.5 to 5Vr.m.s.				
			Within the specified tolerance. (Table A-7)	tance measured in ste temperature sequenti	fficient is determined using the capaciep 3 as a reference. When cycling the interpolation step 1 through 5, the capacients				
			Within the specified tolerance. (Table A-7)	coefficient and capac	the specified tolerance for the temperature itance change as Table A. is calculated by dividing the differences				
9	Capacitance Temperature Characteristics	Capacitance Drift	Within ±0.2% or ±0.05pF (Whichever is larger)	between the maximum step 1, 3 and 5 by the	m and minimum measured values in the e cap. value in step 3. nge shall be measured after 5 min. at				
10	Terminal		No removal of the terminations or other defects shall occur.	Fig.1 using solder cordone either with an irocare so the soldering shock. Then apply a 1	to the test jig (alumina substrate) shown in that the soldering 2.5% silver. The soldering shall be con or in furnace and be conducted with its uniform and free of defects such as heat 10N* force in the direction of the arrow. *ERF1D: 5N Alumina substrate Fig.1				
10	Strength		Capacitor shall not be broken or damaged.		s fixed and a load is applied gradually in til its value reaches 10N (5N for ERH1X).				
		Bending Strength of lead wire terminal (for micro- strip type)	Lead wire shall not be cut or broken.	Position the main body of the capacitor so the lead wire terminal is perpendicular, and load 2.5N to the lead wire terminal. Bend the main body by 90 degrees, bend back to original position, bend 90 degrees in the reverse direction, and then bend back to original position.					





\square	Continued from	om the pred	eding page.		
No.	Ite	m	!	Specification	Test Method
		Appearance	No defects or abnormalities	es.	Solder the capacitor to the test jig (alumina substrate) shown in
11	Vibration Resistance	Capacitance Q	Within the specified toleral Satisfies the initial value. C≤ 220pF: Q≥' 220pF <c≤ 470pf:="" 470pf<c≤1,000pf:="" c:="" capacitance<="" nominal="" q≥="" td=""><td>10,000 5,000 3,000</td><td>Fig.2 using solder containing 2.5% silver. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so the soldering is uniform and free of defects such as heat shock. The capacitor shall be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, shall be traversed in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3 mutually perpendicular directions (total of 6 hours).</td></c≤>	10,000 5,000 3,000	Fig.2 using solder containing 2.5% silver. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so the soldering is uniform and free of defects such as heat shock. The capacitor shall be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, shall be traversed in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3 mutually perpendicular directions (total of 6 hours).
					Fig. 2
12	Solderabi Terminati	•	95% of the terminations is	to be soldered evenly and continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120°C for 10 to 30 seconds. After preheating immerse in solder containing 2.5% silver for 5±0.5 seconds at 230±5°C. The dipping depth for microstrip type capacitors is up to 1 mm from the root of the terminal.
			The measured and obse	erved characteristics shall satisfy the	
13	Resistanc to Solderii		specifications in the follow Item Appearance Capacitance Change Q I.R. Dielectric Strength	specification No marked defect Within ±2.5% or ±0.25pF (Whichever is larger) C≦ 220pF : Q≥10,000 220pF <c≤ (pf)<="" 25°c.="" 3,000="" 30%="" 470pf="" 470pf<c≤1,000pf="" 5,000="" :="" at="" c="" capacitance="" failure="" initial="" more="" no="" nominal="" of="" q≥="" specification="" td="" than="" the="" value=""><td>Preheat the capacitor at 80 to 100°C for 2 minutes and then at 150 to 200°C for 5 minutes. Immerse in solder containing 2.5% silver for 3±0.5 seconds at 270±5°C. Set at room temperature for 24±2 hours, then measure. The dipping depth for microstrip type capacitors is up to 2mm from the root of the terminal.</td></c≤>	Preheat the capacitor at 80 to 100°C for 2 minutes and then at 150 to 200°C for 5 minutes. Immerse in solder containing 2.5% silver for 3±0.5 seconds at 270±5°C. Set at room temperature for 24±2 hours, then measure. The dipping depth for microstrip type capacitors is up to 2mm from the root of the terminal.
14	4 Temperature Cycle		The measured and obsespecifications in the follow Item Appearance Capacitance Change Q I.R. Dielectric Strength	rved characteristics shall satisfy the ving table. Specification No marked defect Within ±1% or ±0.25pF (Whichever is larger) C≦ 220pF : Q≥10,000 220pF <c≤ (pf)<="" 25℃.="" 3,000="" 30%="" 470pf="" 470pf<c≤1,000pf="" 5,000="" :="" at="" c="" capacitance="" failure="" initial="" more="" no="" nominal="" of="" q≥="" specification="" td="" than="" the="" value=""><td>Fix the capacitor to the supporting jig in the same manner and under the same conditions as (11). Perform the five cycles according to the four heat treatments listed in the following table. Then, repeat twice the successive cycles of immersion, each cycle consisting of immersion in a fresh water at 65 ± 5 °C for 15 minutes and immersion in a saturated uqueous solution of salt at 0 ± 3°C for 15 minutes. The cpapcitor is promptly washed with running water, dried with a dry cloth, and allowed to sit at room temperature for 24 ± 2 hours.</td></c≤>	Fix the capacitor to the supporting jig in the same manner and under the same conditions as (11). Perform the five cycles according to the four heat treatments listed in the following table. Then, repeat twice the successive cycles of immersion, each cycle consisting of immersion in a fresh water at 65 ± 5 °C for 15 minutes and immersion in a saturated uqueous solution of salt at 0 ± 3 °C for 15 minutes. The cpapcitor is promptly washed with running water, dried with a dry cloth, and allowed to sit at room temperature for 24 ± 2 hours.
15	Humidity		The measured and obsespecifications in the follow Item Appearance Capacitance Change Q I.R.	erved characteristics shall satisfy the	Apply the 24-hour heat (-10 to +65°C) and humidity (80 to 98%) treatment shown below, 10 consecutive times. Remove, set for 24±2 hours at room temperature, and measure. Thumidity Humidity 80-98% Humidity 80-98% 90-98% 90-98% 90-98% Humidity 90-98% 90-98% 90-98% 10 10 10 10 10 10 10 10 10 10 10 10 10

C: Nominal Capacitance (pF)

One cycle 24 hours 0 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 2021 22 23 24

Continued from the preceding page.

No.	Item	9	Specification	Test Method
16	High Temperature Load	The measured and observed the specifications in the formula litem Appearance Capacitance Change Q I.R.	red characteristics shall satisfy llowing table. Specification No marked defect Within ±2.5% or ±0.25pF (Whichever is larger) C≦ 220pF : Q≧ 10,000 220pF < C≦ 470pF : Q≥ 5,000 470pF < C≦1,000pF : Q≥ 3,000 More than 30% of the initial specification value at 25°C.	Apply 150% of the rated voltage for 2,000±12 hours at 125±3°C. Remove and set for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA.
			C : Nominal Capacitance (pF)	

Table A

	- o "	Capacitance Change from 25℃ Value (%)								
Char. Code	Temp. Coeff. (ppm/°C) Note 1	- 5	5℃	-3	0℃	−10 °C				
	(ppin/c) Note i	Max.	Min.	Max.	Min.	Max.	Min.			
5C	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11			

Note 1 : Nominal values denote the temperature coefficient within a range of 25 to 125°C.



High Frequency Type

■ Features(ERA Series)

- 1. Negligible inductance is achieved by its monolithic structure so the series can be used at frequencies above 1GHz.
- 2. Nickel barriered terminations of ERA series improve solderability and decrease solder leaching.
- 3. ERA11A/21A series are designed for both flow and reflow soldering and ERA32 series are designed for reflow soldering.

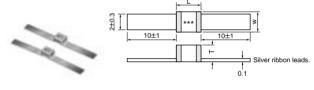
■ Applications

High-frequency and high-power circuits.

■ Features(ERD Series)

- 1. Negligible inductance is achieved by its monolithic structure so the series can be used at frequencies above 1GHz.
- 2. ERD Series capacitors withstand at high temperatures because ribbon leads are attached with
- 3. ERD Series capacitors are easily soldered and are especially well suited in applications where only a soldering iron can be used.

			L	VV							
Part Number	Dimensions (mm)										
Part Number	L	W	T max.	е	g min.						
ERA11A	1.25 ^{+0.5} _{-0.3}	1.0 +0.5	1.0±0.2	0.15 min.	0.3						
ERA21A ERA21B	2.0 +0.5 - 0.3	1.25 ^{+0.5} _{-0.3}	1.0±0.2 1.25±0.2	0.2 max.	0.5						
ERA32X	3.2 ^{+0.6} _{-0.4}	2.5 ^{+0.5} _{-0.3}	1.7±0.2	0.3 max.	0.5						



*** : Capacitance Code

Part Number	Dimensions (mm)							
Part Number	L max.	W max.	T max.					
ERD32D	4.0	3.0	2.3					

■ Application

High-frequency and high-power circuits.

Part Number		ERA11			ERA21			ERA32			ERD32	
LxW		1.25x1.00			2.00x1.25			3.20x2.50)	(1H) (2A) (3 2.3 2.3)
тс		C0G (5C)			C0G (5C)			C0G (5C)			C0G (5C)	
Rated Volt.	50 (1H)	100 (2A)	200 (2D)	50 (1H)	100 (2A)	200 (2D)	50 (1H)	100 (2A)	200 (2D)			200 (2D)
Capacitance and	d T Dimens	ion			<u>'</u>				•			
0.5pF(R50)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
0.6pF(R60)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
0.7pF(R70)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
0.8pF(R80)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
0.9pF(R90)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
1.0pF(1R0)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
1.1pF(1R1)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
1.2pF(1R2)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
1.3pF(1R3)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
1.4pF(1R4)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
1.5pF(1R5)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
1.6pF(1R6)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
1.7pF(1R7)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
1.8pF(1R8)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
1.9pF(1R9)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
2.0pF(2R0)			1.00(A)			1.00(A)			1.70(X)			2.30(D)
2.1pF(2R1)			1.00(A)			1.00(A)			1.70(X)			2.30(D)



Continued from the preceding page.

Part Number L x W		1.25x1.00			ERA21 2.00x1.25			ERA32 3.20x2.50			ERD32 4.00x3.00	
TC		COG			COG			COG			COG	
ic .		(5C)	200	F0	(5C)	200		(5C)	200		(5C)	200
Rated Volt.	50 (1H)	100 (2A)	200 (2D)	50 (1H)	100 (2A)	200 (2D)	50 (1 H)	100 (2A)	200 (2D)	50 (1H)	100 (2A)	200 (2D)
Capacitance and	IT Dimens	ion										,
2.2pF(2R2)			1.00(A)			1.00(A)			1.70(X)			2.30(D
2.4pF(2R4)			1.00(A)			1.00(A)			1.70(X)			2.30(D
2.7pF(2R7)			1.00(A)			1.00(A)			1.70(X)			2.30(D
3.0pF(3R0)			1.00(A)			1.00(A)			1.70(X)			2.30(D
3.3pF(3R3)			1.00(A)			1.00(A)			1.70(X)			2.30(D
3.6pF(3R6)			1.00(A)			1.00(A)			1.70(X)			2.30(D
3.9pF(3R9)			1.00(A)			1.00(A)			1.70(X)			2.30(D
4.3pF(4R3)			1.00(A)			1.00(A)			1.70(X)			2.30(D
4.7pF(4R7)			1.00(A)			1.00(A)			1.70(X)			2.30(D
5.1pF(5R1)			1.00(A)			1.00(A)			1.70(X)			2.30(D
5.6pF(5R6)			1.00(A)			1.00(A)			1.70(X)			2.30(D
6.2pF(6R2)			1.00(A)			1.00(A)			1.70(X)			2.30(D
6.8pF(6R8)			1.00(A)			1.00(A)			1.70(X)			2.30(D
7.5pF(7R5)			1.00(A)			1.00(A)			1.70(X)			2.30(D
8.2pF(8R2)			1.00(A)			1.25(B)			1.70(X)			2.30(D
9.1pF(9R1)			1.00(A)			1.25(B)			1.70(X)			2.30(D
10pF(100)			1.00(A)			1.25(B)			1.70(X)			2.30(D
11pF(110)			1.00(A)			1.25(B)			1.70(X)			2.30(D
12pF(120)			1.00(A)			1.25(B)			1.70(X)			2.30(D
13pF(130)			1.00(A)			1.25(B)			1.70(X)			2.30(D
15pF(150)		1.00(A)				1.25(B)			1.70(X)			2.30(D
16pF(160)		1.00(A)				1.25(B)			1.70(X)			2.30(D
18pF(180)		1.00(A)				1.25(B)			1.70(X)			2.30(D
20pF(200)		1.00(A)				1.25(B)			1.70(X)			2.30(D
22pF(220)		1.00(A)				1.25(B)			1.70(X)			2.30(D
24pF(240)	1.00(A)					1.25(B)			1.70(X)			2.30(D
27pF(270)	1.00(A)					1.25(B)			1.70(X)			2.30(D
30pF(300)	1.00(A)					1.25(B)			1.70(X)			2.30(D
33pF(330)	1.00(A)					1.25(B)			1.70(X)			2.30(D
36pF(360)	1.00(A)					1.25(B)			1.70(X)			2.30(D
39pF(390)	1.00(A)					1.25(B)			1.70(X)			2.30(D
43pF(430)	1.00(A)					1.25(B)			1.70(X)			2.30(D)
47pF(470)	1.00(A)					1.25(B)			1.70(X)			2.30(D
51pF(510)	1.00(A)					1.25(B)			1.70(X)			2.30(D
56pF(560)					1.25(B)				1.70(X)			2.30(D
62pF(620)					1.25(B)				1.70(X)			2.30(D
68pF(680)					1.25(B)				1.70(X)			2.30(D
75pF(750)					1.25(B)				1.70(X)			2.30(D
82pF(820)					1.25(B)				1.70(X)			2.30(D
91pF(910)					1.25(B)				1.70(X)			2.30(D)
100pF(101)				1.00(A)					1.70(X)			2.30(D
110pF(111)				1.25(B)					1.70(X)			2.30(D
120pF(121)				1.25(B)					1.70(X)			2.30(D
130pF(131)				1.25(B)					1.70(X)			2.30(D
150pF(151)				1.25(B)					1.70(X)			2.30(D
160pF(161)				1.25(B)				4 =000	1.70(X)		0.007	2.30(D
180pF(181)								1.70(X)			2.30(D)	
200pF(201)								1.70(X)			2.30(D)	
220pF(221)								1.70(X)			2.30(D)	
240pF(241)								1.70(X)			2.30(D)	
270pF(271)								1.70(X)			2.30(D)	

Continued from the preceding page.

Part Number		ERA11			ERA21			ERA32			ERD32	
LxW		1.25x1.00			2.00x1.25			3.20x2.50			4.00x3.00	
тс		C0G (5C)			C0G (5C)		C0G (5C)		C0G (5C)			
Rated Volt.	50 (1H)	100 (2A)	200 (2D)	50 (1H)	100 (2A)	200 (2D)	50 (1H)	100 (2A)	200 (2D)	50 (1H)	100 (2A)	200 (2D)
Capacitance and	d T Dimens	ion										
330pF(331)								1.70(X)			2.30(D)	
360pF(361)								1.70(X)			2.30(D)	
390pF(391)								1.70(X)			2.30(D)	
430pF(431)								1.70(X)			2.30(D)	
470pF(471)								1.70(X)			2.30(D)	
510pF(511)								1.70(X)			2.30(D)	
560pF(561)							1.70(X)			2.30(D)		
620pF(621)							1.70(X)			2.30(D)		
680pF(681)							1.70(X)			2.30(D)		
750pF(751)							1.70(X)			2.30(D)		
820pF(821)							1.70(X)			2.30(D)		
910pF(911)							1.70(X)			2.30(D)		
1000pF(102)							1.70(X)			2.30(D)		

The part numbering code is shown in $\ (\).$

Dimensions are shown in mm and Rated Voltage in Vdc.

No.	o. Item		Specification	Test Method			
1	Operating Temperature Range		−55°C to +125°C				
2	Rated Voltage		See the previous pages.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p.p} or V whichever is larger, shall be maintained within the rated vol range.			
3	Appearance		No defects or abnormalities.	Visual inspection.			
4	Dimensions		Within the specified dimension.	Using calipers.			
5	Dielectric Strength		No defects or abnormalities.	No failure shall be observed when 300% of the rated voltage is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA.			
6	Insulation Resistance (I.R.)		10,000MΩ min.	The insulation resistance shall be measured with a DC voltage not exceeding the rated voltage at 25°C and standard humidity and within 2 minutes of charging.			
7	Capacita	nce	Within the specified tolerance.	The capacitance/Q shall be measured at 25℃ at the frequency			
8	Q		C≦ 220pF : Q≧10,000 220pF <c≦ 470pf="" 5,000<br="" :="" q≥="">470pF<c≦1,000pf 3,000<br="" :="" q≥="">C : Nominal Capacitance (pF)</c≦1,000pf></c≦>	and voltage shown in the table. Item			
		Capacitance Variation Rate	Within the specified tolerance. (Table A-6)	The temperature coefficient is determined using the capacitance measured in step 3 as a reference. When cycling the temperature sequentially from step 1 through 5, the capacitations are considered in the capacitation of the ca			
		Temperature Coefficient	Within the specified tolerance. (Table A-6)	tance shall be within the specified tolerance for the temperatur coefficient and capacitance change as Table A. The capacitance drift is calculated by dividing the differences			
9	Capacitance Temperature Characteristics	Capacitance Drift	Within ±0.2% or ±0.05pF (Whichever is larger)	between the maximum and minimum measured values in the step 1, 3 and 5 by the cap. value in step 3. The capacitance change shall be measured after 5 min. at each specified temperature stage. Step Temperature(°C) 1 25±2 2 -55±3 3 25±2			
				4 125±3			
				5 25±2			
	Terminal Strength	Adhesive Strength of Termination (for chip type)	No removal of the terminations or other defects shall occur.	Solder the capacitor to the test jig (alumina substrate) shown in Fig.1 using solder containing 2.5% silver. The soldering shall be done either with an iron or in furnace and be conducted with care so the soldering is uniform and free of defects such as heat shock. Then apply a 10N* force in the direction of the arrow. *5N (ERA11)			
10				Fig.1			
		Tensile Strength (for micro- strip type)	Capacitor shall not be broken or damaged.	The capacitor body is fixed and a load is applied gradually in the axial direction until its value reaches 5N.			
		Bending Strength of lead wire terminal (for micro- strip type)	Lead wire shall not be cut or broken.	Position the main body of the capacitor so the lead wire terminal is perpendicular, and load 2.5N to the lead wire terminal. Bend the main body by 90 degrees, bend back to original position, bend 90 degrees in the reverse direction, and then bend back to original position.			





Continued from the preceding page.

lo.	Item	5	Specification	Test Method				
11 Vibration Resistand		No defects or abnormalities Within the specified tolerate Satisfies the initial value. C≤ 220pF: Q≥1 220pF <c≤ 470pf:="" 470pf<c≤1,000pf:="" c:="" capacitance<="" nominal="" q≥="" td=""><td>0,000 5,000 3,000</td><td colspan="5">Solder the capacitor to the test jig (alumina substrate) shown in Fig.2 using solder containing 2.5% silver. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so the soldering is uniform and free of defects such as heat shock. The capacitor shall be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, shall be traversed in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3 mutually perpendicular directions (total of 6 hours).</td></c≤>	0,000 5,000 3,000	Solder the capacitor to the test jig (alumina substrate) shown in Fig.2 using solder containing 2.5% silver. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so the soldering is uniform and free of defects such as heat shock. The capacitor shall be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, shall be traversed in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3 mutually perpendicular directions (total of 6 hours).				
1 /	Solderability of Termination 75% of the terminations is to be soldered evenly and continuously.				Fig.2 Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120°C for 10 to 30 seconds. After preheating immerse in solder containing 2.5% silver for 5±0.5 seconds at 230±5°C. The dipping depth for microstrip type capacitors is up to 1 mm from the root of the terminal.			
Resista to Sold	nce ering Heat	The measured and obse specifications in the follow Item Appearance Capacitance Change Q Dielectric Strength	Specification	Preheat according to the conditions listed in the table below. Immerse in solder containing 2.5% silver for 3±0.5 seconds at 270±5°C. Set at room temperature for 24±2 hours, then measure. The dipping depth for microstrip type capacitors is up to 2mm from the root of the terminal. Chip Size Preheat Condition 2.0X1.25mm max. 1minute at 120 to 150°C 3.2X2.5mm Each 1 minute at 100 to 120°C and then 170 to 200°C				
14 Tempe Cycle	C : Nominal Capacitance (pF) The measured and observed characteristics shall satisfy the specifications in the following table. Item		Fix the capacitor to the supporting jig in the same manner and under the same conditions as (11). Perform the five cycles according to the four heat treatments listed in the following table. Let sit for 24 \pm 2 hours at room temperature, then measure.					
15 Humidi	ty	The measured and obse specifications in the follow Item Appearance Capacitance Change Q I.R.	rved characteristics shall satisfy the	Apply the 24-hour heat (-10 to +65°C) and humidity (80 to 9 treatment shown below, 10 consecutive times. Remove, set 124±2 hours at room temperature, and measure. Humidity 80-98% Humidity 80-98% Humidity 80-98% 90-98% Humidity 80-98% Humidity 90-98% Hum				



Continued from the preceding page.

No.	Item	5	Specification	Test Method	
16	High Temperature Load	The measured and obse specifications in the follow Item Appearance Capacitance Change	rived characteristics shall satisfy the ring table. Specification No marked defect Within ±3% or ±0.3pF (Whichever is larger) C≧30pF : Q≥350 10pF≤C<30pF : Q≥275+ ½ C C<10pF : Q≥200+10C	Apply 200% of the rated voltage for 1,000±12 hours at 125±3°C. Remove and set for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA.	
		I.R.	1,000MΩ min.		
		C : Nominal Capacitance (pF)			

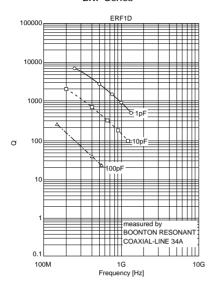
Table A

	Temperature Coefficient (ppm/°C) Note 1	Capacitance Change from 25℃ Value (%)					
Char. Code		-55°C		-30℃		−10 °C	
		Max.	Min.	Max.	Min.	Max.	Min.
5C	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11

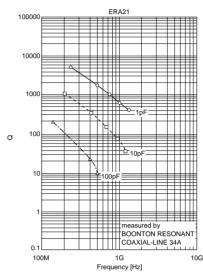
Note 1 : Nominal values denote the temperature coefficient within a range of 25 to 125°C.

ERF/ERH/ERA/ERD Series Data

■ Q-Frequency Characteristics

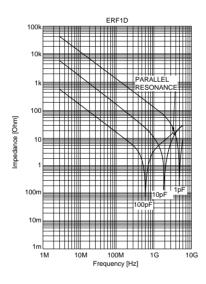


ERA Series

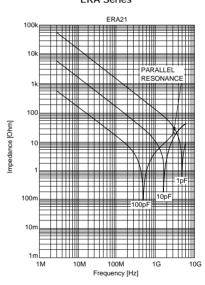


■ Impedance-Frequency Characteristics

ERF Series

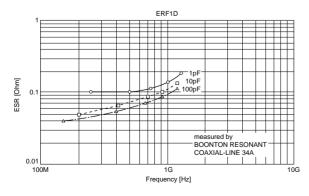


ERA Series

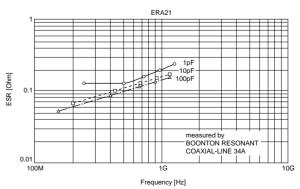


■ ESR-Frequency Characteristics

ERF Series



ERA Series



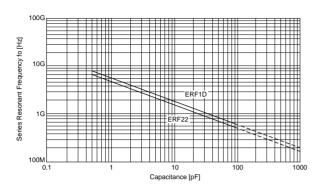


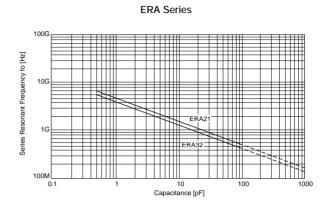
ERF/ERH/ERA/ERD Series Data

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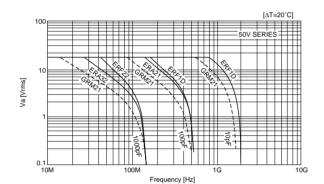
■ Resonant Frequency-Capcitance

ERF Series

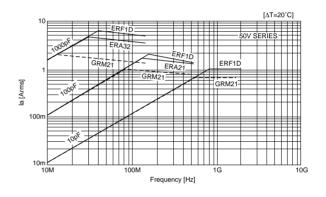




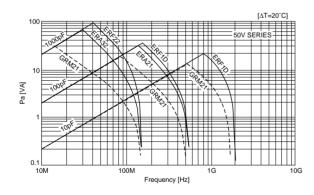
■ Allowable Voltage-Frequency



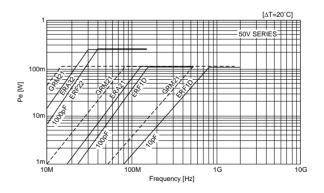
■ Allowable Current-Frequency



■ Allowable Appearent Power-Frequency



■ Allowable Effcteve Power-Frequency



■ Packaging Code

Dooksaina Tuno	Tong Comics Dockoring	Tono Carrior Dockaging Bulk Case Dockaging		Bulk Packaging	
Packaging Type	Tape Carrier Packaging	Bulk Case Packaging	Bulk Packaging in a bag	Bulk Packaging in a tray	
Packaging Code	D, L, K, J, E, F	С	В	Т	

■ Minimum Quantity Guide

		Dim	ensions ((mm)				y (pcs.)			
Part Nur	mber	I \\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\			φ180mm reel		m reel	Bulk Case	Bulk Bag		
Iltro ministruise	GRP03	L	W	T	Paper Tape	Plastic Tape	Paper Tape	Plastic Tape		1.000	
Jltra-miniaturized		0.6	0.3	0.3	15,000	-	-	-		1,000	
	GRM18	1.6	0.8	0.8	4,000	-	10,000	-	15,000	1,000	
				0.6	4,000	-	10,000	-	10,000	1,000	
For Flow/Reflow	GRM21	2.0	1.25	0.85	4,000	-	10,000	-		1,000	
				1.25	-	3,000	-	10,000	5,000	1,000	
				0.85	4,000	-	10,000	-	-	1,000	
	GRM31	3.2	1.6	1.15	-	3,000	-	10,000	-	1,000	
				1.6	-	2,000	-	6,000	-	1,000	
	GRP155	1.0	0.5	0.5	10,000	-	50,000	-	50,000	1,000	
	GRP15X	1.0	0.5	0.25	10,000	-	50,000	-	-	1,000	
				1.15	-	3,000	-	10,000	-	1,000	
For Reflow	GRM32	3.2	2.5	1.35	-	2,000	-	8,000	-	1,000	
				1.8	-	1,000	-	4,000	-	1,000	
				2.5	-	1,000	-	4,000	-	1,000	
	GRM43	4.5	3.2	2.0	-	1,000	-	4,000 2)	-	1,000	
	GRM55	5.7	5.0	2.0	-	1,000	-	4,000 2)	-	1,000	
High-power Type	GJ615	1.0	0.5	0.5	10,000	-	50,000	-	50,000	1,000	
	GJ221	2.0	1.25	1.25	-	3,000	-	10,000	-	-	
GJ231	2.2	1.6	1.15	-	3,000	-	10,000	-	•		
	GJ231	J 231 3.2	3.2	2 1.0	1.35	-	2,000	-	8,000	-	-
Smoothing 1)	C 1222	3.2	2.2	2.5	1.6	-	2,000	-	6,000	-	-
	GJ232		3.2 2.5	1.8	-	1,000	-	4,000	-	-	
	0.1040	0.1242	2.2	2.0	-	1,000	-	3,000	-	-	
	GJ243	4.5	3.2	2.5	-	500	-	2,000	-	-	
	GQM18	1.6	0.8	0.8	4,000	-	10,000	-	-	1,000	
	GQM21	2.0	1.25	1.0	4,000	-	10,000	-	-	1,000	
	ERA11	1.25	1.0	1.2	-	-	-	-	-	1,000	
High-frequency	ERA21	2.0	1.25	1.45	-	3,000	-	-	-	1,000	
	ERA32	3.2	2.5	1.9	-	2,000	-	-	-	1,000	
	ERF1D	1.4	1.4	1.65	-	2,000	-	-	-	1,000	
	ERF22	2.8	2.8	2.8	-	1,000	-	-	-	1,000	
For Ultrasonic	GRM21	2.0	1.25	0.85	4,000	-	10,000	-	-	1,000	
	GMA05	0.5	0.5	0.35	-	-	-	-	-	400 3)	
Micro Chip	GMA08	0.8	0.8	0.5	-	-	-	-	-	400 ³⁾	
				0.8	4,000	-	10,000	-	-	1,000	
Array	GNM31	3.2	1.6	1.0	-	3,000	-	10,000	-	1,000	
	LLL18	0.8	1.6	0.6	4,000	-	10,000	-	-	1,000	
	LLL21	1.25	2.0	1.0	-	4,000 4)	-	10,000	-	1,000	
Low ESL		1.20		0.7	-	4,000	-	10,000	-	1,000	
	LLL31	1.6	.6 3.2	1.25	-	3,000	-	10,000		1,000	

¹⁾ Smoothing rated are available by taping packages only.



²⁾ Depending on capacitance, some products are supplied on the 5,000pcs./reel basis.

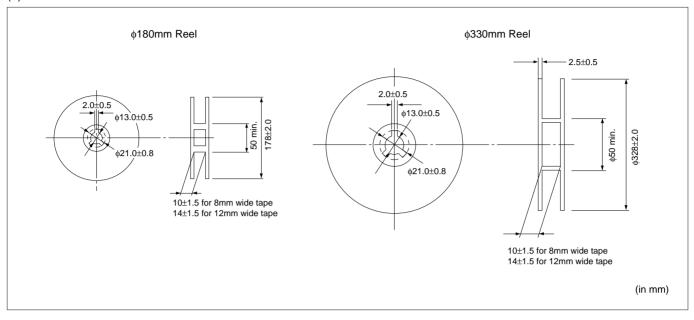
³⁾ Tray

⁴⁾ Depending on capacitance, some products are supplied on the 3,000 pcs./reel basis.

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■ Tape Carrier Packaging

(1) Dimensions of Reel

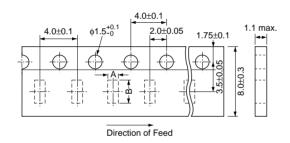


(2) Dimensions of Paper Tape

Part Number

GRM32 (T=0.85mm)





GRM18 GQM18	1.05±0.1	1.85±0.1
GRM21 (T≦1.0mm) GQM21	1.55±0.15	2.3±0.15
GRM31 GNM31 (T≦0.8mm)	2.0±0.2	3.6±0.2

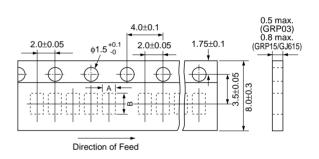
2.8±0.2

Α

В

3.6±0.2

8mm width 2mm pitch Tape



Part Number	A*	B*
GRP03	0.37	0.67
GJ615 GRP15	0.65	1.15

*Nominal Value

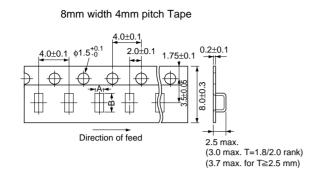
(in mm)





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(3) Dimensions of Plastic Tape



Part Number	Α	В
LLL18	1.05±0.1	1.85±0.1
GRM21 (T=1.25mm) LLL21, GJ221	1.45±0.2	2.25±0.2
GRM31 (T≥1.15mm) LLL31 GNM31 (T≥1.0mm) GJ231	1.9±0.2	3.5±0.2
GRM32 (T≧1.15mm) GJ232	2.8±0.2	3.5±0.2
ERA21	1.8*	2.6*
ERA32	2.8*	3.5*
ERE1D	2.0*	2.1*
ERE22	3.1*	3.2*

*Nominal Value

12mm width 8mm pitch Tape φ1,.5 ^{+0.1}₋₀ 8.0±0.1 2.0±0.1 0.3±0.1 Direction of feed for GRM43/GRM55 (3.7 max. for T=2.5mm) (4.7 max. for T≥3.0mm)

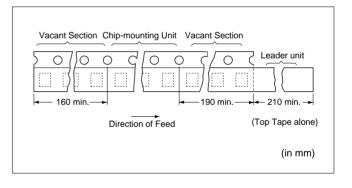
Part Number	A*	B*
GRM43, GJ243	3.6	4.9
GRM55	5.2	6.1

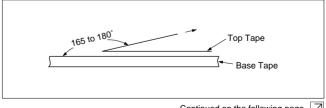
*Nominal Value

(in mm)

(4) Taping Method

- ① Tapes for capacitors are wound clockwise. The sprocket holes are to the right as the tape is pulled toward the user.
- 2 Part of the leader and part of the empty tape shall be attached to the end of the tape as follows.
- 3 The top tape and base tape are not atteached at the end of the tape for a minimum of 5 pitches.
- 4 Missing capacitors number within 0.1% of the number per reel or 1 pc, whichever is greater, and are not continuous.
- 5 The top tape and bottom tape shall not protrude beyond the edges of the tape and shall not cover sprocked holes.
- 6 Cumulative tolerance of sprocket holes, 10 pitches: ±0.3mm.
- 7 Peeling off force: 0.1 to 0.6N* in the direction shown below. *GRP03:0.05 to 0.5N





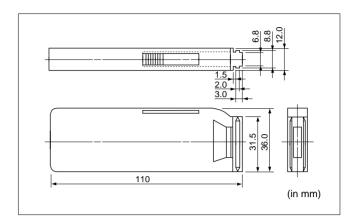


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■ Dimensions of Bulk Case Packaging

The bulk case used antistatic materials. Please contact

Murata for details.



■ Storage and Operating Conditions

Chip monolithic ceramic capacitors (chips) can experience degradation of termination solderability when subjected to high temperature or humidity, or if exposed to sulfur or chlorine gases.

Storage environment must be at an ambient temperature of 5-40 C. and an ambient humidity of 20-70%RH. Use chip within 6 months. If 6 months or more have elapsed, check solderability before use. (Reference Data 1. Solderability)

■ Rating

Die Bonding/Wire Bonding (GMA Series)

- (1) Die Bonding of Capacitors
- Use the following materials
 Braze alloy: Au-Si (98/2) 400 to 420degree C in N2 atmosphere

Au-Sn (80/20) 300 to 320degree C in N2 atmosphere Au-Ge (88/12) 380 to 400degree C in N2 atmosphere

- Mounting
 - Control the temperature of the substrate so that it matches the temperature of the braze alloy.
- 2. Place braze alloy on substrate and place the capacitor on the alloy. Hold the capacitor and

■ Handling

1. Inspection

Thrusting force of the test probe can flex the PCB,resulting in cracked chips or open solder joints. Provide support pins on the back side of the PCB to prevent warping or flexing.

- 2. Board Separation (or Depane-lization)
- Board flexing at the time of separation causes cracked chips or broken solder.
- Severity of stresses imposed on the chip at the time of board break is in the order of: PushbackFSlitterFV SlotFPerforator.
- Board separation must be performed using special jigs, not with hands.

■ Others

1. Resin Coating

When selecting resin materials, select those with low contraction.

2. Circuit Design

These capacitors on this catalog are not safety recognized products

3. Remarks

gently apply the load. Be sure to complete the operation in 1 minute.

(2) Wire Bonding

• Wire

Gold wire: 20mm (0.0008 inch), 25mm (0.001 inch) diameter

- Bonding
- 1. Thermocompression, ultrasonic ball bonding.
- 2. Required stage temperature: 150 to 250degree C
- 3. Required wedge or capillary weight: 0.5N to 2N.
- Bond the capacitor and base substrate or other devices with gold wire.

The above notices are for standard applications and conditions. Contact us when the products are used in special mounting conditions. Select optimum conditions for operation as they determine the reliability of the product after assembly. The data here in are given in typical values, not guaranteed ratings.



■ Soldering and Mounting

1. PCB Design

(1) Notice for Pattern Forms

Unlike leaded components, chip components are susceptible to flexing stresses since they are mounted directly on the substrate.

They are also more sensitive to mechanical and thermal stresses than leaded components.

Excess solder fillet height can multiply these stresses and cause chip cracking. When designing substrates, take land patterns and dimensions into consideration to eliminate the possibility of excess solder fillet height.

Pattern Forms

	Placing Close to Chassis	Placing of Chip Components and Leaded Components	Placing of Leaded Components after Chip Component	Lateral Mounting
Incorrect	Chassis Solder (ground) Electrode Pattern	Lead Wire	Soldering Iron Lead Wire	
Correct	Solder Resist	Solder Resist	Solder Resist	Solder Resist





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(2) Land Dimensions

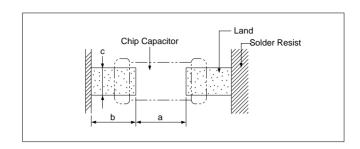


Table 1 Flow Soldering Method

Dimensions Part Number	Dimensions (LXW)	a	b	С
GRM18 GQM18	1.6×0.8	0.6-1.0	0.8-0.9	0.6-0.8
GRM21 GQM21	2.0×1.25	1.0-1.2	0.9-1.0	0.8-1.1
GRM31	3.2×1.6	2.2-2.6	1.0-1.1	1.0-1.4
LLL21	1.25×2.0	0.4-0.7	0.5-0.7	1.4-1.8
LLL31	1.6×3.2	0.6-1.0	0.8-0.9	2.6-2.8
ERA11	1.25×1.0	0.4-0.6	0.6-0.8	0.8-1.0
ERA21	2.0×1.25	1.0-1.2	0.9-1.0	0.8-1.0
ERE1D	1.4×1.4	0.5-0.8	0.8-0.9	1.0-1.2

(in mm)

Table 2 Reflow Soldering Method

Dimensions Part Number	Dimensions (LXW)	a	b	С	
GRP03	0.6×0.3	0.2-0.3	0.2-0.35	0.2-0.4	
GRP15	1.0×0.5	0.3-0.5	0.35-0.45	0.4-0.6	
GJ615	1.0 × 0.5	0.5-0.5	0.35-0.45	0.4-0.6	
GRM18	1.6×0.8	0.6-0.8	0.6-0.7	0.6-0.8	
GQM18	1.0 × 0.0	0.6-0.6	0.6-0.7	0.6-0.6	
GRM21					
GQM21	2.0×1.25	1.0-1.2	0.6-0.7	0.8-1.1	
GJ221					
GRM31	3.2×1.6	2.2-2.4	0.8-0.9	1.0-1.4	
GJ231	5.2 × 1.0	2.2 2.4	0.0 0.9	1.0-1.4	
GRM32	3.2×2.5	2.0-2.4	1.0-1.2	1.8-2.3	
GJ232	5.2 \ 2.5	2.0 2.4	1.0-1.2	1.0 2.3	
GRM43	4.5×3.2	3.0-3.5	1.2-1.4	2.3-3.0	
GJ243	4.3 / 3.2	3.0 3.3	1.2 1.4	2.5 5.0	
GRM55	5.7×5.0	4.0-4.6	1.4-1.6	3.5-4.8	
LLL18	0.8×1.6	0.2-0.4	0.3-0.4	1.0-1.4	
LLL21	1.25×2.0	0.4-0.6	0.3-0.5	1.4-1.8	
LLL31	1.6×3.2	0.6-0.8	0.6-0.7	2.6-2.8	
ERA11	1.25×1.0	0.4-0.6	0.6-0.8	0.8-1.0	
ERA21	2.0×1.25	1.0-1.2	0.6-0.8	0.8-1.0	
ERA32	3.2×2.5	2.2-2.5	0.8-1.0	1.9-2.3	
ERE1D	1.4×1.4	0.4-0.8	0.6-0.8	1.0-1.2	
ERE22	2.8×2.8	1.8-2.1	0.7-0.9	2.2-2.6	

(in mm)

Continued on the following page. $\begin{tabular}{|c|c|c|c|c|c|} \hline \end{tabular}$



Continued from the preceding page.

GNM Series for reflow soldering method

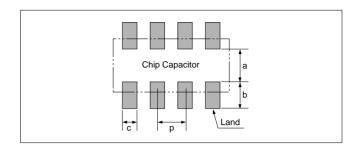
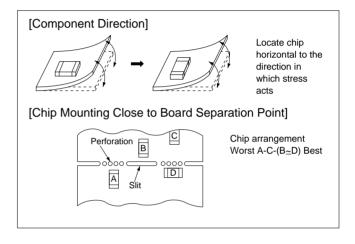


Table 3

Part Number			Dimensi	ons (mm)		
Fait Number	L W a b c				р	
GNM31	3.2	1.6	0.8-1.0	0.7-0.9	0.3-0.4	0.8

(3) Mounting Position

Choose a mounting position that minimizes the stress imposed on the chip during flexing or bending of the board.



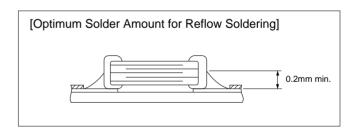
(Reference Data 2. Board bending strength for solder fillet height) (Reference Data 3. Temperature cycling for solder fillet height) (Reference Data 4. Board bending strength for board material)

2. Solder Paste Printing

• Overly thick application of solder paste results in excessive fillet height solder.

This makes the chip more susceptible to mechanical and thermal stress on the board and may cause cracked

- Too little solder paste results in a lack of adhesive strength on the outer electrode, which may result in chips breaking loose from the PCB.
- Make sure the solder has been applied smoothly to the end surface to a height of 0.2mm min.

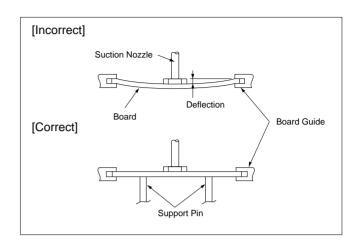




Continued from the preceding page.

3. Chip Placing

- An excessively low bottom dead point of the suction nozzle imposes great force on the chip during mounting, causing cracked chips. So adjust the suction nozzle's bottom dead point by correcting warp in the board. Normally, the suction nozzle's bottom dead point must be set on the upper surface of the board. Nozzle pressure for chip mounting must be a 1 to 3N static load.
- Dirt particles and dust accumulated between the suction nozzle and the cylinder inner wall prevent the nozzle from moving smoothly. This imposes great force on the chip during mounting, causing cracked chips. And the locating claw, when worn out, imposes uneven forces on the chip when positioning, causing cracked chips. The suction nozzle and the locating claw must be maintained, checked and replaced periodically. (Reference Data 5. Break strength)



4. Reflow Soldering

- Sudden heating of the chip results in distortion due to excessive expansion and construction forces within the chip causing cracked chips. So when preheating, keep temperature differential, ΔT , within the range shown in Table 4. The smaller the ΔT , the less stress on the chip.
- When components are immersed in solvent after mounting, be sure to maintain the temperature difference (ΔT) between the component and solvent within the range shown in the above table.

Table 4

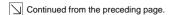
Part Number	Temperature Differential
GRP03/15, GRM18/21/31	
GJ615, GJ221/31	
LLL18/21/31	ΔT≦190°C
ERA11/21/32	
GQM18/21	
GRM32/43/55	
GNM31, GJ232/43	ΔT≦130°C
ERA32, ERE22	

Inverting the PCB

Make sure not to impose an abnormal mechanical shock on the PCB.

[Standard Conditions for Reflow Soldering] Infrared Reflow Soldering cooling (in the air) 200% Temperature(°C) Preheating 60 seconds min. 20-40 seconds 120 seconds max. Vapor Reflow Soldering Temperature(°C) Gradual cooling (in the air) Preheating 60 seconds min. 20 seconds max. 120 seconds max [Allowable Soldering Temperature and Time] Soldering temperature(${}^{\circ}$ C) 270 260 250 240 230 0 30 60 Soldering time (sec.) In case of repeated soldering, the accumulated soldering time must be within the range shown above.





5. Adhesive Application

- Thin or insufficient adhesive causes chips to loosen or become disconnected when flow soldered. The amount of adhesive must be more than dimension C shown in the drawing below to obtain enough bonding strength. The chip's electrode thickness and land thickness must be taken into consideration.
- Low viscosity adhesive causes chips to slip after mounting. Adhesive must have a viscosity of 5000pa-s (500ps)min. (at 25℃)

Adhesive Coverage*

Part Number	Adhesive Coverage*	
GRM18	O OFman Min	
GQM18	0.05mg Min.	
GRM21	O days a Mila	
GQM21	0.1mg Min.	
GRM31	0.15mg Min.	

*Nominal Value

a : 20 to 70 μm b : 30 to 35 μm c : 50 to 105 μm

6. Adhesive Curing

Insufficient curing of the adhesive causes chips to disconnect during flow soldering and causes deteriorated insulation resistance between outer electrodes due to moisture absorption.

Control curing temperature and time in order to prevent insufficient hardening.

Inverting the PCB

Make sure not to impose an abnormal mechanical shock on the PCB.

7. Leaded Component Insertion

If the PCB is flexed when leaded components (such as transformers and ICs) are being mounted, chips may crack and solder joints may break.

Before mounting leaded components, support the PCB using backup pins or special jigs to prevent warping.

8. Flux Application

- An excessive amount of flux generates a large quantity of flux gas, causing deteriorated solderability. So apply flux thinly and evenly throughout. (A foaming system is generally used for flow soldering).
- Flux containing too high a percentage of halide may cause corrosion of the outer electrodes unless sufficiently cleaned. Use flux with a halide content of 0.2wt% max.
 But do not use strongly acidix flux.

Wash thoroughly because water soluble flux causes deteriorated insulation resistance between outer electrodes unless sufficiently cleaned.

Continued from the preceding page.

9. Flow Soldering

- Sudden heating of the chip results in thermal distortion causing cracked chips. And an excessively long soldering time or high soldering temperature results in leaching of the outer electrodes, causing poor adhesion or a reduction in capacitance value due to loss of contact between electrodes and end termination.
- When preheating, keep the temperature differential between solder temperature and chip surface temperature, ΔT , within the range shown in Table 5. The smaller the ΔT , the less stress on the chip. When components are immersed in solvent after mounting, be sure to maintain the temperature difference between the component and solvent within the range shown in Table 5.

Do not apply flow soldering to chips not listed in Table 5.

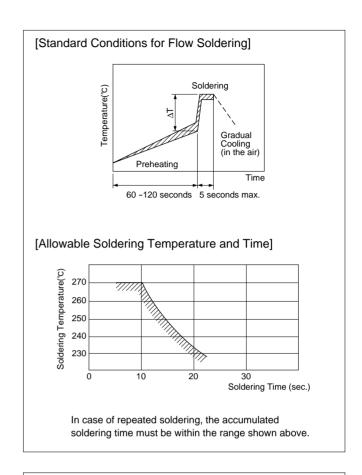
Table 5

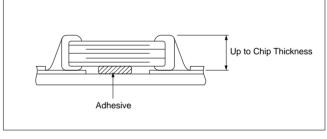
Part Number	Temperature Differential
GRM18/21/31	
LLL21/31	AT < 45000
ERA11/21, ERE1D	ΔT≦150°C
GQM18/21	

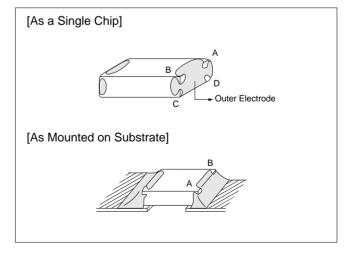
Optimum Solder Amount for Flow Soldering

• Set temperature and time to ensure that leaching of the outer electrode does not exceed 25% of the chip end area as a single chip (full length of the edge A-B-C-D shown below) and 25% of the length A-B shown below as mounted on substrate.

(Reference Data 6. Thermal shock) (Reference Data 7. Solder heat resistance)











Continued from the preceding page.

10. Correction with a Soldering Iron

(1) For Chip Type Capacitors < Except GJ2 Series>

• Sudden heating of the chip results in distortion due to a high internal temperature differential, causing cracked chips. When preheating, keep temperature differential, ΔT , within the range shown in Table 6. The smaller the ΔT , the less stress on the chip.

Table 6

Part Number	Temperature Differential
GRP15, GRM18/21/31	
GJ615	
LLL18/21/31	ΔΤ≦190℃
GQM18/21	
ERA11/21, ERE1D	
GRM32/43/55	
GNM31	ΔΤ≦130℃
ERA32, ERE22	

 Optimum Solder Amount when Corrections Are Made Using a Soldering Iron

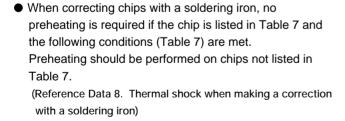
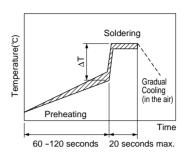


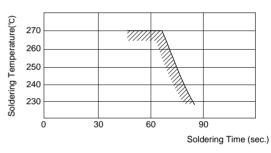
Table 7 Correction with a Soldering Iron

Part Number	Temperature of Iron Tip	Soldering Iron Wattage	Diameter of Iron Tip	Restriction	
GRP15, GRM18/21					
GJ615					
LLL18/21	300℃ max.			Do not allow the iron tip to directly touch the ceramic element.	
GQM18/21		0014/			
ERA11/21, ERE1D		20W max.	φ 3mm max.		
GRM31					
LLL31	270℃ max.				
GNM31					

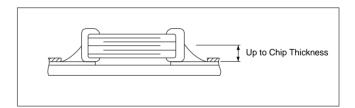




[Allowable Time and Temperature for Making Corrections with a Soldering Iron]



The accumulated soldering Time / temperature including reflow / flow soldering must be within the range shown above.



Continued from the preceding page.

(2) For GJ2 Series

• When solder GJ2 series chip capacitor, keep the following conditions.

<Soldering iron method>

Part Number	Pre-heating	Temperature of iron tip	Soldering iron wattage	Diameter of iron tip	Soldering time	Soldering amount	Restriction
GJ221/31/32/43	Δ≦130℃	300℃ max.	20W max.	φ 3mm max.	5 sec. max.	≤1/2 of chip thickness	Do not allow the iron tip to directly touch the ceramic element.

(3) For Microstrip Types

- Solder 1mm away from the ribbon terminal base, being careful that the solder tip does not directly contact the capacitor. Preheating is unnecessary.
- Complete soldering within 3 seconds with a soldering tip less than 270°C in temperature.

11. Washing

Excessive output of ultrasonic oscillation during cleaning causes PCBs to resonate, resulting in cracked chips or broken solder. Take note not to vibrate PCBs.

1. Solderability

(1) Test Method

Subject the chip capacitor to the following conditions. Then apply flux (a ethanol solution of 25% rosin) to the chip and dip it in 230°C eutectic solder for 2 seconds. Conditions:

Expose prepared at room temperature (for 6 months and 12 months, respectively)

Prepared at high temperature (for 100 hours at 85°C) Prepared left at high humidity (for 100 hours under 90%RH to 95%RH at 40℃)

(2) Test Samples

GRM21: Products for flow/reflow soldering.

(3) Acceptance Criteria

With a 60-power optical microscope, measure the surface area of the outer electrode that is covered with solder.

(4) Results

Refer to Table 1.

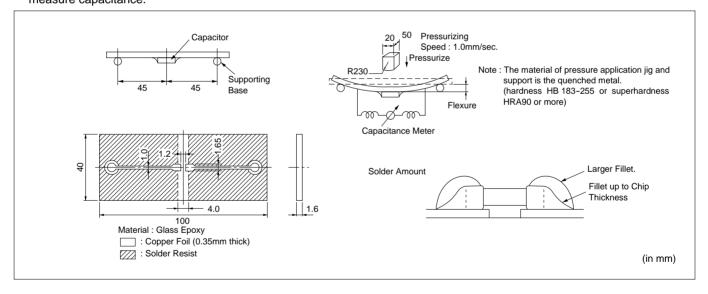
Table 1

Sample	Initial State	Prepared at Room Temperature		Prepared at High Temperature for	Prepared at High Humidity for 100 Hours at 90 to	
Sample	Illitiai State	6 months	12 months	100 Hours at 85℃	95% RH and 40°C	
GRM21 for flow/reflow soldering	95 to 100%	95 to 100%	95%	90 to 95%	95%	

2. Board Bending Strength for Solder Fillet Height

(1) Test Method

Solder the chip capacitor to the test PCB with the amount of solder paste necessary to achieve the fillet heights. Then bend the PCB using the method illustrated and measure capacitance.



(2) Test Samples

GRM21 C0G/X7R/Y5V Characteristics T=0.6mm

(3) Acceptance Criteria

Products shall be determined to be defective if the change in capacitance has exceeded the values specified in Table 2.

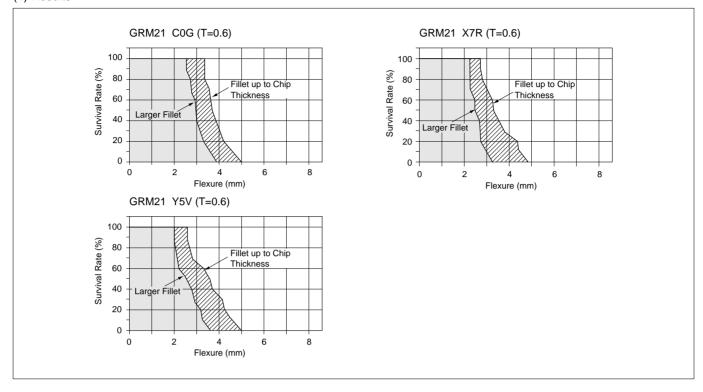
Table 2

Characteristics	Change in Capacitance
C0G	Within ±5% or ±0.5pF, whichever is greater
X7R	Within ±12.5%
Y5V	Within ±20%



Continued from the preceding page.

(4) Results



3. Temperature Cycling for Solder Fillet Height

(1) Test Method

Solder the chips to the substrate various test fixtures using sufficient amounts of solder to achieve the required fillet height. Then subject the fixtures to the cycle illustrated below 200 times.

1 Solder Amount

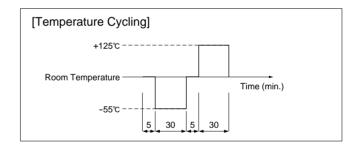
Alumina substrates are typically designed for reflow soldering.

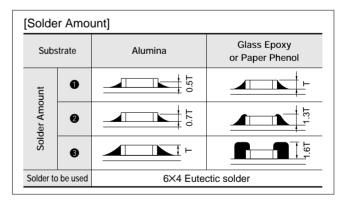
Glass epoxy or paper phenol substrates are typically used for flow soldering.

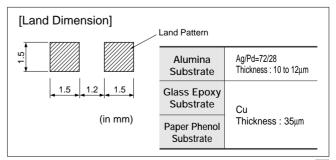
2 Material

Alumina (Thickness: 0.64mm)
Glass epoxy (Thickness: 1.6 mm)
Paper phenol (Thickness: 1.6 mm)

3 Land Dimension







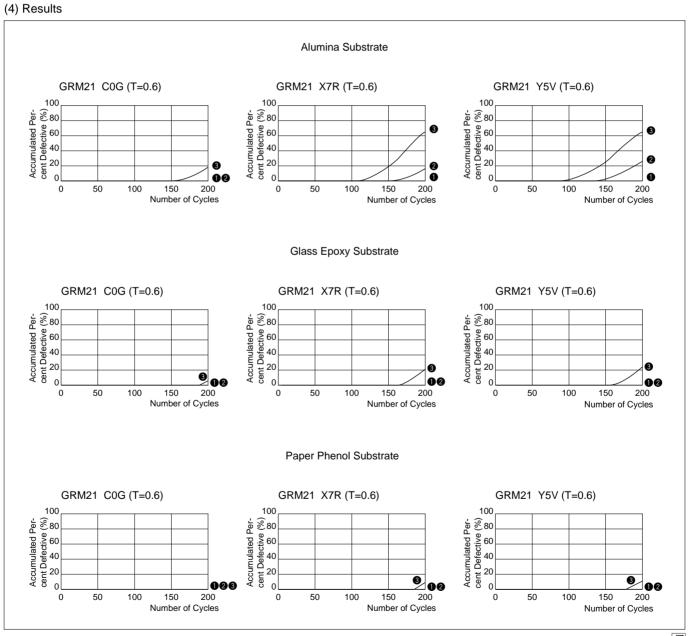
- Continued from the preceding page.
- (2) Test Samples GRM40 C0G/X7R/Y5V Characteristics T=0.6mm

(3) Acceptance Criteria

Products shall be determined to be defective if the change in capacitance has exceeded the values specified in Table 3.

Table 3

Characteristics	Change in Capacitance
COG	Within ±2.5% or ±0.25pF, whichever is greater
X7R	Within ±7.5%
Y5V	Within ±20%



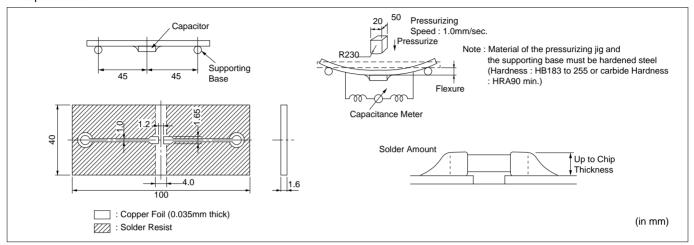


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4. Board Bending Strength for Board Material

(1) Test Method

Solder the chip to the test board. Then bend the board using the method illustrated below, as measure capacitance.



(2) Test Samples GRM21 C0G/X7R/Y5V Characteristics T=0.6mm typical

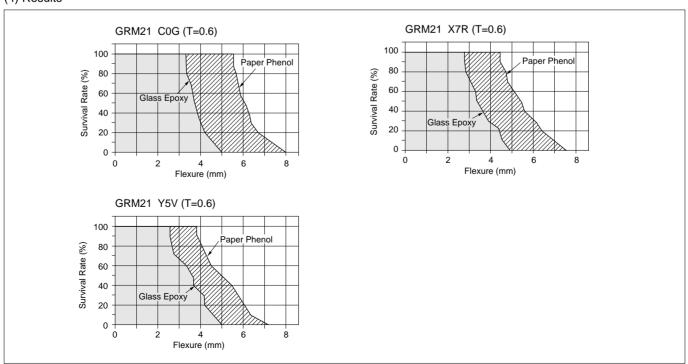
(3) Acceptance Criteria

Products shall be determined to be defective if the change in capacitance has exceeded the values specified in Table 4.

Table 4

Characteristics	Change in Capacitance
C0G	Within ±5% or ±0.5pF, whichever is greater
X7R	Within ±12.5%
Y5V	Within ±20%

(4) Results



Continued from the preceding page.

5. Break Strength

(1) Test Method

Place the chip on a steel plate as illustrated on the right. Increase load applied to a point near the center of the test sample.

(2) Test Samples

GRM21 C0G/X7R/Y5V Characteristics GRM31 C0G/X7R/Y5V Characteristics

(3) Acceptance Criteria

Define the load that has caused the chip to break or crack, as the bending force.

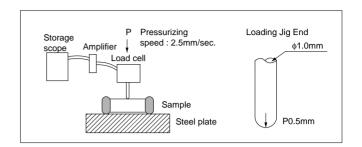
(4) Explanation

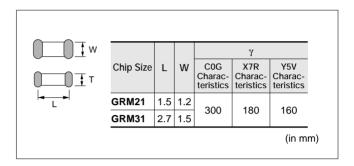
Break strength, P, is proportionate to the square of the thickness of the ceramic element and is expressed as a curve of secondary degree.

The formula is:

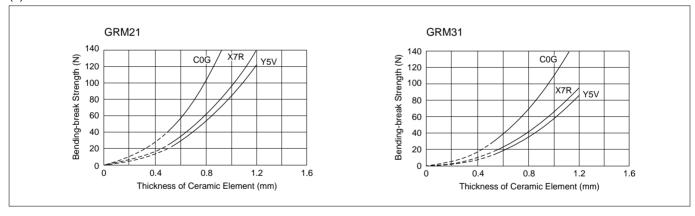
$$P = \frac{2\gamma W T^2}{3L} \quad (N)$$

W: Width of ceramic element (mm) T: Thickness of element (mm) L : Distance between fulcrums (mm) γ: Bending stress (N/mm²)





(5) Results



6. Thermal Shock

(1) Test method

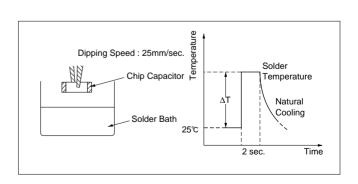
After applying flux (an ethanol solution of 25% rosin), dip the chip in a solder bath (6X4 eutectic solder) in accordance with the following conditions:

(2) Test samples

GRM21 C0G/X7R/Y5V Characteristics T=0.6mm typical

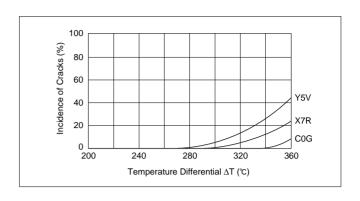
(3) Acceptance criteria

Visually inspect the test sample with a 60-power optical microscope. Chips exhibiting breaks or cracks shall be determined to be defective.



Continued from the preceding page.

(4) Results



7. Solder Heat Resistance

(1) Test Method

1 Reflow soldering:

Apply about 300 μm of solder paste over the alumina substrate. After reflow soldering, remove the chip and check for leaching that may have occurred on the outer electrode.

2 Flow soldering:

After dipping the test sample with a pair of tweezers in wave solder (eutectic solder), check for leaching that may have occurred on the outer electrode.

(2) Test samples

GRM21: For flow/reflow soldering T=0.6mm

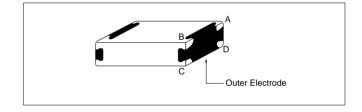
(3) Acceptance criteria

The starting time of leaching shall be defined as the time when the outer electrode has lost 25 % of the total edge length of A-B-C-D as illustrated:

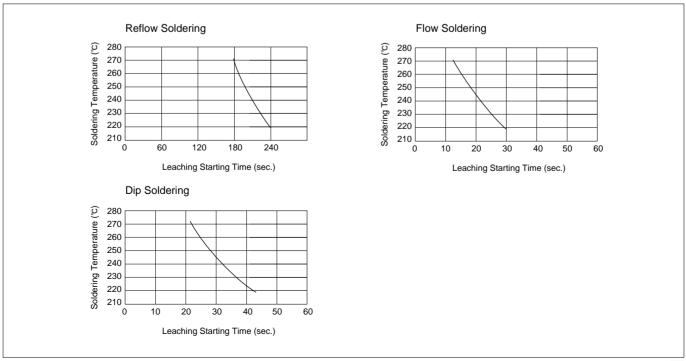
3 Dip soldering:

After dipping the test sample with a pair of tweezers in static solder (eutectic solder), check for leaching that may have occurred on the outer electrode.

4 Flux to be used : An ethanol solution of 25 % rosin.



(4) Results



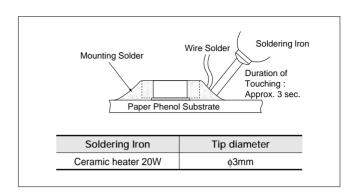
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8. Thermal Shock when Making Corrections with a Soldering Iron

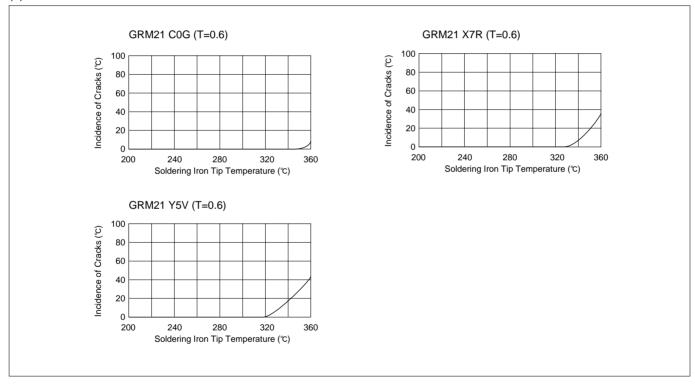
(1) Test Method

Apply a soldering iron meeting the conditions below to the soldered joint of a chip that has been soldered to a paper phenol board, while supplying wire solder. (Note: the soldering iron tip shall not directly touch the ceramic element of the chip.)

- (2) Test Samples
 GRM21 C0G/X7R/Y5V Characteristics T=0.6mm
- (3) Acceptance Criteria for Defects Observe the appearance of the test sample with a 60-power optical microscope. Those units displaying any breaks cracks shall be determined to be defective.



(4) Results



Chip Monolithic Ceramic Capacitors



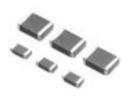
Medium-voltage Low Dissipation Factor

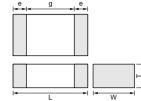
■ Features

- 1. Murata's original internal electrode structure realizes high Flash-over Voltage.
- 2. A new monolithic structure for small, surface-mountable devices capable of operating at high-voltage levels.
- 3. Sn-plated external electrodes realize good solderability.
- 4. The GRM31 type for flow and reflow soldering, and other types for reflow soldering.
- 5. Low-loss and suitable for high-frequency circuits.
- 6. The temperature characteristics C0G and SL are temperature compensating type, and R is high dielectric constant type.

■ Application

- Ideal use on high-frequency pulse circuit such as snubber circuit for switching power supply, DC-DC converter, ballast(inverter fluorescent lamp), and so on. (C0G and R Char.)
- Ideal for use as the ballast in liquid crystal back lighting inverters. (SL Char.)





Doub Nove book	Dimensions (mm)							
Part Number	L	e min.	g min.					
GRM31A	3.2 ±0.2	1.6 +0.2	1.0 +0		1.5*			
GRM31B	3.2 ±0.2	1.0 ±0.2	1.25 ⁺⁰ _{-0.3}		1.5			
GRM32Q	3.2 ±0.2	2.5 ±0.2	1.5 ⁺⁰ _{-0.3}	0.3	1.8			
GRM42D	4.5 ±0.3	2.0 ±0.2	2.0 ±0.3					
GRM43D	4.5 ±0.3	3.2 ±0.3	2.0 +0 -0.3		2.9			
GRM43E	4.5 ±0.5	3.2 ±0.3	2.5 +0 -0.3					

* GRM31B1X3D : 1.8mm min.

Part Number	Rated Voltage (V)	TC Code	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g (mm)	Electrode e (mm)
GRM31AR32J101KY01D	DC630	R	100 +10,-10%	3.2	1.6	1.0	1.5 min.	0.3 min.
GRM31A5C2J151JW01D	DC630	C0G	150 +5,-5%	3.2	1.6	1.0	1.5 min.	0.3 min.
GRM31AR32J151KY01D	DC630	R	150 +10,-10%	3.2	1.6	1.0	1.5 min.	0.3 min.
GRM31AR32J221KY01D	DC630	R	220 +10,-10%	3.2	1.6	1.0	1.5 min.	0.3 min.
GRM31AR32J331KY01D	DC630	R	330 +10,-10%	3.2	1.6	1.0	1.5 min.	0.3 min.
GRM31A5C2J471JW01D	DC630	C0G	470 +5,-5%	3.2	1.6	1.0	1.5 min.	0.3 min.
GRM31BR32J471KY01L	DC630	R	470 +10,-10%	3.2	1.6	1.25	1.5 min.	0.3 min.
GRM31BR32J681KY01L	DC630	R	680 +10,-10%	3.2	1.6	1.25	1.5 min.	0.3 min.
GRM31B5C2J102JW01L	DC630	C0G	1000 +5,-5%	3.2	1.6	1.25	1.5 min.	0.3 min.
GRM31BR32J102KY01L	DC630	R	1000 +10,-10%	3.2	1.6	1.25	1.5 min.	0.3 min.
GRM31AR33A470KY01D	DC1000	R	47 +10,-10%	3.2	1.6	1.0	1.5 min.	0.3 min.
GRM31AR33A680KY01D	DC1000	R	68 +10,-10%	3.2	1.6	1.0	1.5 min.	0.3 min.
GRM31AR33A101KY01D	DC1000	R	100 +10,-10%	3.2	1.6	1.0	1.5 min.	0.3 min.
GRM31AR33A151KY01D	DC1000	R	150 +10,-10%	3.2	1.6	1.0	1.5 min.	0.3 min.
GRM31AR33A221KY01D	DC1000	R	220 +10,-10%	3.2	1.6	1.0	1.5 min.	0.3 min.
GRM31AR33A331KY01D	DC1000	R	330 +10,-10%	3.2	1.6	1.0	1.5 min.	0.3 min.
GRM31BR33A471KY01L	DC1000	R	470 +10,-10%	3.2	1.6	1.25	1.5 min.	0.3 min.
GRM31B1X3D100JY01L	DC2000	SL	10 +5,-5%	3.2	1.6	1.25	1.8 min.	0.3 min.
GRM31B1X3D120JY01L	DC2000	SL	12 +5,-5%	3.2	1.6	1.25	1.8 min.	0.3 min.
GRM31B1X3D150JY01L	DC2000	SL	15 +5,-5%	3.2	1.6	1.25	1.8 min.	0.3 min.
GRM31B1X3D180JY01L	DC2000	SL	18 +5,-5%	3.2	1.6	1.25	1.8 min.	0.3 min.
GRM31B1X3D220JY01L	DC2000	SL	22 +5,-5%	3.2	1.6	1.25	1.8 min.	0.3 min.
GRM32Q1X3D270JY01L	DC2000	SL	27 +5,-5%	3.2	2.5	1.5	1.8 min.	0.3 min.
GRM32Q1X3D330JY01L	DC2000	SL	33 +5,-5%	3.2	2.5	1.5	1.8 min.	0.3 min.
GRM32Q1X3D390JY01L	DC2000	SL	39 +5,-5%	3.2	2.5	1.5	1.8 min.	0.3 min.
GRM32Q1X3D470JY01L	DC2000	SL	47 +5,-5%	3.2	2.5	1.5	1.8 min.	0.3 min.
GRM32Q1X3D560JY01L	DC2000	SL	56 +5,-5%	3.2	2.5	1.5	1.8 min.	0.3 min.



() Continued from the preceding page.

Part Number	Rated Voltage (V)	TC Code	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g (mm)	Electrode e (mm)
GRM32Q1X3D680JY01L	DC2000	SL	68 +5,-5%	3.2	2.5	1.5	1.8 min.	0.3 min.
GRM32Q1X3D820JY01L	DC2000	SL	82 +5,-5%	3.2	2.5	1.5	1.8 min.	0.3 min.
GRM43D1X3D121JY01L	DC2000	SL	120 +5,-5%	4.5	3.2	2.0	2.9 min.	0.3 min.
GRM43D1X3D151JY01L	DC2000	SL	150 +5,-5%	4.5	3.2	2.0	2.9 min.	0.3 min.
GRM43D1X3D181JY01L	DC2000	SL	180 +5,-5%	4.5	3.2	2.0	2.9 min.	0.3 min.
GRM43D1X3D221JY01L	DC2000	SL	220 +5,-5%	4.5	3.2	2.0	2.9 min.	0.3 min.
GRM42D1X3F100JY02L	DC3150	SL	10 +5,-5%	4.5	2.0	2.0	2.9 min.	0.3 min.
GRM42D1X3F120JY02L	DC3150	SL	12 +5,-5%	4.5	2.0	2.0	2.9 min.	0.3 min.
GRM42D1X3F150JY02L	DC3150	SL	15 +5,-5%	4.5	2.0	2.0	2.9 min.	0.3 min.
GRM42D1X3F180JY02L	DC3150	SL	18 +5,-5%	4.5	2.0	2.0	2.9 min.	0.3 min.
GRM42D1X3F220JY02L	DC3150	SL	22 +5,-5%	4.5	2.0	2.0	2.9 min.	0.3 min.
GRM42D1X3F270JY02L	DC3150	SL	27 +5,-5%	4.5	2.0	2.0	2.9 min.	0.3 min.
GRM42D1X3F330JY02L	DC3150	SL	33 +5,-5%	4.5	2.0	2.0	2.9 min.	0.3 min.
GRM42D1X3F390JY02L	DC3150	SL	39 +5,-5%	4.5	2.0	2.0	2.9 min.	0.3 min.
GRM42D1X3F470JY02L	DC3150	SL	47 +5,-5%	4.5	2.0	2.0	2.9 min.	0.3 min.
GRM42D1X3F560JY02L	DC3150	SL	56 +5,-5%	4.5	2.0	2.0	2.9 min.	0.3 min.
GRM42D1X3F680JY02L	DC3150	SL	68 +5,-5%	4.5	2.0	2.0	2.9 min.	0.3 min.
GRM42D1X3F820JY02L	DC3150	SL	82 +5,-5%	4.5	2.0	2.0	2.9 min.	0.3 min.
GRM43E1X3F101JY01L	DC3150	SL	100 +5,-5%	4.5	3.2	2.5	2.9 min.	0.3 min.

			Specif	ication				
No.	Ite	em	Temperature Compensating Type (C0G, SL Char.)	High Dielectric Constant Type (R Char.)	Test Method			
1	Operating Temperatu	ıre Range	-55 to +125℃					
2	Appearan	ice	No defects or abnormalities.		Visual inspection.			
3	Dimensio	ns	Within the specified dimension.		Using calipers.			
4	Dielectric	Strength	No defects or abnormalities.		No failure shall be observed when voltage in Table is applied between the terminations for 1 to 5 s, provided the charge/ discharge current is less than 50mA. Rated voltage More than DC 1kV 120% of the rated voltage Less than DC 1kV 150% of the rated voltage			
5	Insulation F (I.R.)	Resistance	More than 10,000M Ω		The insulation resistance shall be measured with 500 \pm 50V and within 60 \pm 5 s of charging.			
6	Capacitar	nce	Within the specified tolerance.		The capacitance/Q/D.F. shall be measured at 20°C at the			
7	Q/ Dissipation Factor (D.		C≥30pF : Q≥1,000 C<30pF : Q≥400+20C C : Nominal Capacitance (pF)	D.F.≦0.01	frequency and voltage shown as follows. (1) Temperature Compensating Type Frequency: 1±0.2MHz Voltage: 0.5 to 5V (r.m.s.) (2) High Dielectric Constant Type Frequency: 1±0.2kHz Voltage: 1±0.2V (r.m.s.)			
8	Capacitar Temperat Character	ure	Temp. Coefficient C0G char.: 0±30ppm/°C (Temp. Range: +20 to +85°C) SL char.: +350 to −1,000 ppm/°C (Temp. Range: +20 to +85°C)	Cap. Change Within ±15%	(1) Temperature Compensating Type The temperature coefficient is determined using the capacitance measured in step 3 as a reference. When cycling the temperature sequentially from step 1 through 5 (+20 to +85 ℃) the capacitance shall be within the specified tolerance for the temperature coefficient. Step			
9	Adhesive Strength of Termination No removal of the termin		No removal of the terminations	or other defect shall occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig.1 using a eutectic solder. Then apply 10N force in the direction of the arrow. The soldering shall be done either with an iron or using the reflo			
		Appearance	No defects or abnormalities.		Solder the capacitor to the test jig (glass epoxy board).			
		Capacitance	Within the specified tolerance.		The capacitor shall be subjected to a simple harmonic motion			
10	Vibration Resistance	Q/D.F.	C≥30pF : Q≥1,000 C<30pF : Q≥400+20C C : Nominal Capacitance (pF)	D.F.≦0.01	having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, shall be traversed in approximately 1 min. This motion shall be applied for a period of 2 h in each 3 mutually perpendicular directions (total of 6 h). Solder resist Glass Epoxy Board			
"D			estura i 15 to 25°C. Bolotivo humin	ditur 15 to 750/ Atmoonbara are				

[&]quot;Room condition" Temperature : 15 to 35°C, Relative humidity : 45 to 75%, Atmosphere pressure : 86 to 106kPa

Continued from the preceding page Specification No Item Test Method **High Dielectric Temperature Compensating** Type (C0G, SL Char.) Constant Type (R Char.) Solder the capacitor to the testing jig (glass epoxy board) shown No cracking or marking defects shall occur. in Fig.2 using a eutectic solder. Then apply a force in the direction shown in Fig.3. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so that the soldering is uniform and free of defects such as heat shock. Deflection | Pressurize t : 1.6 100 Dimension (mm) LXW (mm) d 3.2X1.6 5.0 2.0 2.2 2.2 2.9 (in mm) 3.2X2.5 5.0 1.0 4.5×2.0 3.5 7.0 2.4 Fig.3 4.5×3.2 3.5 7.0 3.7 Fig.2 Immerse the capacitor in a solution of ethanol (JIS-K-8101) and Solderability of rosin (JIS-K-5902) (25% rosin in weight proportion). Immerse in 75% of the terminations are to be soldered evenly Termination and continuously eutectic solder solution for 2±0.5 s at 235±5°C. Immersing speed: 25±2.5mm/s Preheat the capacitor at 120 to 150°C* for 1 min. No marking defects. Appearance Immerse the capacitor in eutectic solder solution at 260±5℃ for Capacitance Within $\pm 2.5\%$ or ± 0.25 pF Within ±10% 10±1 s. Let sit at room condition for 24±2 h, then measure. Change (Whichever is larger) •Immersing speed: 25±2.5mm/s Pretreatment for high dielectric constant type C≥30pF: Q≥1,000 Resistance Perform a heat treatment at 150 + o °C for 60±5 min and then D F ≤0.01 O/D.F C<30pF: Q≥400+20C 13 to Soldering C: Nominal Capacitance (pF) let sit for 24±2 h at room condition. Heat I.R. More than $10,000M\Omega$ *Preheating for more than 3.2×2.5mm Step Temperature Time Dielectric Pass the item No.4. 100℃ to 120℃ 1 min. Strength 170℃ to 200℃ 1 min. No marking defects. Fix the capacitor to the supporting jig (glass epoxy board) shown Appearance in Fig.4 using a eutectic solder. Canacitance Within +2.5% or +0.25pF Within ±10% Perform the five cycles according to the four heat treatments Change (Whichever is larger) listed in the following table. C≥30pF: Q≥1,000 Let sit for 24±2 h at room condition, then measure Q/D.F. C<30pF : Q≥400+20C D.F.≤0.01 Temperature (°C) Time (min) Step C: Nominal Capacitance (pF) 30±3 Min. Operating Temp.±3 2 Room Temp. 2 to 3 I.R More than $10,000M\Omega$ 3 Max. Operating Temp.±2 30 ± 3 4 Room Temp 2 to 3 Temperature 14 Pretreatment for high dielectric constant type Cycle Perform a heat treatment at 150 ± o o for 60 ± 5 min and then let sit for 24±2 h at room condition. Dielectric Pass the item No.4. Strength **M M M M** • Glass Epoxy Board Fig.4 Appearance No marking defects. Capacitance Within $\pm 5.0\%$ or ± 0.5 pF Within ±10% Sit the capacitor at 40±2℃ and relative humidity 90 to 95% for Change (Whichever is larger) 500 ±24 h. Humidity C≥30pF : Q≥350 Remove and let sit for 24±2 h at room condition, then measure. (Steady Q/D.F. C<30pF : Q≥275+ 5 C D.F.≦0.01 Pretreatment for high dielectric constant type State) C: Nominal Capacitance (pF) Perform a heat treatment at 150 ± 18 °C for 60±5 min and then I.R. More than $1,000M\Omega$ let sit for 24±2 h at room condition. Dielectric Pass the item No.4.

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[&]quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

Continued from the preceding page.

			Specif	ication		
No.	Ite	em	Temperature Compensating Type (C0G, SL Char.)	High Dielectric Constant Type (R Char.)		Test Method
		Appearance	No marking defects.		Apply the voltage in follow	ring table for 1,000 ± 48 at maximum
		Capacitance Change	Within ±3.0% or ±0.3pF (Whichever is larger)	Within ±10%	operating temperature±3°c. Remove and let sit for 24±2 The charge/discharge curren • Pretreatment for high dielect Apply test voltage for 60±5 Remove and let sit for 24±2	£2 h at room condition, then measure.
16	Life	Q/D.F.	C≥30pF : Q≥350 C<30pF : Q≥275+ ½ C C : Nominal Capacitance (pF)	D.F.≦0.02		lectric constant type ±5 min at test temperature.
		I.R.	More than 1,000MΩ		Rated voltage	Test voltage
		Dielectric Strength	Pass the item No.4.		More than DC 1kV Less than DC 1kV	Rated voltage 120% of the rated voltage

[&]quot;Room condition" Temperature : 15 to 35°C, Relative humidity : 45 to 75%, Atmosphere pressure : 86 to 106kPa

Chip Monolithic Ceramic Capacitors



Medium-voltage High-Capacitance for General-Use

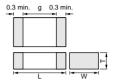
■ Features

- 1. A new monolithic structure for small, high-capacitance capable of operating at high-voltage levels.
- 2. Sn-plated external electrodes allow mounting without silver compound solder.
- 3. The GRM21/31 type for flow and reflow soldering, and other types for reflow soldering.

■ Applications

- 1. Ideal use as hot-cold coupling for DC-DC converter.
- 2. Ideal use on line filter and ringer detector for telephone, facsimile and modem.
- Ideal use on diode-snubber circuit for switching power supply.





Part Number		Din	nensions (mm)		
Part Number	L W T			g min.	
GRM21A	2.0 ±0.2	.0 ±0.2 1.25 ±0.2 1.0 +0,-0.3		0.7	
GRM21B	2.0 ±0.2	1.23 ±0.2	1.25 ±0.2	0.7	
GRM31B	3.2 ±0.2	1.6 ±0.2	1.25 +0,-0.3		
GRM31C	3.2 ±0.2	1.0 ±0.2	1.6 ±0.2	1.2	
GRM32Q	3.2 ±0.3	2.5 ±0.2	1.5 +0,-0.3		
GRM32D	3.2 ±0.3	2.5 ±0.2	2.0 +0,-0.3		
GRM43Q	4.5 ±0.4	3.2 ±0.3	1.5 +0,-0.3	2.2	
GRM43D	4.5 ±0.4	3.2 ±0.3	2.0 +0,-0.3	2.2	
GRM55D	5.7 ±0.4	5.0 ±0.4	2.0 +0,-0.3	3.2	
GRM55X	5.7 ±0.4	5.0 ±0.4	2.7 +0,-0.3	3.2	

Part Number	Rated Voltage (V)	TC Code	Capacitance	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g (mm)	Electrode e (mm)
GRM21AR72E102KW01D	DC250	X7R	1000pF +10,-10%	2.0	1.25	1.0	0.7 min.	0.3 min.
GRM21AR72E152KW01D	DC250	X7R	1500pF +10,-10%	2.0	1.25	1.0	0.7 min.	0.3 min.
GRM21AR72E222KW01D	DC250	X7R	2200pF +10,-10%	2.0	1.25	1.0	0.7 min.	0.3 min.
GRM21AR72E332KW01D	DC250	X7R	3300pF +10,-10%	2.0	1.25	1.0	0.7 min.	0.3 min.
GRM21AR72E472KW01D	DC250	X7R	4700pF +10,-10%	2.0	1.25	1.0	0.7 min.	0.3 min.
GRM21AR72E682KW01D	DC250	X7R	6800pF +10,-10%	2.0	1.25	1.0	0.7 min.	0.3 min.
GRM21BR72E103KW03L	DC250	X7R	10000pF +10,-10%	2.0	1.25	1.25	0.7 min.	0.3 min.
GRM31BR72E153KW01L	DC250	X7R	15000pF +10,-10%	3.2	1.6	1.25	1.2 min.	0.3 min.
GRM31BR72E223KW01L	DC250	X7R	22000pF +10,-10%	3.2	1.6	1.25	1.2 min.	0.3 min.
GRM31CR72E333KW03L	DC250	X7R	33000pF +10,-10%	3.2	1.6	1.6	1.2 min.	0.3 min.
GRM31CR72E473KW03L	DC250	X7R	47000pF +10,-10%	3.2	1.6	1.6	1.2 min.	0.3 min.
GRM32QR72E683KW01L	DC250	X7R	68000pF +10,-10%	3.2	2.5	1.5	1.2 min.	0.3 min.
GRM32DR72E104KW01L	DC250	X7R	0.1μF +10,-10%	3.2	2.5	2.0	1.2 min.	0.3 min.
GRM43QR72E154KW01L	DC250	X7R	0.15μF +10,-10%	4.5	3.2	1.5	2.2 min.	0.3 min.
GRM43DR72E224KW01L	DC250	X7R	0.22μF +10,-10%	4.5	3.2	2.0	2.2 min.	0.3 min.
GRM55DR72E334KW01L	DC250	X7R	0.33μF +10,-10%	5.7	5.0	2.0	3.2 min.	0.3 min.
GRM55DR72E474KW01L	DC250	X7R	0.47μF +10,-10%	5.7	5.0	2.0	3.2 min.	0.3 min.
GRM31BR72J102KW01L	DC630	X7R	1000pF +10,-10%	3.2	1.6	1.25	1.2 min.	0.3 min.
GRM31BR72J152KW01L	DC630	X7R	1500pF +10,-10%	3.2	1.6	1.25	1.2 min.	0.3 min.
GRM31BR72J222KW01L	DC630	X7R	2200pF +10,-10%	3.2	1.6	1.25	1.2 min.	0.3 min.
GRM31BR72J332KW01L	DC630	X7R	3300pF +10,-10%	3.2	1.6	1.25	1.2 min.	0.3 min.
GRM31BR72J472KW01L	DC630	X7R	4700pF +10,-10%	3.2	1.6	1.25	1.2 min.	0.3 min.
GRM31BR72J682KW01L	DC630	X7R	6800pF +10,-10%	3.2	1.6	1.25	1.2 min.	0.3 min.
GRM31BR72J103KW01L	DC630	X7R	10000pF +10,-10%	3.2	1.6	1.25	1.2 min.	0.3 min.
GRM31CR72J153KW03L	DC630	X7R	15000pF +10,-10%	3.2	1.6	1.6	1.2 min.	0.3 min.
GRM32QR72J223KW01L	DC630	X7R	22000pF +10,-10%	3.2	2.5	1.5	1.2 min.	0.3 min.
GRM32DR72J333KW01L	DC630	X7R	33000pF +10,-10%	3.2	2.5	2.0	1.2 min.	0.3 min.
GRM32DR72J473KW01L	DC630	X7R	47000pF +10,-10%	3.2	2.5	2.0	1.2 min.	0.3 min.
GRM43QR72J683KW01L	DC630	X7R	68000pF +10,-10%	4.5	3.2	1.5	2.2 min.	0.3 min.
GRM43DR72J104KW01L	DC630	X7R	0.1μF +10,-10%	4.5	3.2	2.0	2.2 min.	0.3 min.
GRM55DB32J154KY01L	DC630	В	0.15μF +10,-10%	5.7	5.0	2.0	3.5 min.	0.3 min.
GRM55XB32J224KY05L	DC630	В	0.22μF +10,-10%	5.7	5.0	2.7	3.5 min.	0.3 min.

No.	Ite	m	Specification	Test Method			
1	Operating Temperatu	re Range	-55 to +125℃	_			
2	Appearan	ce	No defects or abnormalities.	Visual inspection.			
3	Dimension	าร	Within the specified dimensions.	Using calipers.			
4	Dielectric Strength		No defects or abnormalities.	No failure shall be observed when 150% of the rated voltage (200% of the rated voltage in case of rated voltage: DC 250V) is applied between the terminations for 1 to 5 s, provided the charge/discharge current is less than 50mA.			
5	Insulation R (I.R.)	tesistance	C≥0.01μF : More than 100MΩ • μF C<0.01μF : More than 10,000MΩ	The insulation resistance shall be measured with $500\pm50V$ ($250\pm50V$ in case of rated voltage: DC $250V$) and within 60 ± 5 s of charging.			
6	Capacitan	ice	Within the specified tolerance.	The capacitance/D.F. shall be measured at 20°C at a frequency of 1±0.2kHz and a voltage of 1±0.2V (r.m.s.) •Pretreatment			
7	Dissipatio Factor (D.		0.025 max.	Perform a heat treatment at 150^{+0}_{-10} °C for 60 ± 5 min and then let sit for 24 ± 2 h at room condition.			
8	Capacitan Temperatu Characteri	rature (Temp. Range : −25 to +85°C)		The range of capacitance change compared with the 20° C (B), 25° C (X7R) value within -25 to $+85^{\circ}$ C shall be within the specified range. •Pretreatment Perform a heat treatment at $150^{+}_{-10}^{\circ}$ C for 60 ± 5 min and then let sit for 24 ± 2 h at room condition.			
9	Adhesive Strength of Termination		No removal of the terminations or other defect shall occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig.1 using a eutectic solder. Then apply 10N force in the direction of the arrow. The soldering shall be done either with an iron or using the reflo			
				Fig.1			
		Appearance	No defects or abnormalities.	Solder the capacitor to the test jig (glass epoxy board).			
10	Capacitance		Within the specified tolerance. 0.025 max.	The capacitor shall be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, shall be traversed in approximately 1 min. This motion shall be applied for a period of 2 h in each 3 mutually perpendicular directions (total of 6 h).			
			No cracking or marking defects shall occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig.2 using a eutectic solder.			
11	Deflection	b 64.5		Then apply a force in the direction shown in Fig.3. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing speed:1.0mm/s Pressurize Pressurize Gapacitance meter 45 (in mm) Fig.3			

"Room condition" Temperature : 15 to 35°C, Relative humidity : 45 to 75%, Atmosphere pressure : 86 to 106kPa

Continued on the following page. $\begin{tabular}{|c|c|c|c|} \hline \end{tabular}$



Continued from the preceding page.

lo.	Ite	em	Specification	Test Method Immerse the capacitor in a solution of ethanol (JIS-K-8101)				
12	Solderab Terminati		75% of the terminations is to be soldered evenly and continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Immerse in eutectic solder solution for 2±0.5 s at 235±5°C. Immersing speed: 25±2.5mm/s				
		Appearance	No marking defects.	Preheat the capacitor at 120 to 150°C* for 1 min.				
	Resistance	Capacitance Change	Within ±10%	Immerse the capacitor in eutectic solder solution at 260±5°C for 10±1 s. Let sit at room condition for 24±2 h, then measure.				
		D.F.	0.025 max.	•Immersing speed : 25±2.5mm/s •Pretreatment				
3	to Soldering Heat	I.R.	C≧0.01μF : More than 100MΩ • μF C<0.01μF : More than 10,000MΩ	Perform a heat treatment at 150±18°C for 60±5 min and then let sit for 24±2 h at room condition.				
				*Preheating for more than 3.2×2.5mm				
		Dielectric Strength Pass the item No.4.		Step Temperature Time 1 100℃ to 120℃ 1 min. 2 170℃ to 200℃ 1 min.				
		Appearance	No marking defects.	Fix the capacitor to the supporting jig (glass epoxy board) show				
		Capacitance Change	Within ±7.5%	in Fig.4 using a eutectic solder. Perform the five cycles according to the four heat treatments				
		D.F.	0.025 max.	listed in the following table. Let sit for 24±2 h at room condition, then measure.				
			C≥0.01μF : More than 100MΩ • μF	Step Temperature (°C) Time (min)				
		I.R.	$C \le 0.01 \mu F$: More than $10,000 M\Omega$	1 Min. Operating Temp.±3 30±3				
			1 1/111	2 Room Temp. 2 to 3				
				3 Max. Operating Temp.±2 30±3 4 Room Temp. 2 to 3				
		Dielectric Strength Pass the item No.4.		Perform a heat treatment at 150±18°C for 60±5 min and then let sit for 24±2 h at room condition.				
		Appearance	No marking defects.					
		Capacitance Change	Within ±15%	Sit the capacitor at $40\pm2^{\circ}\text{C}$ and relative humidity 90 to 95% for $500\pm^{20}_{\circ}\text{h}$.				
5	Humidity (Steady	D.F.	0.05 max.	Remove and let sit for 24±2 h at room condition, then measure				
J	State)	I.R.	C≥0.01μF : More than $10MΩ • μF$ $C<0.01μF$: More than $1,000MΩ$	Pretreatment Perform a heat treatment at 150 ± 10 °C for 60±5 min and then let sit for 24±2 h at room condition.				
		Dielectric Strength	Pass the item No.4.	et sit for 24±2 if at footh condition.				
		Appearance	No marking defects.					
		Capacitance Change	Within ±15%	Apply 120% of the rated voltage (150% of the rated voltage in case of rated voltage: DC250V) for 1,000 ^{±48} h at maximum operating temperature±3°C. Remove and let sit for 24 ±2 h at				
,	1 :6-	D.F.	0.05 max.	room condition, then measure.				
6	Life	I.R.	$C≥0.01\mu F$: More than $10MΩ • μF$ C<0.01μF: More than $1,000MΩ$	The charge/discharge current is less than 50mA. •Pretreatment				
		Dielectric Strength	Pass the item No.4.	Apply test voltage for 60±5 min at test temperature. Remove and let sit for 24±2 h at room condition.				
		Appearance	No marking defects.					
		Capacitance Change	Within ±15%	Apply the rated voltage at 40±2°C and relative humidity 90 to				
	Humidity	D.F.	0.05 max.	95% for 500 ^{±2} 6 h. Remove and let sit for 24±2 h at room condition, then measure				
7	Loading	I.R.	C≥0.01μF : More than 10MΩ • μF C<0.01μF : More than 1,000MΩ	Pretreatment Apply test voltage for 60±5 min at test temperature.				
		Dielectric Strength Pass the item No.4.		Remove and let sit for 24±2 h at room condition.				

[&]quot;Room condition" Temperature : 15 to 35°C, Relative humidity : 45 to 75%, Atmosphere pressure : 86 to 106kPa

Chip Monolithic Ceramic Capacitors



AC250V(r.m.s.) Type

■ Features

- 1. Chip monolitic ceramic capacitor for AC line.
- 2. A new monolithic structure for small, high-capacitance capable of operating at high-voltage levels.
- 3. Sn-plated external electrodes realize good solderability.
- 4. Only for Reflow soldering.
- 5. Capacitance 0.01 to 0.1 uF for connecting lines and 470 to 4700 pF for connecting line to earth.



Noise suppression filters for switching power supplies, telephones, facsimiles, modems.

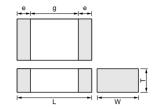
■ Refference standard

JIS C 5102

JIS C 5150

The standards of the electrical appliance and material control law of Japan, separated table 4.





Part Number	Dimensions (mm)							
Part Number	L	L W T		e min.	g min.			
GA252D	5.7 ±0.4	2.8 ±0.3	2.0 ±0.3	0.3	3.5			
GA255D	5.7 ±0.4	5.0 ±0.4	2.0 ±0.3	0.3				

Part Number	Rated Voltage (V)	TC Code	Capacitance	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g (mm)	Electrode e (mm)
GA252DB3E2471MY02L	AC250 (r.m.s.)	В	470pF +20,-20%	5.7	2.8	2.0	3.5 min.	0.3 min.
GA252DB3E2102MY02L	AC250 (r.m.s.)	В	1000pF +20,-20%	5.7	2.8	2.0	3.5 min.	0.3 min.
GA252DB3E2222MY02L	AC250 (r.m.s.)	В	2200pF +20,-20%	5.7	2.8	2.0	3.5 min.	0.3 min.
GA252DB3E2472MY02L	AC250 (r.m.s.)	В	4700pF +20,-20%	5.7	2.8	2.0	3.5 min.	0.3 min.
GA252DB3E2103MY02L	AC250 (r.m.s.)	В	10000pF +20,-20%	5.7	2.8	2.0	3.5 min.	0.3 min.
GA252DB3E2223MY02L	AC250 (r.m.s.)	В	22000pF +20,-20%	5.7	2.8	2.0	3.5 min.	0.3 min.
GA252DB3E2473MY02L	AC250 (r.m.s.)	В	47000pF +20,-20%	5.7	2.8	2.0	3.5 min.	0.3 min.
GA255DB3E2104MY02L	AC250 (r.m.s.)	В	0.1μF +20,-20%	5.7	5.0	2.0	3.5 min.	0.3 min.

100

Ite	em	Specification	Test Method				
Operating Temperatu	ıre Range	−25 to +85°C	-				
Appearan	nce	No defects or abnormalities.	Visual inspection.				
Dimensio	ns	Within the specified dimensions.	Using calipers.				
Dielectric Strength		No defects or abnormalities.	No failure shall be observed when voltage as table is applied between the terminations for 60±1 s, provided the charge/discharge current is less than 50mA. Nominal Capacitance Test voltage C≥10,000pF AC575V (r.m.s.) C<10,000pF AC1500V (r.m.s.)				
Insulation F (I.R.)	Resistance	More than $2,000M\Omega$	The insulation resistance shall be measured with 500±50V and within 60±5 s of charging.				
Capacitar	nce	Within the specified tolerance.					
		0.025 max.	The capacitance/D.F. shall be measured at 20°C at a frequency of 1±0.2kHz and a voltage of 1±0.2V (r.m.s.)				
O.025 max. Capacitance Temperature Characteristics Cap. Change Within ±10% Perform a heat treatment at 150 ± 18 °C for let sit for 24±2 h at room condition.							
Discharge Test (Application: Nominal Capacitance C<10,000pF)	Appearance	No defects or abnormalities.	As in Fig., discharge is made 50 times at 5 s intervals from the capacitor(Cd) charged at DC voltage of specified. R3 R1 Ct: Capacitor under test Cd: 0.001μF R1: 1,000Ω R2: 100ΜΩ R3: Surge resistance				
Adhesive Strength of Termination		No removal of the terminations or other defects shall occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig.1 using a eutectic solder. Then apply 10N force in the direction of the arrow. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so that the soldering is uniform and free of defects such as heat shock. 10N, 10±1s Speed: 1.0mm/s Glass Epoxy Board Fig.1				
	Appearance	No defects or abnormalities.	Solder the capacitor to the test jig (glass epoxy board).				
	Capacitance	Within the specified tolerance.	The capacitor shall be subjected to a simple harmonic motion				
Vibration Resistance	D.F.	0.025 max.	having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, shall be traversed in approximately 1 min. This motion shall be applied for a period of 2 h in each 3 mutually perpendicular directions (total of 6 h). Solder resist Glass Epoxy Board				
	Operating Temperature Appearary Dimension Dielectrical Insulation	Operating Temperature Range Appearance Dimensions Dielectric Strength Insulation Resistance (I.R.) Capacitance Dissipation Factor (D.F.) Capacitance Temperature Characteristics Discharge Test (Application: Nominal Capacitance C<10,000pF) Adhesive Strength of Termination Appearance Capacitance Capacitance Capacitance Capacitance Capacitance	Operating Temperature Range Papearance No defects or abnormalities.				

[&]quot;Room condition" Temperature : 15 to 35℃, Relative humidity : 45 to 75%, Atmosphere pressure : 86 to 106kPa



Continued from the preceding page. Specification No Item Test Method Solder the capacitor to the testing jig (glass epoxy board) shown No cracking or marking defects shall occur. in Fig.2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so that the soldering is uniform and free of defects such as heat shock. 50 Pressurizing speed: 1.0mm/s Deflection Dimension (mm) I×W (mm) а h C. d Capacitance mete 5.7X2.8 4.5 8.0 3.2 45 (in mm) 1.0 5.7×5.0 4.5 8.0 5.6 Fig.3 Fig.2 Immerse the capacitor in a solution of ethanol (JIS-K-8101) and Solderability of rosin (JIS-K-5902) (25% rosin in weight proportion). 75% of the terminations are to be soldered evenly and continuously. Termination Immerse in eutectic solder solution for 2±0.5 s at 235±5℃. Immersing speed: 25±2.5mm/s Appearance No marking defects. Capacitance Within ±15% Change The capacitor shall be subjected to 40±2℃, relative humidity of Humidity D.F. 0.05 max. 90 to 98% for 8 h, and then removed in room condition for 16 h 14 Insulation until 5 cycles. I.R. More than $1.000M\Omega$ Dielectric Pass the item No.4. Strength Preheat the capacitor as table. Appearance No marking defects. Immerse the capacitor in eutectic solder solution at 260±5℃ for Capacitance Within ±10% 10±1 s. Let sit at room condition for 24±2 h, then measure. Change •Immersing speed: 25±2.5mm/s D.F. 0.025 max. Resistance Perform a heat treatment at 150⁺₋₁₀ °C for 60±5 min and then I.R. More than $2,000M\Omega$ to Soldering let sit for 24±2 h at room condition. Heat *Preheating Dielectric Pass the item No.4. Step Temperature Time Strength 100℃ to 120℃ 1 min 2 170℃ to 200℃ 1 min Fix the capacitor to the supporting jig (glass epoxy board) shown No marking defects. Appearance in Fig.4 using a eutectic solder. Capacitance Within ±7.5% Perform the five cycles according to the four heat treatments Change listed in the following table. D.F. 0.025 max. Let sit for 24±2 h at room condition, then measure. Temperature (°C) Time (min) Step I.R. More than $2,000M\Omega$ 1 Min. Operating Temp.±3 30±3 2 Room Temp. 2 to 3 3 Max. Operating Temp. ±2 30 ± 3 4 Room Temp 2 to 3 Temperature 16 Cycle Pretreatment Perform a heat treatment at 150⁺₋₁₀ °C for 60±5 min and then let sit for 24±2 h at room condition. Dielectric Pass the item No.4. Strength *m m m* Solder resist

"Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

Continued on the following page. |

Fig.4



Continued from the preceding page.

No.	Ite	em	Specification	Test Method			
		Appearance	No marking defects.				
	Humidity	Capacitance Change	Within ±15%	Sit the capacitor at $40\pm2^{\circ}$ C and relative humidity 90 to 95% f $500\pm^{20}$ h.			
7	(Steady	D.F.	0.05 max.	Remove and let sit for 24±2 h at room condition, then meas •Pretreatment			
	State)	I.R.	More than 1,000M Ω	Perform a heat treatment at 150 ⁺ ₋₁₀ °C for 60±5 min and the			
		Dielectric Strength	Pass the item No.4.	let sit for 24±2 h at room condition.			
		Appearance	No marking defects.	Apply voltage and time as Table at 85±2℃. Remove and let			
		Capacitance Change	Within ±15%	for 24 ±2 h at room condition, then measure. The charge / discharge current is less than 50mA.			
		D.F.	0.05 max.	Nominal Capacitance Test Time Test voltage C≥10,000pF 1,000 ⁺⁴ ₀ h AC300V (r.m.s			
8	Life	I.R.	More than 1,000M Ω	C<10,000pF 1,500 ⁺⁴⁸ ₀ h AC500V (r.m.s			
)	Liio	Dielectric Strength	Pass the item No.4.	* Except that once each hour the voltage is increased to AC1,000V (r.m.s.) for 0.1 s •Pretreatment Apply test voltage for 60±5 min at test temperature. Remove and let sit for 24±2 h at room condition.			
		Appearance	No marking defects.				
		Capacitance Change	Within ±15%	Apply the rated voltage at $40\pm2^{\circ}$ C and relative humidity 90 to 95% for $500\pm^{24}$ h.			
9	Humidity Loading	D.F.	0.05 max.	Remove and let sit for 24±2 h at room condition, then meas •Pretreatment			
	Loading	I.R.	More than 1,000M Ω	Apply test voltage for 60±5 min at test temperature.			
	-	Dielectric Strength	Pass the item No.4.	Remove and let sit for 24±2 h at room condition.			

[&]quot;Room condition" Temperature : 15 to 35°C, Relative humidity : 45 to 75%, Atmosphere pressure : 86 to 106kPa

Chip Monolithic Ceramic Capacitors



Safety Standard Recognized Type

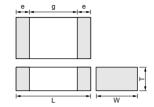
■ Features

- 1. Chip monolitic ceramic capacitor (certified as conforming to safety standards) for AC line.
- 2. A new monolithic structure for small, high-capacitance capable of operating at high-voltage levels.
- Compared to lead type capacitors, this new capacitor is greatly downsized and low-profiled to 1/10 or less in volume, and 1/4 or less in height.
- 4. The type GB can be used as an X2-class capacitor.
- 5. The type GC can be used as an X1-class and Y2-class capacitor.
- 6. +125 degree C guaranteed.
- 7. Only for reflow soldering.

■ Applications

- Ideal use as Y capacitor or X capacitor for various switching power supply.
- Ideal use as linefilter for MODEM.





Part Number	Dimensions (mm)							
Part Number	L	L W T			g min.			
GA355D	5.7 ±0.4	5.0 ±0.4	2.0 ±0.3	0.3	4.0			
GA355X	3.7 ±0.4	5.0 ±0.4	2.7 ±0.3	0.3				

■ Standard Recognition

	Standard No.	Status of R	Recognition	Rated	
	Standard No.	Type GB	Type GC	Voltage	
UL	UL1414	_	©*		
BSI		_	0		
VDE	EN1400400	0	0	AC250V	
SEV	EN132400	0	0	(r.m.s.)	
SEMKO		0	0		
EN132400 Class		X2	X1, Y2		

*: Line By Pass only

Type GC

Part Number	Rated Voltage (V)	TC Code	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g (mm)	Electrode e (mm)
GA355DR7GC101KY02L	AC250 (r.m.s.)	X7R	100 +10,-10%	5.7	5.0	2.0	4.0 min.	0.3 min.
GA355DR7GC151KY02L	AC250 (r.m.s.)	X7R	150 +10,-10%	5.7	5.0	2.0	4.0 min.	0.3 min.
GA355DR7GC221KY02L	AC250 (r.m.s.)	X7R	220 +10,-10%	5.7	5.0	2.0	4.0 min.	0.3 min.
GA355DR7GC331KY02L	AC250 (r.m.s.)	X7R	330 +10,-10%	5.7	5.0	2.0	4.0 min.	0.3 min.
GA355DR7GC471KY02L	AC250 (r.m.s.)	X7R	470 +10,-10%	5.7	5.0	2.0	4.0 min.	0.3 min.
GA355DR7GC681KY02L	AC250 (r.m.s.)	X7R	680 +10,-10%	5.7	5.0	2.0	4.0 min.	0.3 min.
GA355DR7GC102KY02L	AC250 (r.m.s.)	X7R	1000 +10,-10%	5.7	5.0	2.0	4.0 min.	0.3 min.
GA355DR7GC152KY02L	AC250 (r.m.s.)	X7R	1500 +10,-10%	5.7	5.0	2.0	4.0 min.	0.3 min.
GA355DR7GC222KY02L	AC250 (r.m.s.)	X7R	2200 +10,-10%	5.7	5.0	2.0	4.0 min.	0.3 min.
GA355DR7GC332KY02L	AC250 (r.m.s.)	X7R	3300 +10,-10%	5.7	5.0	2.0	4.0 min.	0.3 min.
GA355DR7GC472KY02L	AC250 (r.m.s.)	X7R	4700 +10,-10%	5.7	5.0	2.0	4.0 min.	0.3 min.

Type GB

Part Number	Rated Voltage (V)	TC Code	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g (mm)	Electrode e (mm)
GA355DR7GB103KY02L	AC250 (r.m.s.)	X7R	10000 +10,-10%	5.7	5.0	2.0	4.0 min.	0.3 min.
GA355DR7GB153KY02L	AC250 (r.m.s.)	X7R	15000 +10,-10%	5.7	5.0	2.0	4.0 min.	0.3 min.
GA355DR7GB223KY02L	AC250 (r.m.s.)	X7R	22000 +10,-10%	5.7	5.0	2.0	4.0 min.	0.3 min.
GA355XR7GB333KY06L	AC250 (r.m.s.)	X7R	33000 +10,-10%	5.7	5.0	2.7	4.0 min.	0.3 min.

No.	o. Item		Specification	Test Method			
1	Operating Temperature Range		-55 to +125℃		_		
2	Appearance No defects or abnormalities.		No defects or abnormalities.	Visual inspection.			
3	Dimensio	mensions Within the specified dimensions.		Using calipers.			
4	4 Dielectric Strength		No defects or abnormalities.	No failure shall be observed between the terminations charge/discharge current Type GB Type GC	• •		
5	Insulation Resistance (I.R.)		More than $6{,}000M\Omega$	The insulation resistance shall be measured with 500±50V and within 60±5 s of charging.			
6	Capacitance		Within the specified tolerance.	The appearance/D C shall be assessed at 2000 at a f			
7	Dissipation Factor (D.F.)		0.025 max.	The capacitance/D.F. shall be measured at 20°C at a frequency of 1±0.2kHz and a voltage of 1±0.2V (r.m.s.)			
8	Capacitance Temperature Characteristics		Cap. Change Within ±15%	The range of capacitance change compared with the 25°C value within −55 to +125°C shall be within the specified range. •Pretreatment Perform a heat treatment at 150 ± 10°C for 60±5 min and then let sit for 24±2 h at room condition.			
		Appearance	No defects or abnormalities.		ade 50 times at 5 s intervals from		
		I.R.	More than 1,000MΩ	, , ,	d at DC voltage of specified.		
9	Discharge Test (Application: Type GC)	Dielectric Strength	Pass the item No.4.		$R1$ Ct $R2$ or under test $Cd: 0.001\mu F$ $Ct: 100M\Omega$ $R3: Surge resistance$		
10	Adhesive Strength of Termination		No removal of the terminations or other defect shall occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig.1 using a eutectic solder. Then apply 10N force in the direction of the arrow. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so that the soldering is uniform and free of defects such as heat shock. 10N, 10±1s Speed: 1.0mm/s Glass Epoxy Board Fig.1			
		Appearance	No defects or abnormalities.	Solder the capacitor to the test jig (glass epoxy board). The capacitor shall be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied			
		Capacitance	Within the specified tolerance.				
11	Vibration Resistance	D.F.	0.025 max.	uniformly between the ap frequency range, from 10 traversed in approximatel a period of 2 h in each 3 i of 6 h).	proximate limits of 10 and 55Hz. The to 55Hz and return to 10Hz, shall be y 1 min. This motion shall be applied for mutually perpendicular directions (total		
				201 1001 5			

[&]quot;Room condition" Temperature : 15 to 35℃, Relative humidity : 45 to 75%, Atmosphere pressure : 86 to 106kPa



Continued from the preceding page. Specification No Item Test Method Solder the capacitor to the testing jig (glass epoxy board) shown No cracking or marking defects shall occur. in Fig.2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3. The soldering shall be done either with an iron or using the reflow method and shall be conducted with care so that the soldering is uniform and free of defects such as heat shock. Deflection 1 Pressurize Dimension (mm) I×W (mm) а h C. d 5.7×5.0 4.5 5.6 1.0 (in mm) 8.0 Fig.2 Fig.3 Immerse the capacitor in a solution of ethanol (JIS-K-8101) and Solderability of rosin (JIS-K-5902) (25% rosin in weight proportion). 75% of the terminations is to be soldered evenly and continuously. Termination Immerse in eutectic solder solution for 2±0.5 s at 235±5℃. Immersing speed: 25±2.5mm/s Preheat the capacitor as table. Immerse the capacitor in Appearance No marking defects. eutectic solder solution at 260±5°C for 10±1 s. Let sit at room Capacitance Within ±10% condition for 24±2 h, then measure. Change •Immersing speed: 25±2.5mm/s I.R. More than 1,000M Ω Pretreatment Resistance Perform a heat treatment at 150 ± 18 °C for 60±5 min and then to Soldering 14 let sit for 24±2 h at room condition. Heat Dielectric *Preheating Pass the item No.4. Strength Step Temperature Time 100°C to 120°C 1 min 170℃ to 200℃ 1 min. Appearance No marking defects. Fix the capacitor to the supporting jig (glass epoxy board) shown in Fig.4 using a eutectic solder. Capacitance Within ±15% Perform the five cycles according to the four heat treatments Change listed in the following table. D.F. 0.05 max. Let sit for 24±2 h at room condition, then measure. Time (min) Step Temperature (°C) I.R. More than $3.000M\Omega$ Min. Operating Temp.±3 30±3 2 Room Temp. 2 to 3 3 Max. Operating Temp.±2 30 ± 3 4 Room Temp. 2 to 3 Temperature Cycle Pretreatment Perform a heat treatment at 150⁺₋₁₀ °C for 60±5 min and then let sit for 24±2 h at room condition. Dielectric Pass the item No.4. Strength Glass Epoxy Board Fig.4 No marking defects. Appearance Capacitance Within ±15% Change Humidity Sit the capacitor at 40±2℃ and relative humidity 90 to 95% for (Steady D.F. 0.05 max. 500±12 h. Remove and let sit for 24±2 h at room condition, then measure. State) I.R. More than $3,000M\Omega$ Dielectric Pass the item No.4. Strength

"Room condition" Temperature : 15 to 35℃, Relative humidity : 45 to 75%, Atmosphere pressure : 86 to 106kPa



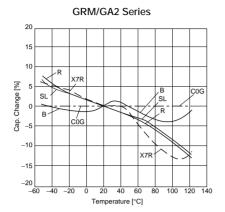
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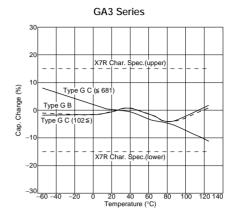
No.	. Item		Specification		Test Method		
17	Life	Appearance	No marking defects.	-	Impulse Voltage T _{100 (%)} T _{1=1.2μs=1.67} T		
		Capacitance Change	Within ±20%	subjected to	Each individual capacitor shall be subjected to a 2.5kV (Type GC:5kV) Impulses (the voltage value means		
		D.F.	0.05 max.	zero to pea	zero to peak) for three times. Then the capacitors are applied to life test.		
		I.R.	More than $3,000 M\Omega$	the capacit			
		Dielectric Strength	,	Apply voltage as Table for 1,000 h at $125 \pm ^{\circ}_{0}$ °C, relative humidity 50% max.			
				Туре	Applied voltage		
				GB	AC312.5V (r.m.s.), except that once each hour the voltage is increased to AC1,000V (r.m.s.) for 0.1s.		
				GC	AC425V (r.m.s.), except that once each hour the voltage is increased to AC1,000V (r.m.s.) for 0.1s.		
18	Humidity Loading	Appearance	No marking defects.				
		Capacitance Change	Within ±15%	Apply the	Apply the rated voltage at 40±2°C and relative humidity 90 to 95% for 500±26 h. Remove and let sit for 24±2 h at room		
		D.F.	0.05 max.	95% for 50			
		I.R.	More than $3{,}000M\Omega$	condition,	condition, then measure.		
		Dielectric Strength	Pass the item No.4.				

[&]quot;Room condition" Temperature : 15 to 35°C, Relative humidity : 45 to 75%, Atmosphere pressure : 86 to 106kPa

GRM/GA2/GA3 Series Data

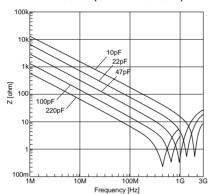
■ Capacitance-Temperature Characteristics

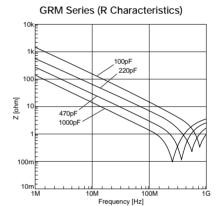




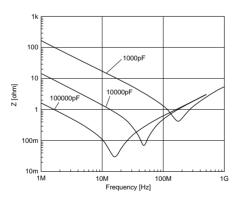
■ Impedance-Frequency Characteristics

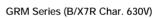
GRM Series (SL Characteristics)

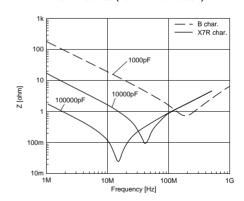




GRM Series (X7R Char. 250V)





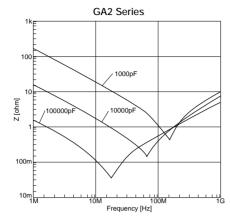


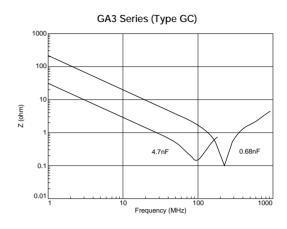


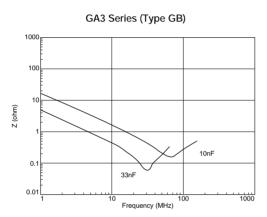
GRM/GA2/GA3 Series Data

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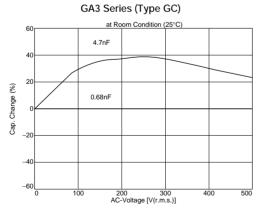
■ Impedance-Frequency Characteristics

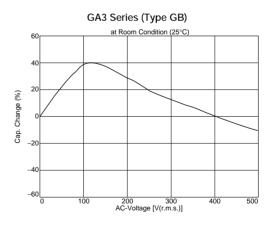






■ Capacitance-AC Voltage Characteristics





Package

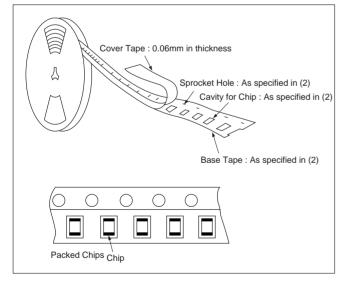
Taping is standard packaging method.

■ Minimum Quantity Guide

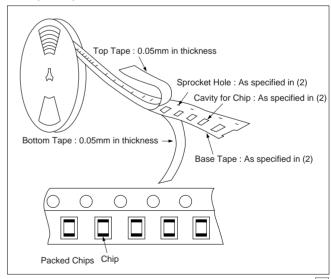
Part Number		Dimensions (mm)		n)	Quantity (pcs.) \$\phi\$180mm reel	
		L	W	Т	Paper Tape	Plastic Tape
	GRM21	2.0	1.25	1.0	4,000	-
				1.25	-	3,000
				1.0	4,000	-
	GRM31	3.2	1.6	1.25	-	3,000
				1.6	-	2,000
	CDM22	3.2	2.5	1.5	-	2,000
Madium valtaga	GRM32			2.0	-	1,000
Medium-voltage	GRM42	4.5	2.0	2.0	-	2,000
	GRM43	4.5	3.2	1.5	-	1,000
				2.0	-	1,000
				2.5	-	500
				2.6	-	500
	GRM55	5.7	5.0	2.0	-	1,000
	GRIVISS			2.7	-	500
AC250V	GA252	5.7	2.8	2.0	-	1,000
AC250V	GA255	5.7	5.0	2.0	-	1,000
Safety Std.	GA355	5.7	5.0	2.0	-	1,000
Recognition	GASSS	5.7	5.0	2.7	-	500

■ Tape Carrier Packaging

- (1) Appearance of Taping
- ① Plastic Tape



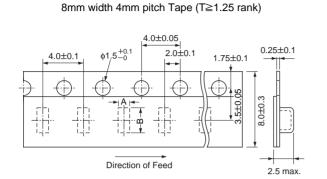
② Paper Tape





Package

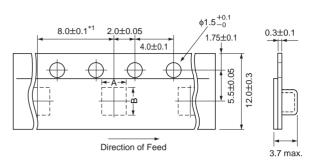
- Continued from the preceding page.
- (2) Dimensions of Tape
- 1) Plastic Tape



Part Number	A*	B*
GRM21	1.45	2.25
GRM31	2.0	3.6
GRM32	2.9	3.6

*Nominal Value

12mm width 8mm/4mm pitch Tape



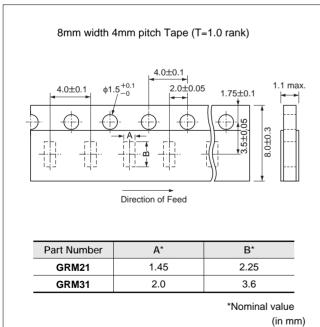
Part Number	A*	B*
GRM42	2.5	5.1
GRM43	3.6	4.9
GA252	3.2	6.1
GRM55		
GA255	5.4	6.1
GA355		

*1 4.0±0.1mm in case of GRM42

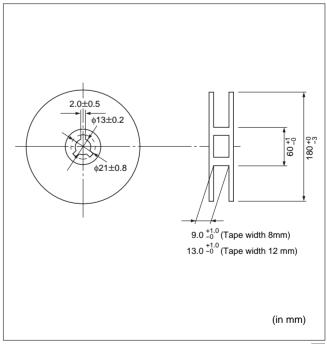
*Nominal Value

(in mm)

2 Paper Tape



(3) Dimensions of Reel

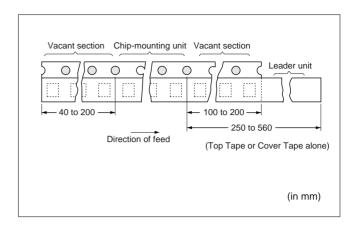


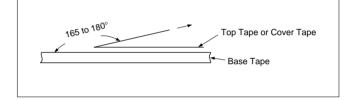




Package

- Continued from the preceding page.
- (4) Taping Method
 - ① Tapes for capacitors are wound clockwise. The sprocket holes are to the right as the tape is pulled toward the user.
 - ② Part of the leader and part of the empty tape shall be attached to the end of the tape as right figure.
 - ③ The top tape or cover tape and base tape are not attached at the end of the tape for a minimum of 5 pitches.
 - 4 Missing capacitors number within 0.1% of the number per reel or 1 pc, whichever is greater, and are not continuous.
 - (5) The top tape or cover tape and bottom tape shall not protrude beyond the edges of the tape and shall not cover sprocket holes.
 - **(6)** Cumulative tolerance of sprocket holes, 10 pitches : ± 0.3 mm.
 - Peeling off force: 0.1 to 0.7N in the direction shown on the right.





⚠Caution

■ Storage and Operating Conditions

Operating and storage environment
 Do not use or store capacitors in a corrosive atmosphere, especially where chloride gas, sulfide gas, acid, alkali, salt or the like are present and avoid exposure to moisture. Before cleaning, bonding or molding this product, verify that these processes do not affect product quality by testing the performance of a cleaned, bonded or molded product in

the intended equipment. Store the capacitors where the temperature and relative humidity do not exceed 5 to 40 degrees centigrade and 20 to 70%.

Use capacitors within 6 months. Confirm the solderability in case of 6 months or more.

Failure to follow the above cautions may result, worst case, in a short circuit and cause fuming or

partial dispersion when the product is used.

■ Handling

Vibration and impact
 Do not expose a capacitor to excessive shock or vibration during use.

Failure to follow the above cautions may result, worst case, in a short circuit and cause fuming or partial dispersion when the product is used.

⚠Caution

■ Caution (Rating)

1. Operating Voltage

When DC-rated capacitors are to be used in AC or ripple current circuits, be sure to maintain the Vp-p value of the applied voltage or the Vo-p which contains DC bias within the rated voltage range.

When the voltage is started to apply to the circuit or it is stopped applying, the irregular voltage may be generated for a transit period because of resonance or switching. Be sure to use a capacitor within rated voltage containing these irregular voltage.

Voltage	DC Voltage	DC+AC Voltage	AC Voltage	Pulse Voltage (1)	Pulse Voltage (2)
Positional Measurement	Vo-p	Vo-p	Vp-p	Vp-p	Vp-p

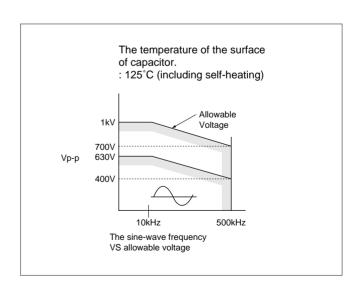
2. Operating Temperature and Self-generated Heat

(1) In case of B/X7R char.

Keep the surface temperature of a capacitor below the upper limit of its rated operating temperature range. Be sure to take into account the heat produced by the capacitor itself. When a capacitor is used in a highfrequency current, pulse current or the like, it may produce heat due to dielectric loss. Keep such selfgenerated temperature below 20°C. When measuring, use a thermocouple of small thermal capacity-K of \$\phi 0.1\$ mm and be in the condition where capacitor is not affected by radiant heat of other components and wind of surroundings. Excessive heat may lead to deterioration of the capacitor's characteristics and reliability.

(2) In case of C0G/R char.

Keep the surface temperature of a capacitor below the upper limit of its rated operating temperature range. Be sure to take into account the heat produced by the capacitor itself. When a capacitor is used in a highfrequency current, pulse current or the like, it may produce heat due to dielectric loss. The allowable frequency should be in less than 500kHz in sine wave. The applied voltage should be limited maximum 60% of the rated voltage (400Vp-p): rated voltage: DC630V and maximum 70% of the rated voltage (700Vp-p): rated voltage DC1kV at 500kHz in more than 10kHz domain as right figure. While, in case of non-sine wave which include a harmonic frequency, please contact our sales representatives or product engineers. The excessive heat may occur a deterioration of the electric characteristic or the reliability on a capacitor.





∆Caution

Continued from the preceding page

(3) In case of SL char.

Keep the surface temperature of a capacitor below the upper limit of its rated operating temperature range. Be sure to take into account the heat produced by the capacitor itself. When a capacitor is used in a highfrequency current, pulse current or the like, it may produce heat due to dielectric loss. The allowable frequency should be in less than 500kHz in sine wave. The applied voltage should be limited maximum 75% of the rated voltage(1.5kVp-p):rated voltage DC2kV and 55% of the rated voltage(1.75kVp-p):rated voltage DC3.15kV at 10kHz and maximum 40% of the rated voltage(800Vp-p):rated voltage DC2kV and 32% of the rated voltage(1.0kVp-p):rated voltage DC3.15kV at 500kHz respectively as right figure. While, in case of nonsine wave which include a harmonic frequency, please contact our sales representatives or product engineers. The excessive heat may occur a deterioration of the electric characteristic or the reliability on a capacitor.



(1) Test Equipment

Test equipment for AC withstanding voltage shall be used with the performance of the wave similar to 50/60 Hz sine

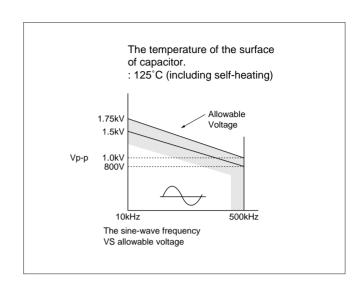
If the distorted sine wave or over load exceeding the specified voltage value is applied, the defective may be caused.

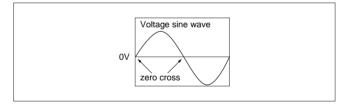
(2) Voltage applied method

When the withstanding voltage is applied, capacitor's lead or terminal shall be firmly connected to the out-put of the withstanding voltage test equipment, and then the voltage shall be raised from near zero to the test voltage. If the test voltage without the raise from near zero voltage would be applied directly to capacitor, test voltage should be applied with the *zero cross. At the end of the test time, the test voltage shall be reduced to near zero, and then capacitor's lead or terminal shall be taken off the out-put of the withstanding voltage test equipment. If the test voltage without the raise from near zero voltage would be applied directly to capacitor, the surge voltage may arise, and therefore, the defective may be caused.

*ZERO CROSS is the point where voltage sine wave pass 0V.

- See the right figure -









∆Caution

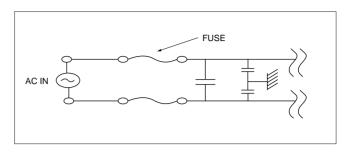
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4. Fail-Safe

When capacitor would be broken, failure may result in a short circuit. Be sure to provide an appropriate fail-safe function like a fuse on your product if failure would follow an electric shock, fire or fume.

Please be considered to use fuses on each AC lines in case that capacitors are used between AC input line to earth (line by-pass capacitor) preparing for the worst (short-circuit).

Failure to follow the above cautions may result, worst case, in a short circuit and cause fuming or partial dispersion when the product is used.



⚠Caution

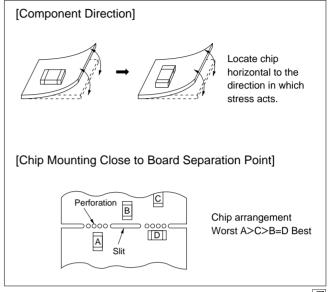
■ Caution (Soldering and Mounting)

Vibration and Impact
 Do not expose a capacitor to excessive shock or vibration during use.

2. Circuit Board Material

Please contact our sales representatives or engineers in case that GR/GA products (size 4.5×3.2mm and over) are to be mounted upon a metal-board or metal-frame. Soldering heat causes the expansion and shrinkage of a board or frame. which may result in chip-cracking.

3. Land Layout for Cropping PC Board
Choose a mounting position that minimizes the stress
imposed on the chip during flexing or bending of the
board.







1 Caution

Continued from the preceding page.

4. Soldering (Prevention of the thermal shock)
If a chip component is heated or cooled abruptly during
soldering, it may crack due to the thermal shock. To
prevent this, adequate soldering condition should be
taken following our recommendation below.

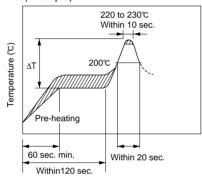
Carefully perform pre-heating so that temperature difference (ΔT) between the solder and component surface should be in the following range. When components are immersed in solvent after mounting, pay special attention to maintain the temperature difference within 100°C.

Chip Size Soldering Method	3.2×1.6mm and under	3.2×2.5mm and over
Reflow Method or Soldering Iron Method	ΔT≦190°C	ΔΤ≦130°C
Flow Method or Dip Soldering Method	ΔT≦150°C	

When soldering chips with a soldering iron, it should be performed in following conditions.

Item	Conditions		
Chip Size	≦2.0×1.25mm 3.2×1.6m		
Temperature of Iron-tip	300°C max.	270°C max.	
Soldering Iron Wattage	20W max.		
Diameter of Iron-tip	ф 3.0mm max.		
Soldering Time	3 sec. max.		
Caution	Do not allow the iron-tip to directly touch the ceramic element.		

Infrared Reflow Soldering Conditions (Example)



(Example)

230 to 240°C

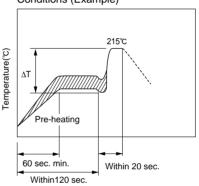
AT

Pre-heating

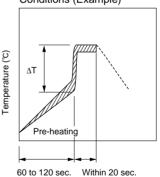
Within 5 sec

Flow Soldering Conditions

Vapor Reflow Soldering (VPS) Conditions (Example)



Dip Soldering/Soldering Iron Conditions (Example)



5. Soldering Method

GR/GA products whose sizes are 3.2×1.6mm and under for flow and reflow soldering, and other sizes for reflow soldering.

60 to 120 sec.

Be sure to contact our sales representatives or engineers in case that GR/GA products (size 3.2X2.5mm and over) are to be mounted with flow soldering. It may crack due to the thermal shock.

Failure to follow the above cautions may result, worst case, in a short circuit and fuming when the product is used.

Notice

■ Notice (Soldering and Mounting)

- 1. Mounting of Chips
- Mechanical shock of the chip placer
 When the positioning claws and pick up nozzle are worn, the load is applied to the chip while positioning is concentrated to one position, thus causing cracks,

Careful checking and maintenance are necessary to prevent unexpected trouble.

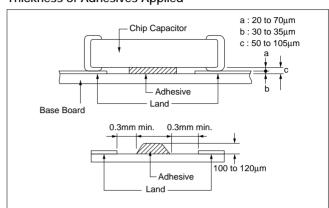
breakage, faulty positioning accuracy, etc.

An excessively low bottom dead point of the suction nozzle imposes great force on the chip during mounting, causing cracked chips. Please set the suction nozzle's bottom dead point on the upper surface of the board.

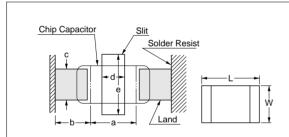
2. Construction of Board Pattern

After installing chips, if solder is excessively applied to the circuit board, mechanical stress will cause destruction resistance characteristics to lower. To pre-vent this, be extremely careful in determining shape and dimension before designing the circuit board diagram.

Termination Thickness of Chip Capacitor and Desirable Thickness of Adhesives Applied



Construction and Dimensions of Pattern (Example)



Preparing slit help flux cleaning and resin coating on the back of the capacitor.

Flow Soldering

L×W	а	b	С
2.0×1.25	1.0-1.2	0.9-1.0	0.8-1.1
3.2×1.6	2.2-2.6	1.0-1.1	1.0-1.4

Reflow Soldering

L×W	a	b	С	d	е
2.0×1.25	1.0-1.2	0.9-1.0	0.8-1.1	-	-
3.2×1.6	2.2-2.4	0.8-0.9	1.0-1.4	1.0-2.0	3.2-3.7
3.2×2.5	2.0-2.4	1.0-1.2	1.8-2.3	1.0-2.0	4.1-4.6
4.5×2.0	2.8-3.4	1.2-1.4	1.4-1.8	1.0-2.8	3.6-4.1
4.5×3.2	2.8-3.4	1.2-1.4	2.3-3.0	1.0-2.8	4.8-5.3
5.7×2.8	4.0-4.6	1.4-1.6	2.1-2.6	1.0-4.0	4.4-4.9
5.7×5.0	4.0-4.6	1.4-1.6	3.5-4.8	1.0-4.0	6.6-7.1

(in mm)

Land Layout to Prevent Excessive Solder

	Mounting Close to a Chassis	Mounting with Leaded Components	Mounting Leaded Components Later
Examples of Arrangements to be Avoided	Chassis Solder (Ground solder) Adhesive Base board Land Pattern in section	Lead Wire Connected to a Part Provided with Lead Wires.	Soldering Iron Lead Wire of Component to be Connected Later. in section
Examples of Improvements by the Land Division	Solder Resist	Solder Resist	Solder Resist
	in section	in section	in section

Notice

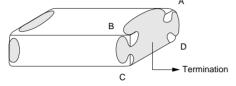
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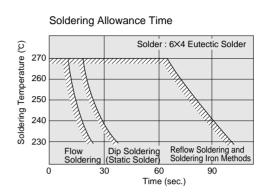
3. Soldering

(Care for minimizing loss of the terminations.) Limit of losing effective area of the terminations and conditions needed for soldering.

> Depending on the conditions of the soldering temperature and/or immersion (melting time), effective areas may be lost in some part of the terminations.

To prevent this, be careful in soldering so that any possible loss of the effective area on the terminations will securely remain minimum 25% on all edge length A-B-C-D of part with A, B, C, D, shown in the Figure below.





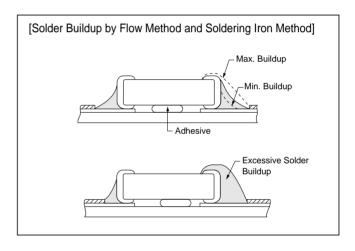
In case of repeated soldering, the accumulated soldering time must be within the range shown above.

(2) Flux

• Use rosin-type flux and do not use a highly acidic flux (any containing a minimum of 0.2wt% chlorine).

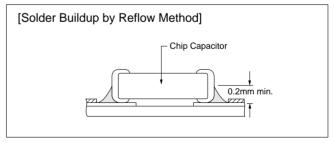
(3) Solder Buildup

1) Flow soldering and iron soldering Use as little solder as possible, and confirm that the solder is securely placed.



(2) Reflow soldering

When soldering, confirm that the solder is placed over 0.2mm of the surface of the terminations.



4. Cleaning

To perform ultrasonic cleaning, observe the following conditions on the right.

5. Resin Coating

- When selecting resin materials, select those with low contraction and low moisture absorption coefficient (generally epoxy resin is used).
- Buffer coat can decrease the influence of the resin shrinking (generally silicone resin).

Rinse bath capacity: Output of 20 watts per liter or less. Rinsing time: 5 minutes maximum.

Notice

■ Notice (Rating)

Capacitance change of capacitor

- Class 1 capacitors
 Capacitance might change a little depending on a surrounding temperature or an applied voltage.
 Please contact us if you use for the strict time constant circuit.
- 2. Class 2 and 3 capacitors Class 2 and 3 capacitors like temperature characteristic B, E and F have an aging

characteristic, whereby the capacitor continually decreases its capacitance slightly if the capacitor leaves for a long time. Moreover, capacitance might change greatly depending on a surrounding temperature or an applied voltage. So, it is not likely to be able to use for the time constant circuit. Please contact us if you need a detail information.



ISO 9000 Certifications

Plant	Certified Date	Organization	Registration No.
Fukui Murata Manufacturing Co., Ltd.	Apr. 2, '97	UL *1	A5287
Izumo Murata Manufacturing Co., Ltd.	Jul. 25, '97	ISO9001	A5587
Murata Electronics Singapore (Pte.) Ltd.	Nov. 3, '99	PSB *2 ISO9001	99-2-1085
Murata Manufacturing (UK) Ltd.	Jun. 24, '98	BSI *3 ISO9001	FM 22169
Murata Amazonia Industria Comercio Ltda.	Jul. 28, '98	FUNDACAO VANZOLINI ISO9002	SQ-480-675/98
Murata Electronics North America State College Plant	Mar. 7, '96	UL *1 ISO9001	A1734
Beijing Murata Electronics Co., Ltd.	Dec. 10, '98	UL *1 ISO9002	A7123

^{*1} UL : Underwriters Laboratories Inc.

^{*2} PSB : Singapore Productivity and Standards Board

^{*3} BSI : British Standards Institution

∧ Note:

1. Export Control

(For customers outside Japan)

Murata products should not be used or sold for use in the development, production, stockpiling or utilization of any conventional weapons or mass-destructive weapons (nuclear weapons, chemical or biological weapons, or missiles), or any other weapons. (For customers in Japan)

For products which are controlled items subject to the "Foreign Exchange and Foreign Trade Law" of Japan, the export license specified by the law is required

- 2. Please contact our sales representatives or product engineers before using our products listed in this catalog for the applications listed below which require especially high reliability for the prevention of defects which might directly cause damage to the third party's life, body or property, or when intending to use one of our products for other applications than specified in this catalog.
 - 1 Aircraft equipment
 - 2 Aerospace equipment
 - 3 Undersea equipment
 - 4 Power plant equipment (5) Medical equipment

 - 6 Transportation equipment (vehicles, trains, ships, etc.)
 - Traffic signal equipment
 - 8 Disaster prevention / crime prevention equipment
 - 9 Data-processing equipment
 - ① Application of similar complexity and/or reliability requirements to the applications listed in the above
- 3. Product specifications in this catalog are as of May 2001. They are subject to change or our products in it may be discontinued without advance notice. Please check with our sales representatives or product engineers before your ordering. If there are any questions, please contact our sales representatives or product
- 4. The parts numbers and specifications listed in this catalog are for information only. You are requested to approve our product specification or to transact the approval sheet for product specification, before your ordering.
- 5. Please note that unless otherwise specified, we shall assume no responsibility whatsoever for any conflict or dispute that may occur in connection with the effect of our and/or third party's intellectual property rights and other related rights in consideration of your using our products and/or information described or contained in our catalogs. In this connection, no representation shall be made to the effect that any third parties are authorized to use the rights mentioned above under licenses without our consent.
- 6. None of ozone depleting substances (ODS) under the Montreal Protocol is used in manufacturing process of us.



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